AFE5401-Q1 Quad-Channel, Analog Front-End for Automotive Radar Baseband Receiver

1 Features

- Qualified for Automotive Applications
- AEC-Q100 Qualified With the Following Results:
  - Device Temperature Grade 1: –40°C to 125°C Ambient Operating Temperature Range
  - Device HBM ESD Classification Level 2
  - Device CDM ESD Classification Level C4B
- Integrated Analog Front-End Includes:
  - Quad LNA, Equalizer, PGA, Antialiasing Filter, and ADC
- Input-Referred Noise with 30-dB PGA Gain:
  - 2.9-nV/√Hz for 15-dB LNA Gain
  - 2.0-nV/√Hz for 18-dB LNA Gain with HIGH_POW_LNA Mode
- Simultaneous Sampling Across Channels
- Programmable LNA Gain: 12 dB, 15 dB, 16.5 dB, and 18 dB
- Programmable Equalizer Modes
- Built-In Diagnostic Modes
- Temperature Sensor
- Programmable-Gain Amplifiers (PGAs):
  - 0 dB to 30 dB in 3-dB Steps
- Programmable, Third-Order, Antialiasing Filter:
  - 7 MHz, 8 MHz, 10.5 MHz, and 12 MHz
- Analog-to-Digital Converter (ADC):
  - Quad Channel, 12 Bits, 25 MSPS per Channel
  - No External Decoupling Required for References
- Parallel CMOS Outputs
- 64-mW Total Core Power per Channel at 25 MSPS per Channel
- Supplies: 1.8 V and 3.3 V
- Package: 9-mm × 9-mm VQFN-64

2 Applications

- Automotive Radar
- Data Acquisition
- SONAR™

3 Description

The AFE5401-Q1 is an analog front-end (AFE), targeting applications where the level of integration is critical. The device includes four channels, with each channel comprising a low-noise amplifier (LNA), a programmable equalizer (EQ), a programmable gain amplifier (PGA), and an antialias filter followed by a high-speed, 12-bit, analog-to-digital converter (ADC) at 25 MSPS per channel.

Each of the four differential input pairs are amplified by an LNA and are followed by a PGA with a programmable gain range from 0 dB to 30 dB. An antialias, low-pass filter (LPF) is also integrated between the PGA and ADC for each channel.

Each LNA, PGA, and antialiasing filter output is differential (limited to 2 V_{PP}). The antialiasing filter drives the on-chip, 12-bit, 25-MSPS ADC. The four ADC outputs are multiplexed on a 12-bit, parallel, CMOS output bus.

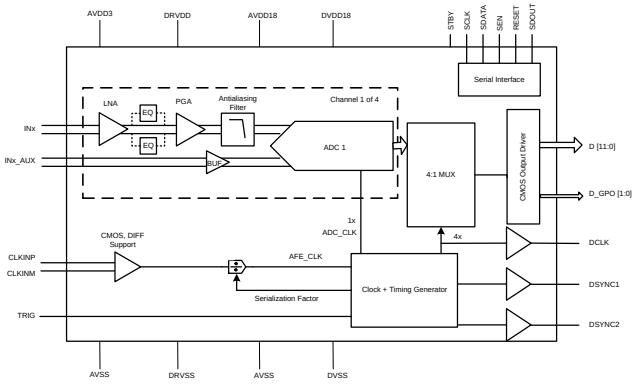
The device is available in a 9-mm × 9-mm, VQFN-64 package and is specified over a temperature range of –40°C to +105°C. For more information, contact AFE5401_info@list.ti.com.

Device Information(1)

PART NUMBER	PACKAGE	BODY SIZE (NOM)
AFE5401-Q1	VQFN (64)	9.00 mm × 9.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Simplified Schematic



An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

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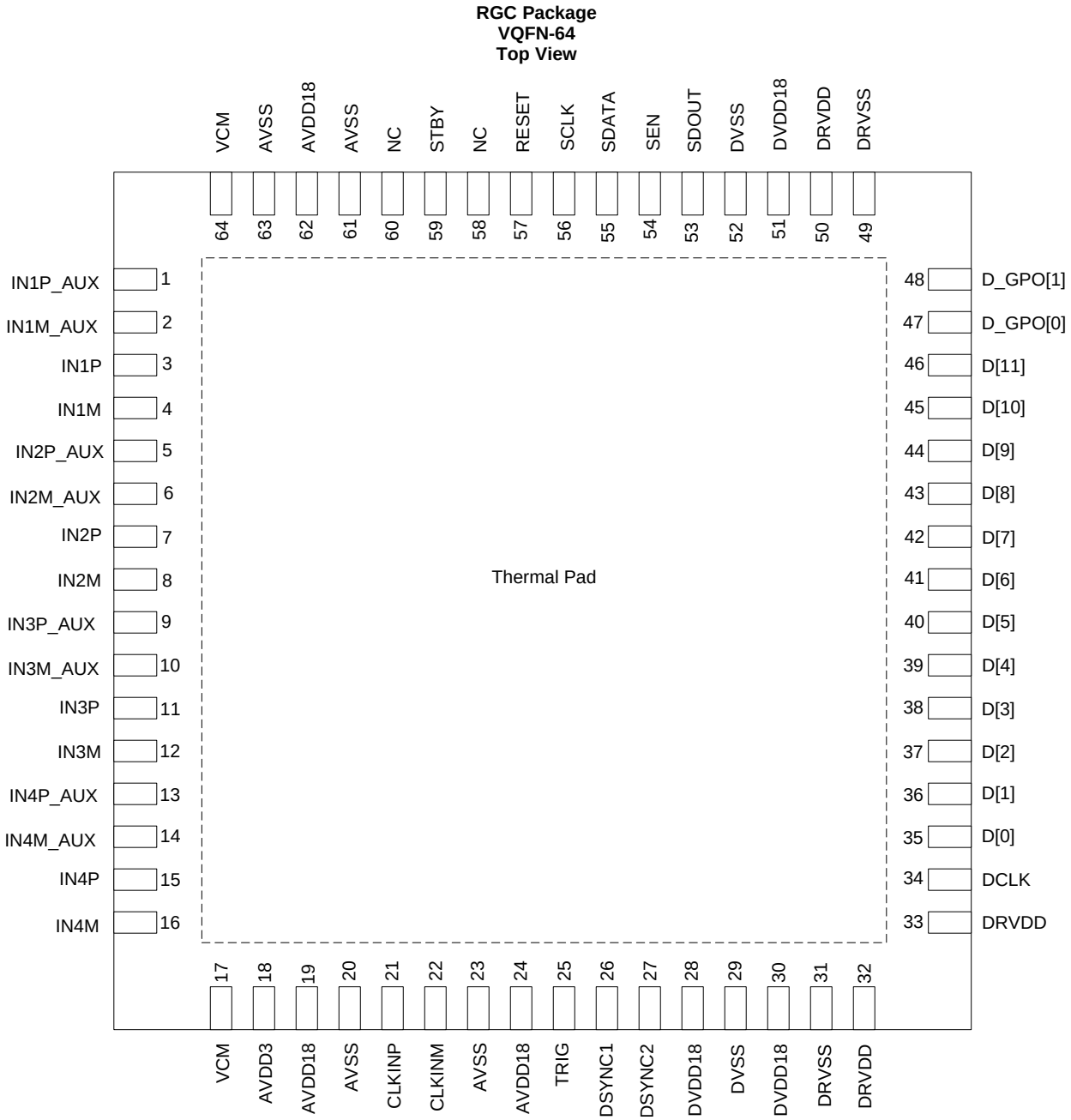
4 Revision History

Changes from Original (March 2014) to Revision A **Page**

- Added automotive Features bullets ... 1
- First public release ... 1
- Changed *Device Information* table to current standards ... 1
- Changed order of *Pin Functions* table to be sorted by pin name instead of pin number ... 4
- Changed *ESD Rating* table title and format, moved Storage temperature parameter to *Absolute Maximum Ratings* table ... 5
- Added *Receiving Notification of Documentation Updates* and *Community Resources* sections ... 71

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5 Pin Configuration and Functions



Pin Functions

PIN		DESCRIPTION
NAME	NO	
D[11:0]	35-46	CMOS outputs for channels 1 to 4
D_GPO[1:0]	47, 48	General-purpose CMOS output
AVDD3	18	3.3-V analog supply voltage
AVDD18	19, 24, 62	1.8-V analog supply voltage
AVSS	20, 23, 61, 63	Analog ground
CLKINM	22	Negative differential clock input pin. A single-ended clock is also supported.
CLKINP	21	Positive differential clock input pin. A single-ended clock is also supported.
DCLK	34	CMOS output clock
DRVDD	32, 33, 50	CMOS output driver supply
DRVSS	31, 49	CMOS output driver ground
DSYNC1	26	Data synchronization clock 1
DSYNC2	27	Data synchronization clock 2
DVDD18	28, 30, 51	1.8-V digital supply voltage
DVSS	29, 52	Digital ground
IN1M	4	Negative differential analog input pin for channel 1
IN1P	3	Positive differential analog input pin for channel 1
IN1M_AUX	2	Negative differential auxiliary analog input pin for channel 1
IN1P_AUX	1	Positive differential auxiliary analog input pin for channel 1
IN2M	8	Negative differential analog input pin for channel 2
IN2P	7	Positive differential analog input pin for channel 2
IN2M_AUX	6	Negative differential auxiliary analog input pin for channel 2
IN2P_AUX	5	Positive differential auxiliary analog input pin for channel 2
IN3M	12	Negative differential analog input pin for channel 3
IN3P	11	Positive differential analog input pin for channel 3
IN3M_AUX	10	Negative differential auxiliary analog input pin for channel 3
IN3P_AUX	9	Positive differential auxiliary analog input pin for channel 3
IN4M	16	Negative differential analog input pin for channel 4
IN4P	15	Positive differential analog input pin for channel 4
IN4P_AUX	13	Positive differential auxiliary analog input pin for channel 4
IN4M_AUX	14	Negative differential auxiliary analog input pin for channel 4
NC	58, 60	Do not connect
RESET	57	Hardware reset pin (active high). This pin has an internal 150-kΩ pull-down resistor.
SCLK	56	Serial interface clock input. This pin has an internal 150-kΩ pull-down resistor.
SDATA	55	Serial interface data input. This pin has an internal 150-kΩ pull-down resistor.
SDOUT	53	Serial interface data readout
SEN	54	Serial interface enable. This pin has an internal 150-kΩ pull-up resistor.
STBY	59	Standby control input. This pin has an internal 150-kΩ pull-down resistor.
TRIG	25	Trigger for DSYNC1 and DSYNC2. This pin has an internal 150-kΩ pull-down resistor.
VCM	17, 64	Output pins for common-mode bias voltage of the auxiliary input signals
Thermal pad	Pad	Located on bottom of package, internally connected to AVSS. Connect to ground plane on the board.

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6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Voltage range	DRVDD to DRVSS	–0.3	+3.8	V
	AVDD3 to AVSS	–0.3	+3.8	
	AVDD18 to AVSS	–0.3	+2.2	
	DVDD18 to DVSS	–0.3	+2.2	
Voltage between	AVSS and DVSS	–0.3	+0.3	V
	AVSS and DRVSS	–0.3	+0.3	
	DVSS and DRVSS	–0.3	+0.3	
Clock input pins (CLKINP and CLKINM) to AVSS		–0.3	minimum (2.2, AVDD18 + 0.3)	V
Analog input pins (IN_iP, IN_iM, IN_iP_AUX, and IN_iM_AUX) to AVSS		–0.3	minimum (2.2, AVDD18 + 0.3)	V
Digital control pins to DVSS	STBY, RESET, SCLK, SDATA, SEN, TRIG	–0.3	+3.6	V
Maximum operating junction temperature, T_J max			+125	°C
Storage temperature, T_{stg}		–60	+150	°C

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002(1)	±1000	V
		Charged-device model (CDM), per AEC Q100-011	±500	

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

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6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
TEMPERATURE						
T_A	Ambient temperature range		–40		+105	°C
SUPPLIES						
DRVDD	Output driver supply		1.7		3.6	V
AVDD3	3-V analog supply voltage		3	3.3	3.6	V
AVDD18	1.8-V analog supply voltage		1.7	1.8	1.9	V
DVDD18	1.8-V digital supply voltage		1.7	1.8	1.9	V
CLOCK INPUT						
CLKIN	Input clock frequency	Default mode (DIV_EN disabled)	12.5		25	MHz
		With DIV_EN, DIV_FRC enabled and DIV_REG = 1	25		50	
		With DIV_EN, DIV_FRC enabled and DIV_REG = 2	37.5		75	
		With DIV_EN, DIV_FRC enabled and DIV_REG = 3	50		100	
		With decimate-by-2 or decimate-by-4 modes enabled (DIV_EN disabled)(1)	12.5		50	
$V_{CLKINP} – V_{CLKINM}$	Input clock amplitude differential	Sine wave, ac-coupled	0.2	1.5		V_{PP}
		LVPECL, ac-coupled	0.2	1.6		
		LVDS, ac-coupled	0.2	0.7		
	Single-ended CMOS clock on CLKINP with CLKINM connected to AVSS			1.8		V
	Input clock duty cycle		40%		60%	
DIGITAL OUTPUT						
C_{LOAD}	Tolerable external load capacitance from each output pin to DRVSS			5		pF

(1) In decimation mode, input clock frequency (CLKIN) can be scaled up to maximum of 200 MHz with the input divider.

6.4 Thermal Information

THERMAL METRIC(1)		AFE5401-Q1 RGC (VQFN) 64 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	24.9	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	8.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	3.9	°C/W
ψ_{JT}	Junction-to-top characterization parameter	0.2	°C/W
ψ_{JB}	Junction-to-board characterization parameter	3.9	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	0.5	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

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6.5 Electrical Characteristics

Minimum and maximum values are across the full temperature range of T_{MIN} = –40°C to T_{MAX} = +105°C, DRVDD = 3.3 V, AVDD3 = 3.3 V, AVDD18 = 1.8 V, DVDD18 = 1.8 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, and differential input clock with 50% duty cycle, unless otherwise noted. Typical values are at T_{NOM} = +25°C.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
FULL-CHANNEL CHARACTERISTICS						
	Maximum differential input signal amplitude on IN_IP and IN_IM	LNA gain = 12 dB		0.5		V_{PP}
		LNA gain = 15 dB (default)		0.35		
		LNA gain = 16.5 dB		0.3		
		LNA gain = 18 dB		0.25		
	Input resistance, from each input to internal dc bias level	Default		1 ± 20%		kΩ
		TERM_INT_20K_LNA / TERM_INT_20K_AUX = 1		10 ± 20%		
C_I	Input capacitance	Differential input capacitance		5.5		pF
V_{VCM}	VCM output voltage	Voltage on VCM pins		1.45		V
	VCM output current capability	For 50-mV drop in VCM voltage		3		mA
	Gain matching	Across channels and devices		0.15	1	dB
E_G	Gain error	PGA gain = 30 dB		± 0.6	± 1.4	dB
E_O	Offset error	PGA gain = 30 dB, 1 sigma value		± 120		LSB
	Input-referred noise voltage	f_{IN} = 3 MHz, idle channel, PGA gain = 30 dB (default)		2.9	3.8	nV/√Hz
		f_{IN} = 3 MHz, idle channel, PGA gain = 30 dB (HIGH_POW_LNA mode)		2.5		
SNR	Signal-to-noise ratio	f_{IN} = 3 MHz, main channel	65	67.7		dBFS
		f_{IN} = 3 MHz, AUX channel		69.2		
SFDR	Spurious-free dynamic range	f_{IN} = 3 MHz, main channel (default)	57	66		dBc
		f_{IN} = 3 MHz, main channel (HPL_EN mode)		74		
THD	Total harmonic distortion	f_{IN} = 3 MHz, main channel	56	65		dBc
IMD	Intermodulation distortion	f_{IN1} = 1.5 MHz, f_{IN2} = 2 MHz, A_{IN1} and A_{IN2} = –7 dBFS		83		dBFS
PSRR	Power-supply rejection ratio	For a 50-mV_{PP} signal on AVDD18 up to 10 MHz, no input applied to analog inputs		> 50		dB
	Number of bits in the ADC			12		Bits
	Crosstalk, main channel to main channel	Aggressor channel: f_{IN} = 2 MHz, 1 dB below ADC full-scale. Victim channel: f_{IN}= 3 MHz, 1 dB below ADC full-scale.		70		dB
	Maximum channel gain	LNA gain = 18 dB, PGA gain = 30 dB		48		dB
	Minimum channel gain	LNA gain = 12 dB, PGA gain = 0 dB		12		dB
	PGA gain resolution			3		dB
	PGA gain range	Maximum PGA gain – minimum PGA gain		30		dB
	Differential input voltage range for AUX channel			2		V_{PP}
ANTIALIAS FILTER (Third-Order Elliptic)						
f_C	3-dB filter corner frequency	FILTER_BW = 0 (default)		8		MHz
		FILTER_BW = 1		7		
		FILTER_BW = 2		10.5		
		FILTER_BW = 3		12		
	3-dB filter corner frequency tolerance	For all FILTER_BW settings		±5%		
ATT_{2FC}	Filter attenuation	At 2 × f_C		30		dBc
ATT_{STPBND}		Stop-band attenuation (f_{IN} > 2.25 × f_C)		40		
RP_{PSBND}	Ripple in pass band			1.5		dB

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Electrical Characteristics (continued)

Minimum and maximum values are across the full temperature range of T_{MIN} = –40°C to T_{MAX} = +105°C, DRVDD = 3.3 V, AVDD3 = 3.3 V, AVDD18 = 1.8 V, DVDD18 = 1.8 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, and differential input clock with 50% duty cycle, unless otherwise noted. Typical values are at T_{NOM} = +25°C.

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
POWER							
	Total core power, per channel	Idle channel, excluding DRVDD power			64		mW
I_{AVDD18}	AVDD18 current consumption	Default mode			131	145	mA
		With HIGH_POW_LNA mode enabled			153		
		With HPL_EN mode enabled			135		
I_{AVDD3}	AVDD3 current consumption				1.5	3.5	mA
I_{DVDD18}	DVDD18 current consumption				8	12	mA
I_{DRVDD}	DRVDD current consumption	5-pF load, toggle data test pattern mode	DRVDD = 3.3 V		14		mA
			DRVDD = 1.8 V		8.5		
		15-pF load, toggle data test pattern mode	DRVDD = 3.3 V		36		
			DRVDD = 1.8 V		20		
	Power-down				5		mW
	STBY power				15		mW

6.6 Digital Characteristics

The dc specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. Minimum and maximum values are across the full temperature range of T_{MIN} = –40°C to T_{MAX} = +105°C, DRVDD = 3.3 V, AVDD3 = 3.3 V, AVDD18 = 1.8 V, and DVDD18 = 1.8 V, unless otherwise noted. Typical values are at T_{NOM} = +25°C.

PARAMETER		MIN	TYP	MAX	UNIT
DIGITAL INPUTS (STBY, RESET, SCLK, CLKIN, SDATA, SEN, TRIG)(1)					
V_{IH}	High-level input voltage	1.4			V
V_{IL}	Low-level input voltage			0.4	V
I_{IH}	High-level input current		10		µA
I_{IL}	Low-level input current		10		µA
C_I	Input capacitance		4		pF
V_{IL_CLKINP}	Input clock CMOS single-ended (V_{CLKINP}), V_{CLKINM} connected to AVSS			0.25 × AVDD18	V
V_{IH_CLKINP}		0.75 × AVDD18			V
DIGITAL OUTPUTS					
V_{OH}	High-level output voltage	DRVDD – 0.2	DRVDD		V
V_{OL}	Low-level output voltage		0	0.2	V

(1) The SEN pin has an internal 150-kΩ pull-up resistor. The STBY, RESET, SCLK, SDATA, and TRIG pins have an internal 150-kΩ pull-down resistor.

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6.7 Timing Requirements: Output Interface

Minimum and maximum values are across the full temperature range of T_{MIN} = –40°C to T_{MAX} = +105°C, DRVDD = 3.3 V, AVDD3 = 3.3 V, AVDD18 = 1.8 V, DVDD18 = 1.8 V, –1-dBFS analog input ac-coupled with 0.1 µF, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, and differential input clock with 50% duty cycle, unless otherwise noted. Typical values are at T_{NOM} = +25°C.

			MIN	NOM	MAX	UNIT
t_{ADLY}	Aperture delay between the rising edge of the input sampling clock and the actual time at which the sampling occurs			3		ns
	Wake-up time	Time to valid data after coming out of STANDBY mode		500		µs
		Time to valid data after coming out of GLOBAL_PDN mode		2		ms
		Time to valid data after stopping and restarting the input clock		500		µs
t_{LAT}	ADC latency (default, after reset)			10.5		t_{AFE_CLK} cycles
t_{SU}	Data setup time	Data valid(1) to 50% of DCLK rising edge, DRVDD = 3.3 V, load = 5 pF, 4x serialization, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 0	4.1			ns
		Data valid(1) to 50% of DCLK rising edge, DRVDD =1.8 V, load = 5 pF, 4x serialization, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 5	3.7			ns
t_{HO}	Data hold time	50% of DCLK rising edge to data becoming invalid(1), DRVDD = 3.3 V, load = 5 pF, 4x serialization, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 0	2.8			ns
		50% of DCLK rising edge to data becoming invalid(1), DRVDD = 1.8 V, load = 5 pF, 4x serialization, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 5	2.7			ns
t_R, t_F	CMOS output data and clock rise and fall time	DRVDD = 3.3 V, load = 5 pF, 10% to 90%, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 0		1.2		ns
		DRVDD = 1.8 V, load = 5 pF, 10% to 90%, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 5		1.1		ns
t_{OUT}	Delay from CLKIN rising edge to DCLK rising edge, zero-crossing of input clock to 50% of DCLK rising edge, DRVDD = 3.3 V, load = 5 pF, 4x serialization, STR_CTRL_CLK and STR_CTRL_CLK_DATA = 0		6.7		9.5	ns
t_{S_TRIG}	TRIG setup time, TRIG pulse duration ≥ t_{AFE_CLK}		4			ns
t_{H_TRIG}	TRIG hold time, TRIG pulse duration ≥ t_{AFE_CLK}		3			ns

(1) Data valid refers to a logic high of 0.7 × DRVDD and a logic low of 0.3 × DRVDD.

6.8 Timing Requirements: RESET

Typical values are at T_A = +25°C. Minimum and maximum specifications are across the full temperature range of T_{MIN} = –40°C to T_{MAX} = +105°C, DRVDD = 3.3 V, AVDD3 = 3.3 V, AVDD18 = 1.8 V, and DVDD18 = 1.8 V, unless otherwise noted.

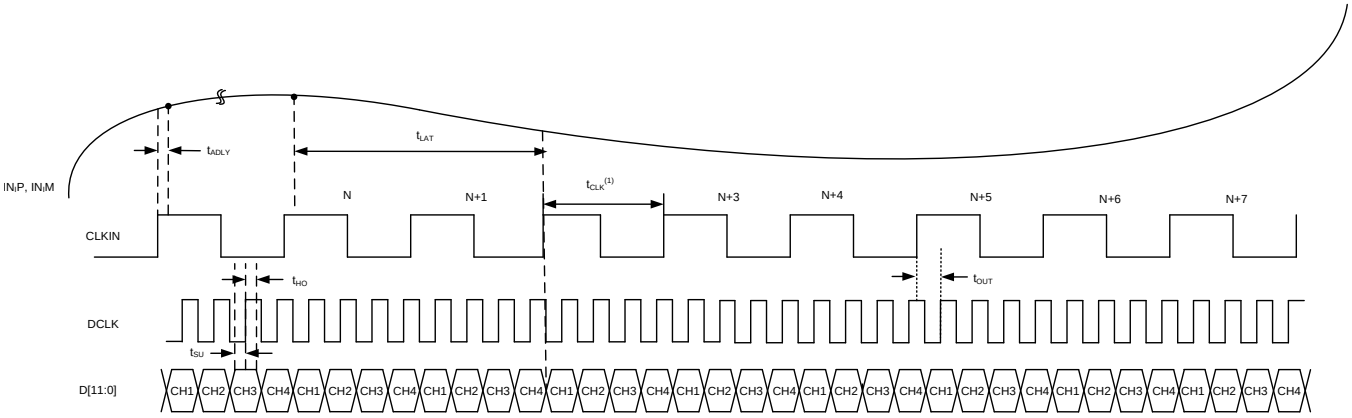
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_1	Power-on to reset delay	Delay from power-up of AVDD18 and DVDD18 to RESET pulse active		1		ms
t_2	Reset pulse duration	Pulse duration of active RESET signal	40			ns
t_3	Register write delay	Delay from RESET disable to SEN active	100			ns

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6.9 Timing Requirements: Serial Interface Operation

Minimum specifications are across the full temperature range of T_{MIN} = –40°C to T_{MAX} = +105°C, DRVDD = 3.3 V, AVDD3 = 3.3 V, AVDD18 = 1.8 V, and DVDD18 = 1.8 V, C_{LOAD} on SDOUT = 5 pF, unless otherwise noted.

PARAMETER		MIN	TYP	MAX	UNIT
t_1	SCLK period	50			ns
t_2	SCLK high time	20			ns
t_3	SCLK low time	20			ns
t_4	Data setup time	5			ns
t_5	Data hold time	5			ns
t_6	SEN falling to SCLK rising	8			ns
t_7	Time between last SCLK rising edge to SEN rising edge	8			ns
t_8	Delay from SCLK falling edge to SDOUT valid	7	11	15	ns



(1) t_{CLK} = 1 / f_{CLKIN}

Figure 1. Output Interface Timing Diagram

A high pulse on the RESET pin is required for register initialization through the reset pin. Figure 2 shows the timing requirement for reset after power-up.

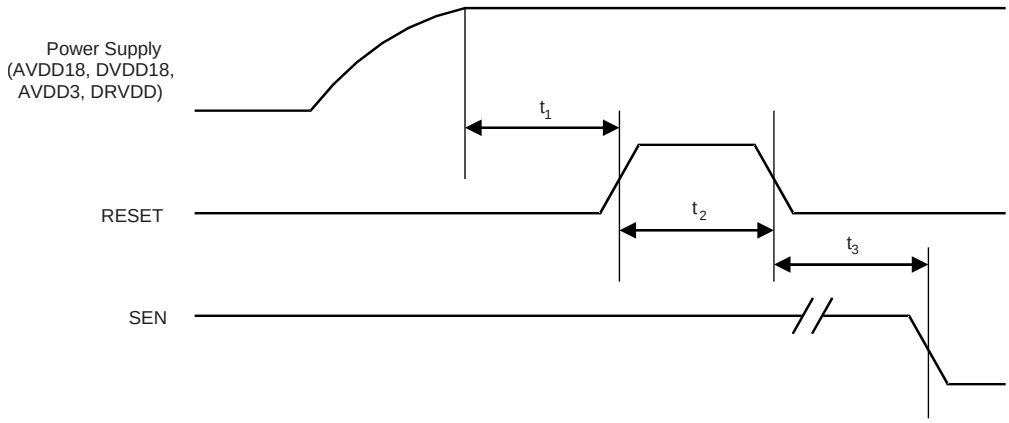


Figure 2. Reset Timing

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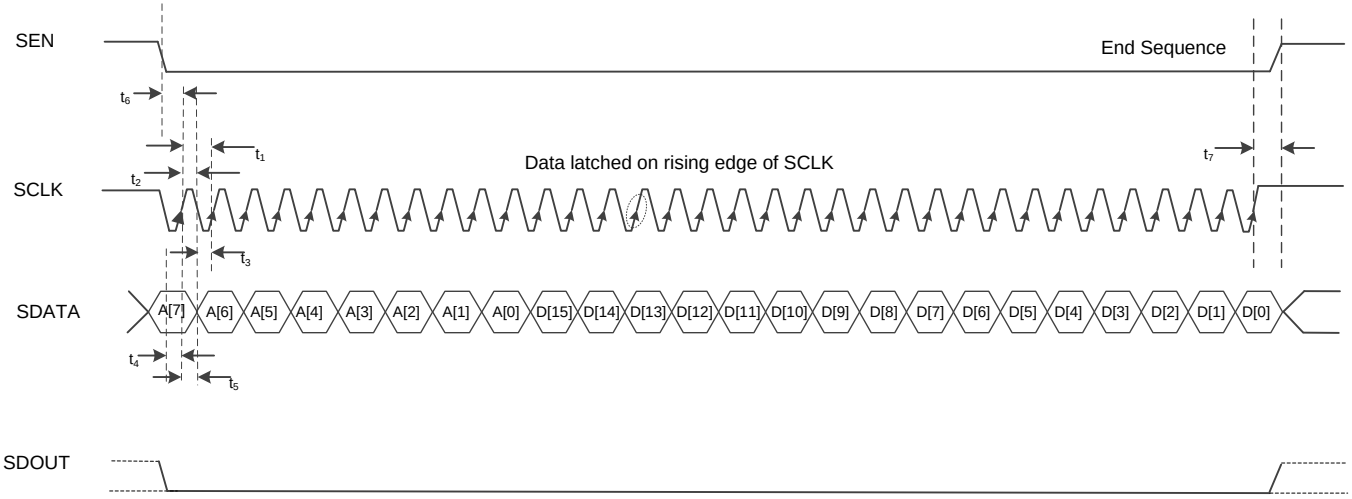


Figure 3. Serial Interface Register Write Timing Diagram

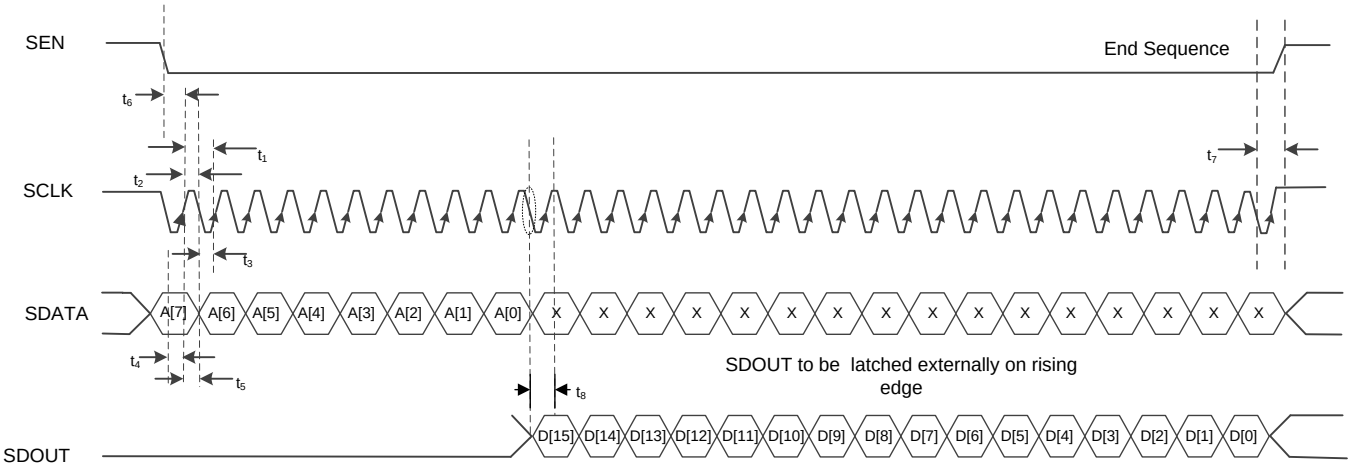
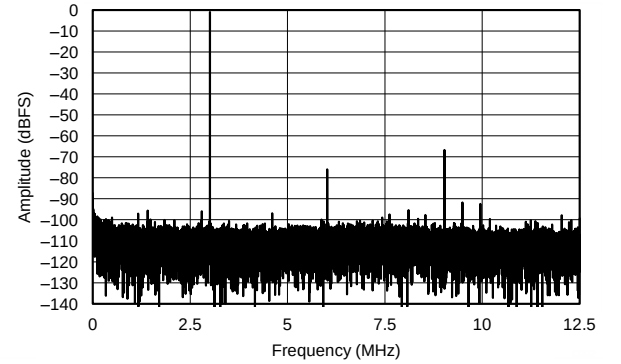


Figure 4. Serial Interface Register Readout Timing Diagram

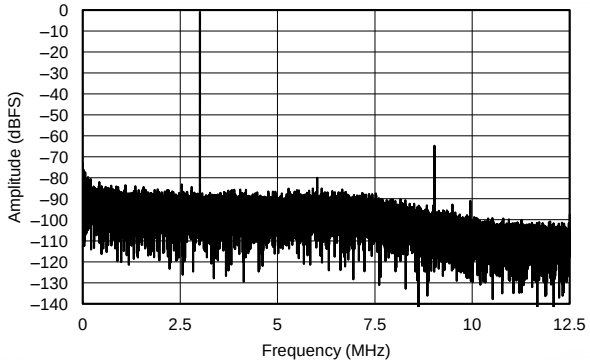
6.10 Typical Characteristics

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.



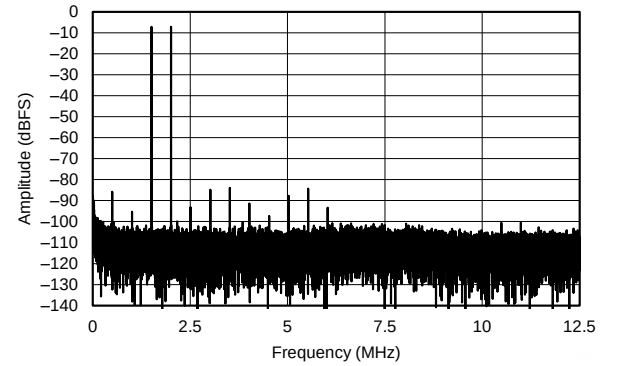
SNR = 67.7 dBFS SFDR = 65.7 dBc THD = 65.2 dBc

Figure 5. FFT for 3-MHz, –1-dBFS Input Signal, 0-dB PGA Gain (Sample Rate = 25 MSPS)



SNR = 53.3 dBFS SFDR = 63.7 dBc THD = 63.6 dBc

Figure 6. FFT for 3-MHz, –1-dBFS Input Signal, 30-dB PGA Gain (Sample Rate = 25 MSPS)



f_{IN1} = 1.5 MHz Each Tone at –7-dBFS Amplitude
f_{IN2} = 2 MHz Two-Tone IMD = –83 dBFS

Figure 7. FFT with Two-Tone Signal

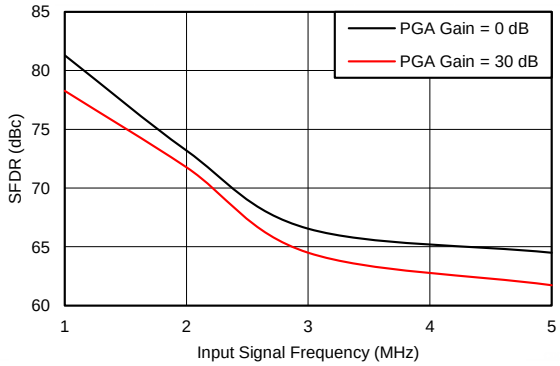


Figure 8. Spurious-Free Dynamic Range vs Input Signal Frequency

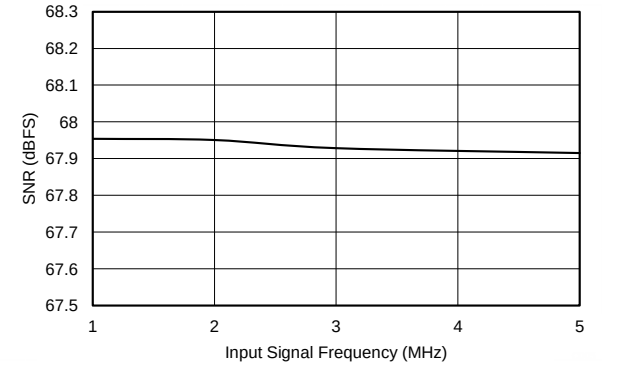


Figure 9. Signal-to-Noise Ratio vs Input Signal Frequency (PGA Gain = 0 dB)

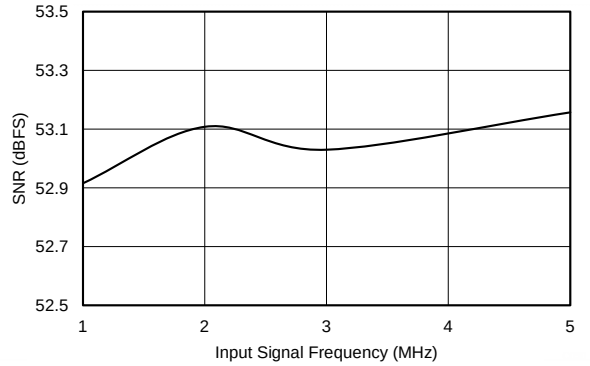


Figure 10. Signal-To-Noise Ratio vs Input Signal Frequency (PGA Gain = 30 dB)

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

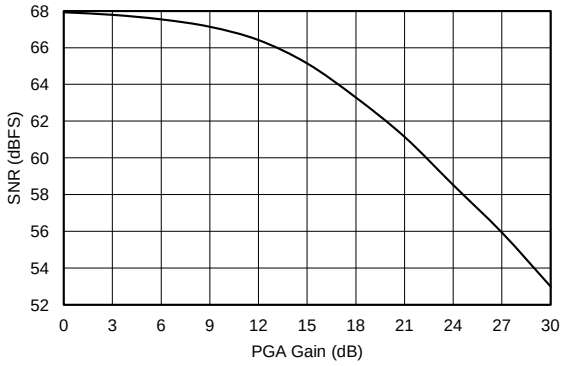


Figure 11. Signal-to-Noise Ratio vs PGA Gain

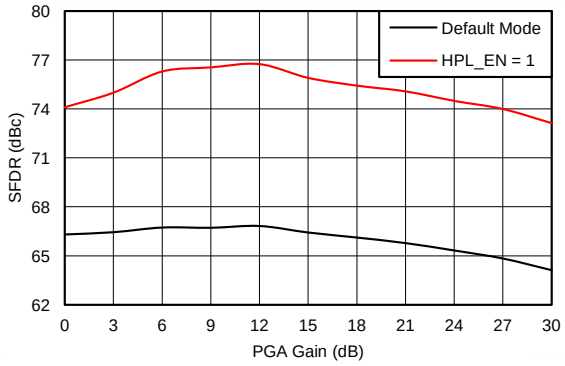


Figure 12. Spurious-Free Dynamic Range vs PGA Gain

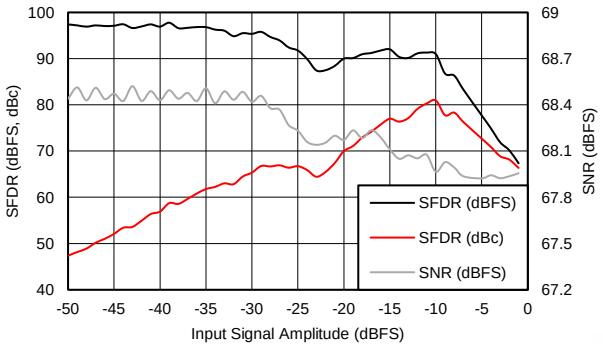


Figure 13. Signal-to-Noise Ratio, Spurious-Free Dynamic Range vs Input Signal Amplitude (PGA Gain = 0 dB)

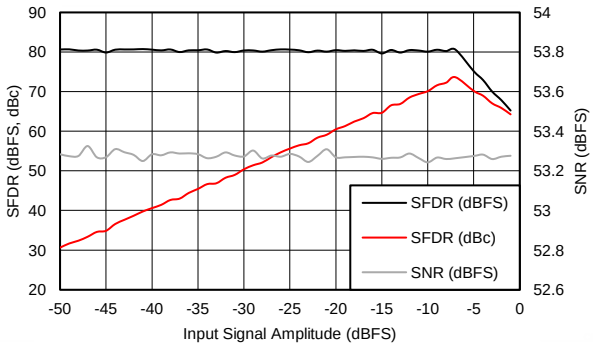


Figure 14. Signal-to-Noise Ratio, Spurious-Free Dynamic Range vs Input Signal Amplitude (PGA Gain = 30 dB)

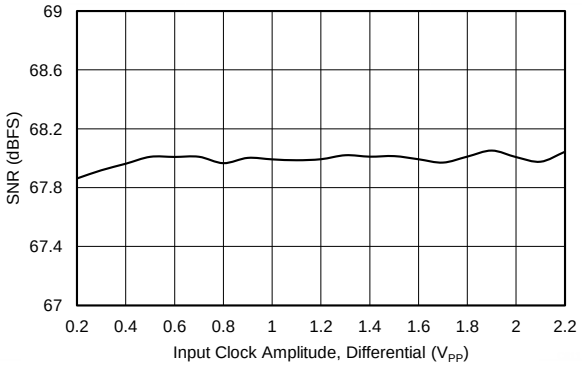


Figure 15. Signal-to-Noise Ratio vs Input Clock Amplitude (PGA Gain = 0 dB)

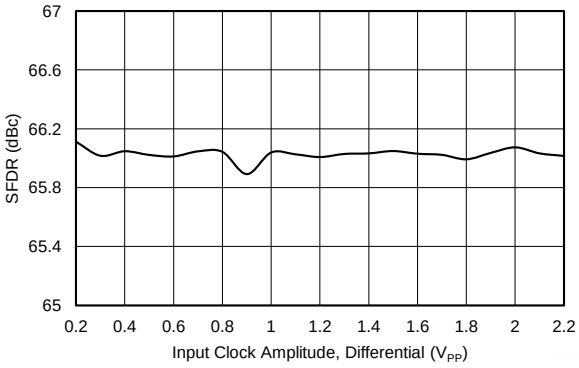


Figure 16. Spurious-Free Dynamic Range vs Input Clock Amplitude (PGA Gain = 0 dB)

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

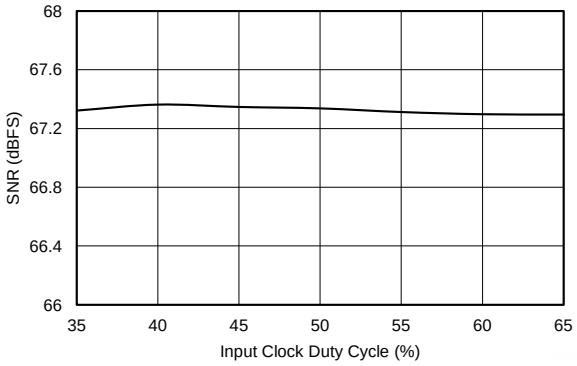


Figure 17. Signal-to-Noise Ratio vs Input Clock Duty Cycle (PGA Gain = 0 dB)

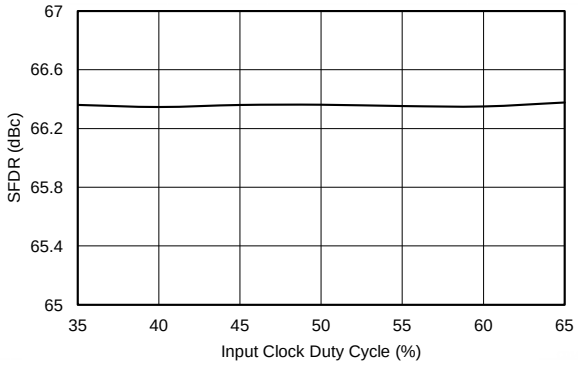


Figure 18. Spurious-Free Dynamic Range vs Input Clock Amplitude (PGA Gain = 0 dB)

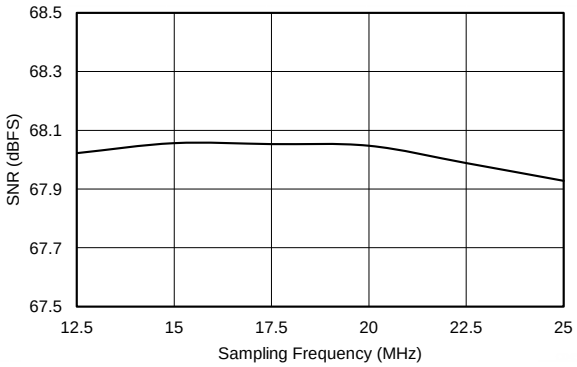


Figure 19. Signal-to-Noise Ratio vs Sampling Frequency (PGA Gain = 0 dB)

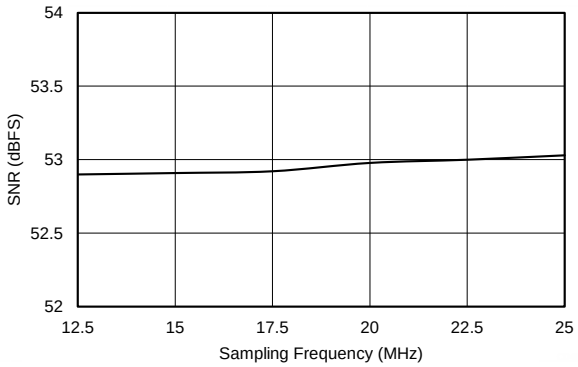


Figure 20. Signal-to-Noise Ratio vs Sampling Frequency (PGA Gain = 30 dB)

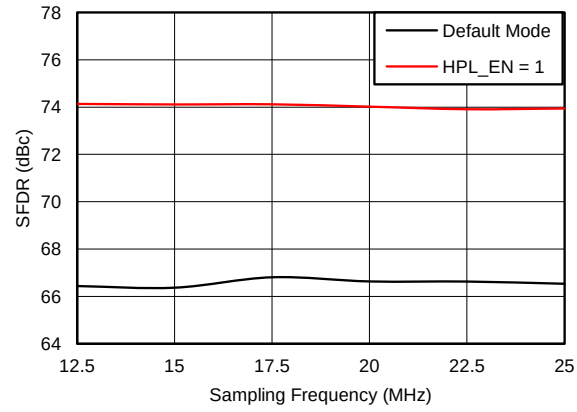


Figure 21. Spurious-Free Dynamic Range vs Sampling Frequency (PGA Gain = 0 dB)

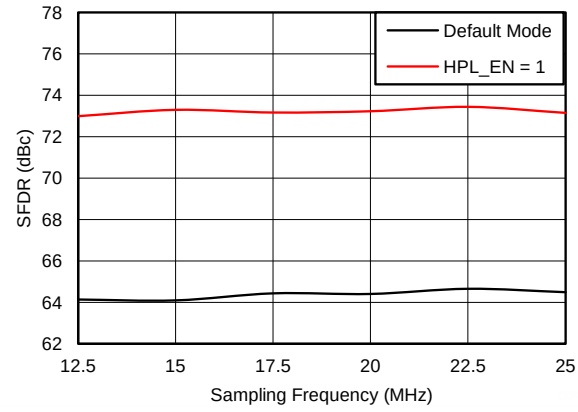


Figure 22. Spurious-Free Dynamic Range vs Sampling Frequency (PGA Gain = 30 dB)

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

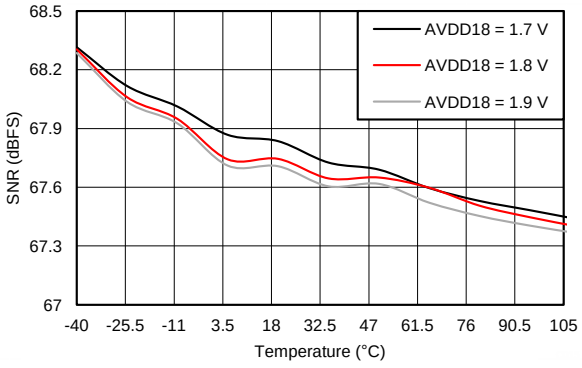


Figure 23. Signal-to-Noise Ratio vs AVDD18 and Temperature (PGA Gain = 0 dB)

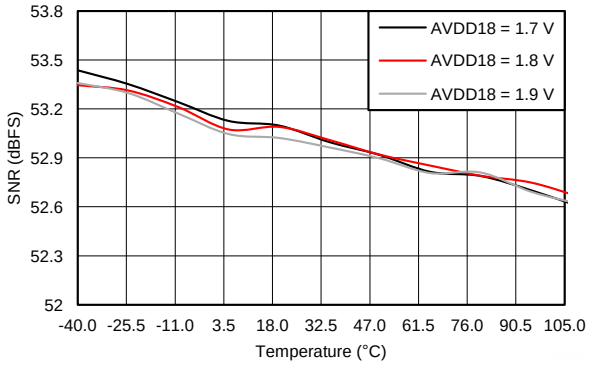


Figure 24. Signal-to-Noise Ratio vs AVDD18 and Temperature (PGA Gain = 30 dB)

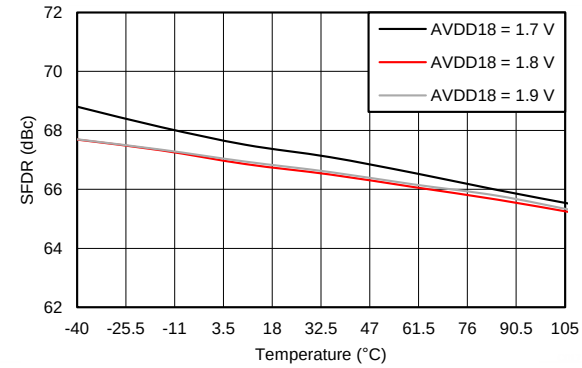


Figure 25. Spurious-Free Dynamic Range vs AVDD18 and Temperature (PGA Gain = 0 dB, Default Mode)

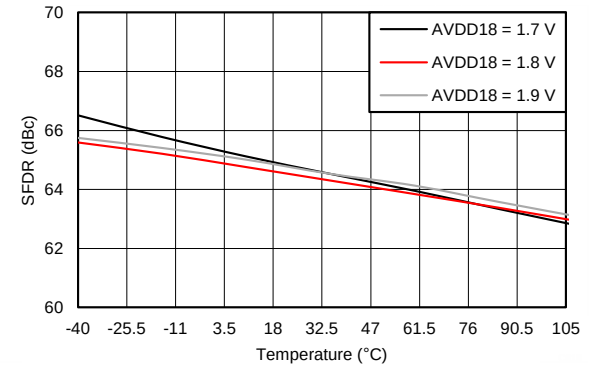


Figure 26. Spurious-Free Dynamic Range vs AVDD18 and Temperature (PGA Gain = 30 dB, Default Mode)

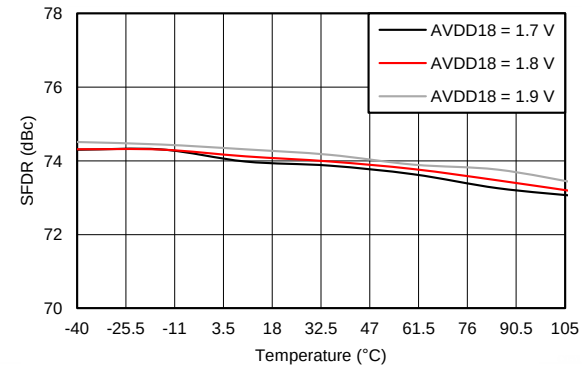


Figure 27. Spurious-Free Dynamic Range vs AVDD18 and Temperature (PGA Gain = 0 dB, HPL_EN = 1)

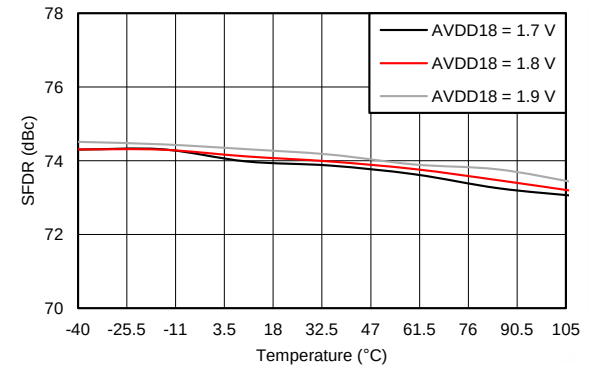


Figure 28. Spurious-Free Dynamic Range vs AVDD18 and Temperature (PGA Gain = 30 dB, HPL_EN = 1)

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

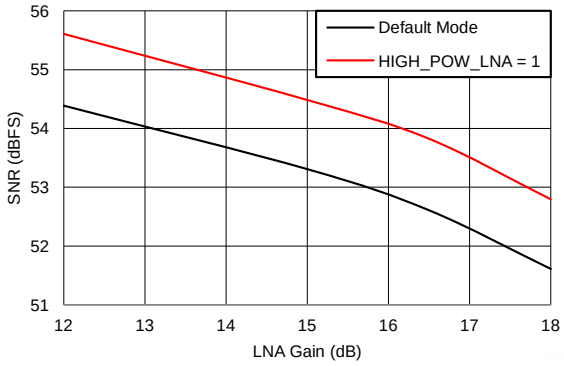


Figure 29. Signal-to-Noise Ratio vs LNA Gain (PGA Gain = 30 dB)

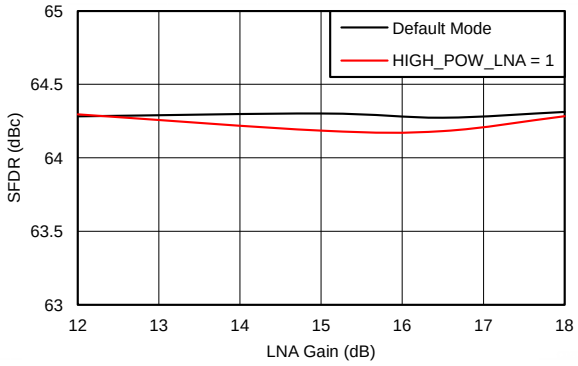


Figure 30. Spurious-Free Dynamic Range vs LNA Gain (PGA Gain = 30 dB)

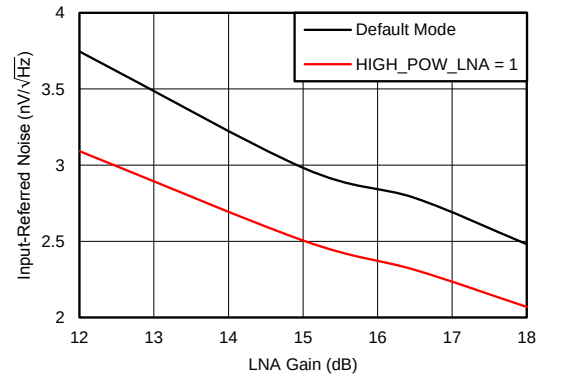


Figure 31. Input-Referred Noise vs LNA Gain (PGA Gain = 30 dB)

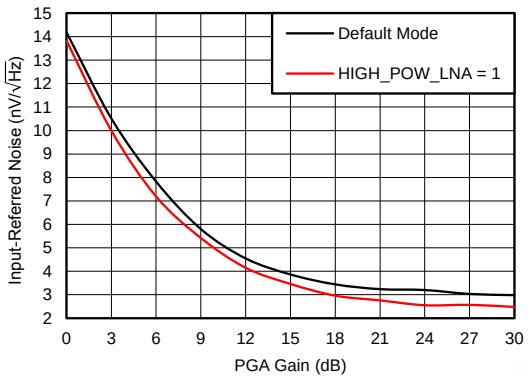


Figure 32. Input-Referred Noise vs PGA Gain

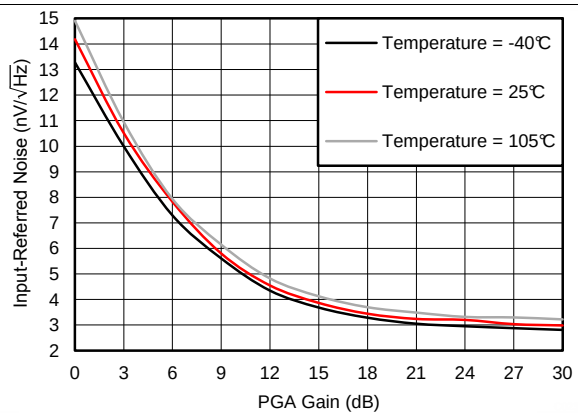


Figure 33. Input-Referred Noise vs PGA Gain and Temperature

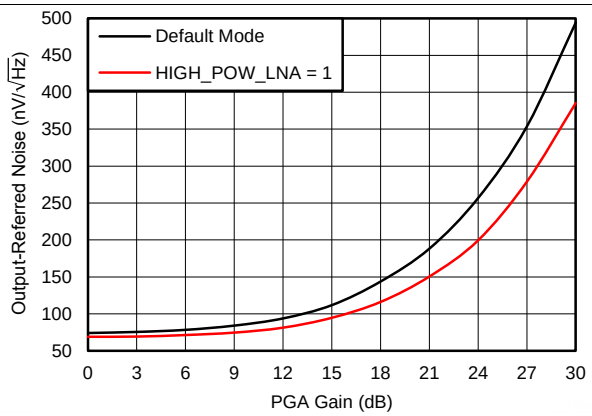


Figure 34. Output-Referred Noise vs PGA Gain

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

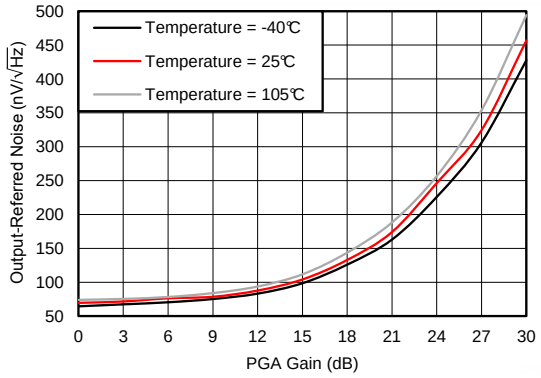


Figure 35. Output-Referred Noise vs PGA Gain and Temperature

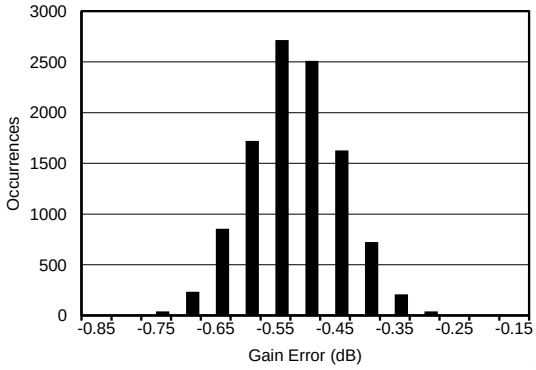


Figure 36. Gain Error Histogram for PGA Gain = 30 dB

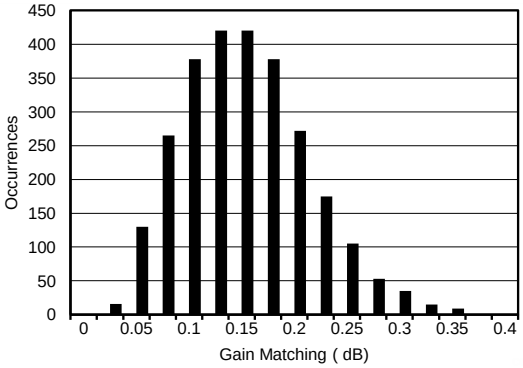


Figure 37. Gain Matching Histogram (Maximum Gain Difference Among the Four Channels within a Device)

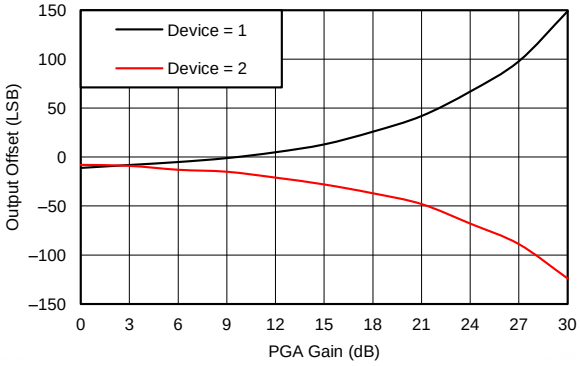


Figure 38. Channel Offset vs PGA Gain for Two Typical Devices

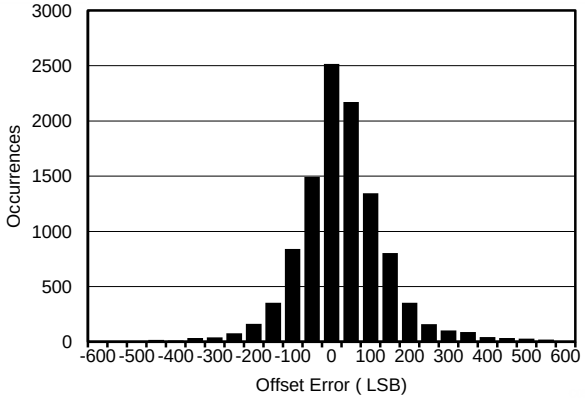


Figure 39. Offset Error Histogram at PGA Gain = 30 dB

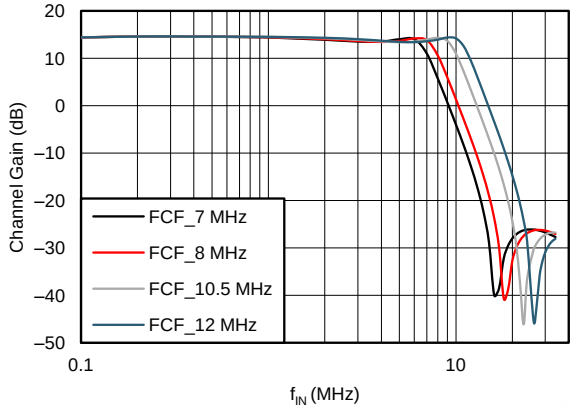


Figure 40. Antialias Filter Response vs FILTER_BW Settings (PGA Gain = 0 dB)

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

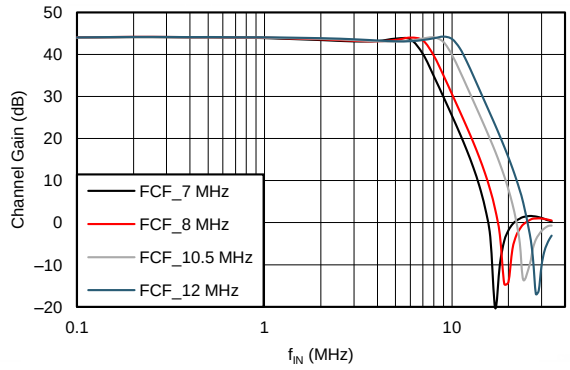


Figure 41. Antialias Filter Response vs FILTER_BW Settings (PGA Gain = 30 dB)

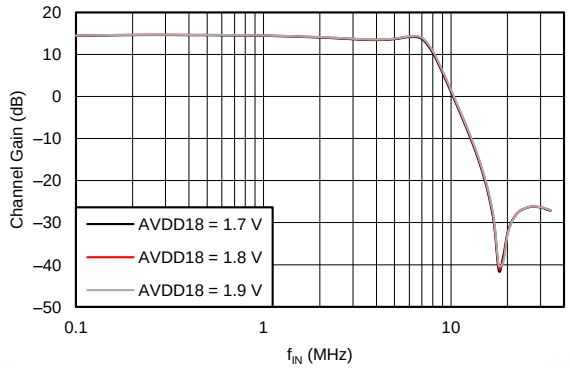


Figure 42. Antialias Filter Response vs AVDD18 (PGA Gain = 0 dB, FILTER_BW = 8 MHz)

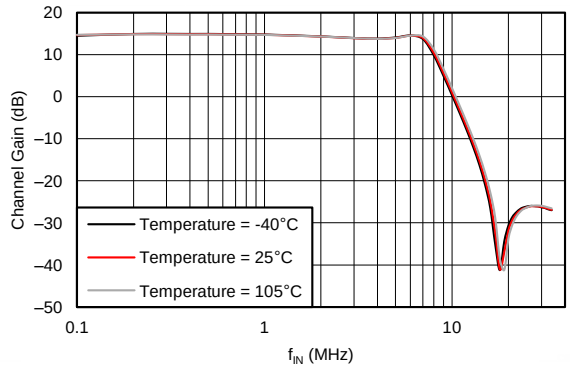


Figure 43. Antialias Filter Response vs Temperature (PGA Gain = 0 dB, FILTER_BW = 8 MHz)

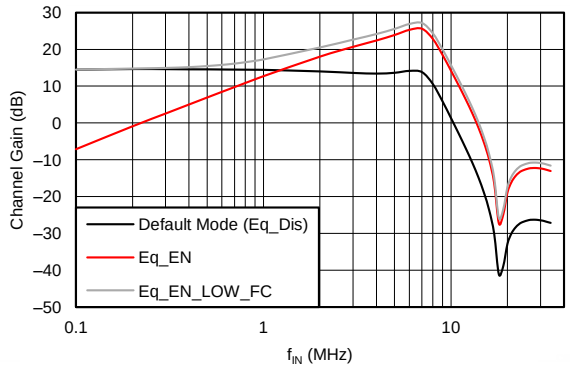


Figure 44. Antialias Filter Response for Equalizer Modes (PGA Gain = 0 dB)

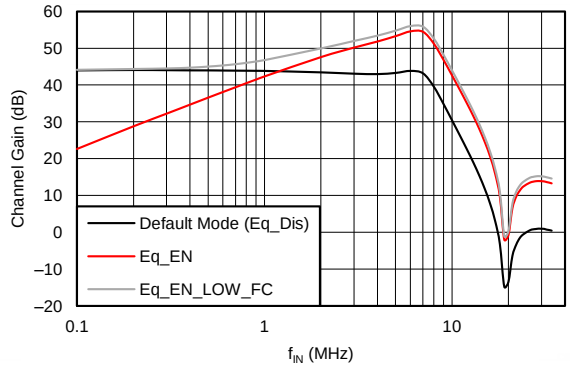


Figure 45. Antialias Filter Response for Equalizer Modes (PGA Gain = 30 dB)

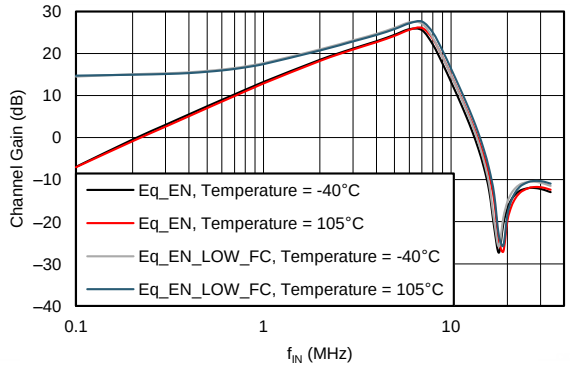


Figure 46. Antialias Filter Response for Equalizer Modes across Temperature (PGA Gain = 0 dB)

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

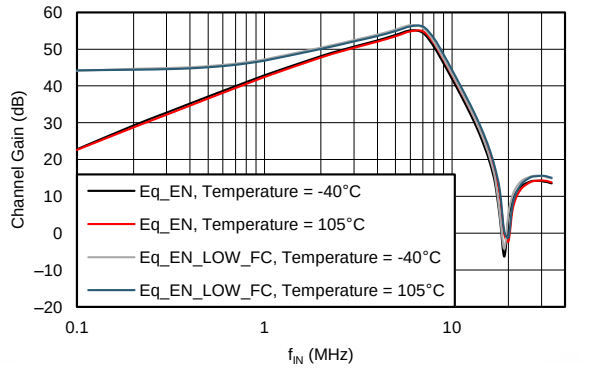
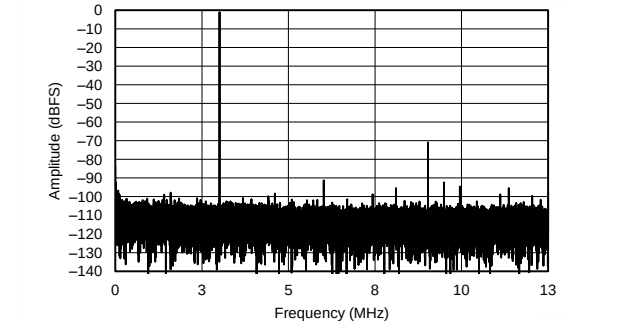


Figure 47. Antialias Filter Response for Equalizer Modes across Temperature (PGA Gain = 30 dB)



SNR = 69.2 dBFS SFDR = 69.8 dBc THD = 69.7 dBc

Figure 48. FFT for AUX Channel (3-MHz, –1-dBFS Input Signal, Sample Rate = 25 MSPS)

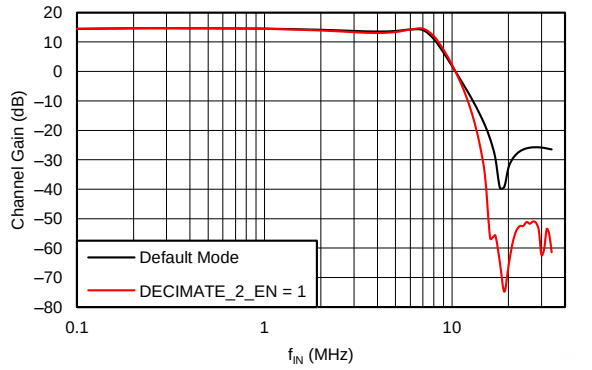


Figure 49. Decimate-by-2 Filter Response (Sampling Frequency = 50 MHz)

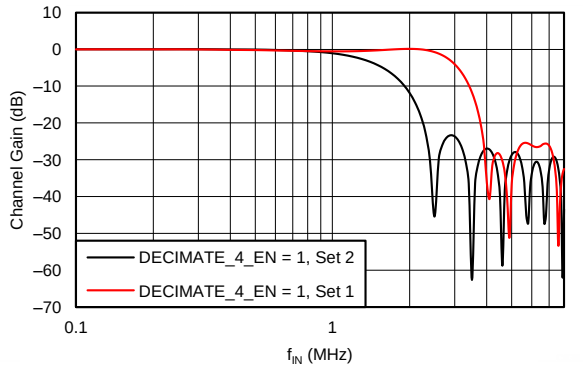


Figure 50. Decimate-by-4 Filter Response (Sampling Frequency = 12.5 MHz)

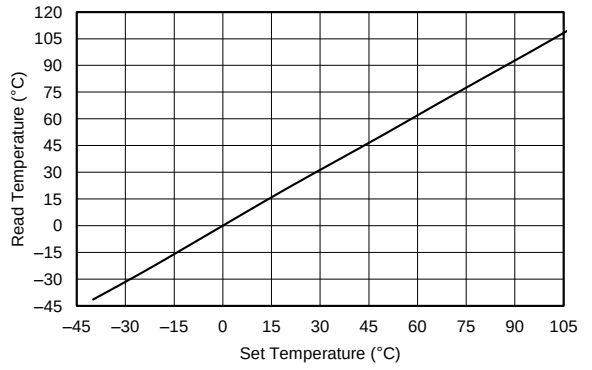


Figure 51. Temperature Sensor Response

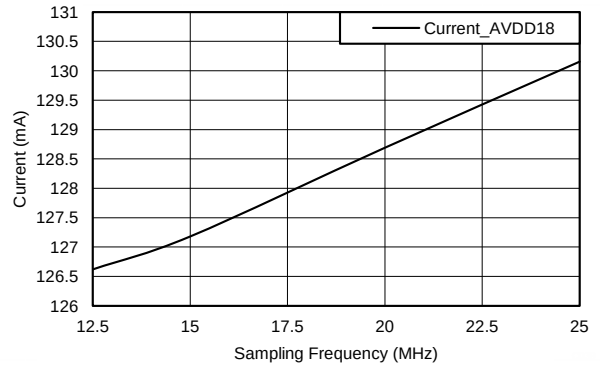


Figure 52. AVDD18 Supply Current vs Sampling Frequency

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Typical Characteristics (continued)

Typical values are at T_A = +25°C, AVDD18 = DVDD18 = 1.8 V, AVDD3 = DRVDD = 3.3 V, –1-dBFS analog input ac-coupled with a 0.1-µF capacitor, AFE_CLK = 25 MHz, LNA gain = 15 dB, PGA gain = 0 dB, default mode, antialiasing filter corner frequency = 8 MHz, and differential input sine wave clock with 50% duty cycle, unless otherwise noted.

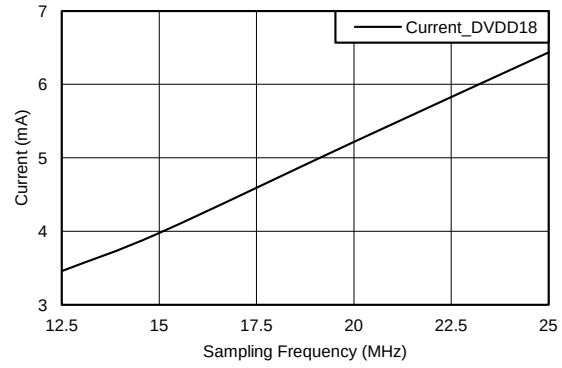


Figure 53. DVDD18 Supply Current vs Sampling Frequency

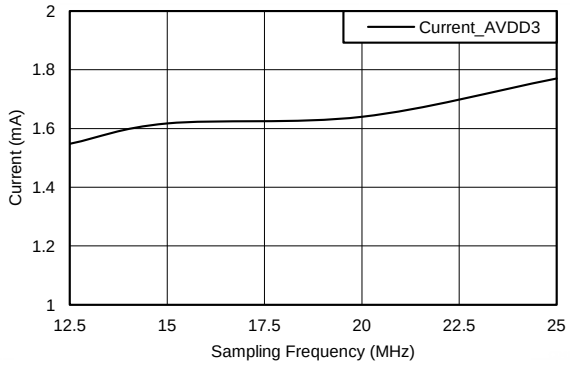


Figure 54. AVDD3 Supply Current vs Sampling Frequency

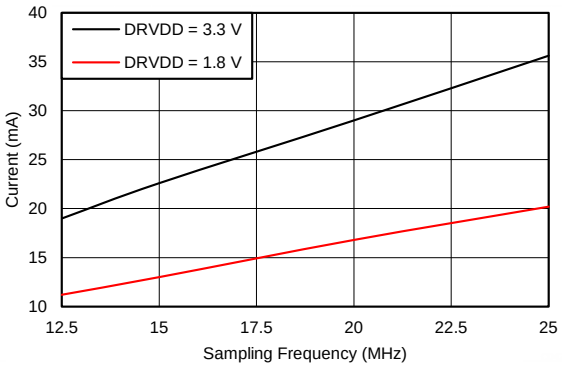


Figure 55. DRVDD Supply Current vs Sampling Frequency (15-pF Load with Toggle Test Mode)

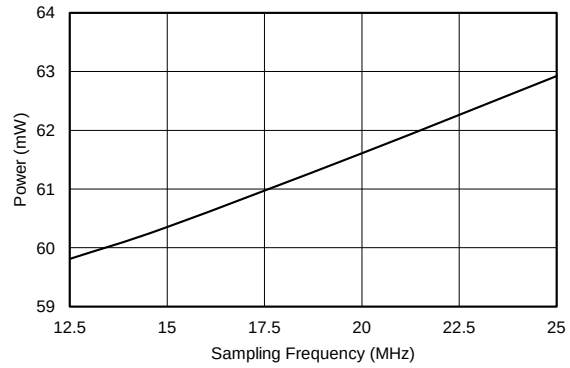


Figure 56. AFE Core Power, Channel Excluding DRVDD

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7 Parameter Measurement Information

7.1 Timing Requirements: Across Output Serialization Modes

Table 1 and Table 2 provide details for the 4x serialization timing requirements for DRVDD = 3.3 V and DRVDD = 1.8 V, respectively. Table 3 and Table 4 provide details for the 3x serialization timing requirements for DRVDD = 3.3 V and DRVDD = 1.8 V, respectively. Table 5 provides the details for the 2x and 1x serialization timing requirements for DRVDD = 1.8 V to 3.3 V.

Table 1. Timing Requirements: 4x Serialization (DRVDD = 3.3 V)

INPUT CLOCK FREQUENCY (MHz)	OUTPUT CLOCK (DCLK) FREQUENCY (MHz)	TEST CONDITIONS	SETUP TIME (ns) t_{SU}			HOLD TIME (ns) t_{HO}			t_{OUT} (ns)		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
12.5	50	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	9.1			7.9			6.7		9.5
15	60	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	7.1			6.1			6.7		9.5
20	80	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	5.3			4.1			6.7		9.5
25	100	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	4.1			2.8			6.7		9.5
25	100	C_{LOAD} = 15 pF, STR_CTRL_CLK, STR_CTRL_DATA = 6	3.5			2.6			6.4		9.0

Table 2. Timing Requirements: 4x Serialization (DRVDD = 1.8 V)

INPUT CLOCK FREQUENCY (MHz)	OUTPUT CLOCK (DCLK) FREQUENCY (MHz)	TEST CONDITIONS	SETUP TIME (ns) t_{SU}			HOLD TIME (ns) t_{HO}			t_{OUT} (ns)		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
12.5	50	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	9.2			7.9			5.6		10.6
15	60	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	7.2			6.1			5.6		10.6
20	80	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	5.3			3.9			5.6		10.6
25	100	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	3.7			2.7			5.6		10.6
25	100	C_{LOAD} = 15 pF, STR_CTRL_CLK and STR_CTRL_DATA = 14	2.6			2.7			5.3		10.0

Table 3. Timing Requirements: 3x Serialization (DRVDD = 3.3 V)

INPUT CLOCK FREQUENCY (MHz)	OUTPUT CLOCK (DCLK) FREQUENCY (MHz)	TEST CONDITIONS	SETUP TIME (ns) t_{SU}			HOLD TIME (ns) t_{HO}			t_{OUT} (ns)		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
12.5	37.5	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	12.4			11.8			20.1		23.2
15	45	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	9.9			9.1			17.4		20.4
20	60	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	7.2			6.3			15.1		18.0
25	75	C_{LOAD} = 5 pF, STR_CTRL_CLK, STR_CTRL_DATA = 0	5.7			4.1			13.4		16.0
25	75	C_{LOAD} = 15 pF, STR_CTRL_CLK and STR_CTRL_DATA = 6	5.1			3.8			12.8		15.3

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Table 4. Timing Requirements: 3x Serialization (DRVDD = 1.8 V)

INPUT CLOCK FREQUENCY (MHz)	OUTPUT CLOCK (DCLK) FREQUENCY (MHz)	TEST CONDITIONS	SETUP TIME (ns) t_{SU}			HOLD TIME (ns) t_{HO}			t_{OUT} (ns)		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
12.5	37.5	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	12.5			11.9			19.2		23.6
15	45	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	10.0			9.3			16.6		20.1
20	60	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	7.3			6.4			14.0		18.4
25	75	C_{LOAD} = 5 pF, STR_CTRL_CLK and STR_CTRL_DATA = 5	5.7			4.7			12.4		16.7
25	75	C_{LOAD} = 15 pF, STR_CTRL_CLK and STR_CTRL_DATA = 14	4.7			4			12.1		16.4

Table 5. Timing Requirements: 2x and 1x Serialization (DRVDD = 1.8 V to 3.3 V)

INPUT CLOCK FREQUENCY (MHz)	OUTPUT CLOCK (DCLK) FREQUENCY (MHz)	TEST CONDITIONS	SETUP TIME (ns) t_{SU}			HOLD TIME (ns) t_{HO}			t_{OUT} (ns)		
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
25	50	2x Serialization mode: C_{LOAD} = 5 pF. For DRVDD = 1.8 V, STR_CTRL_CLK and STR_CTRL_DATA = 5. For DRVDD = 3.3 V, STR_CTRL_CLK and STR_CTRL_DATA = 0.	7.3			8.0			5.5		10.5
25	25	1x Serialization mode: C_{LOAD} = 5 pF. For DRVDD = 1.8 V, STR_CTRL_CLK and STR_CTRL_DATA = 5. For DRVDD = 3.3 V, STR_CTRL_CLK and STR_CTRL_DATA = 0.	18.5			17.5			25.2		30.1

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8 Detailed Description

8.1 Overview

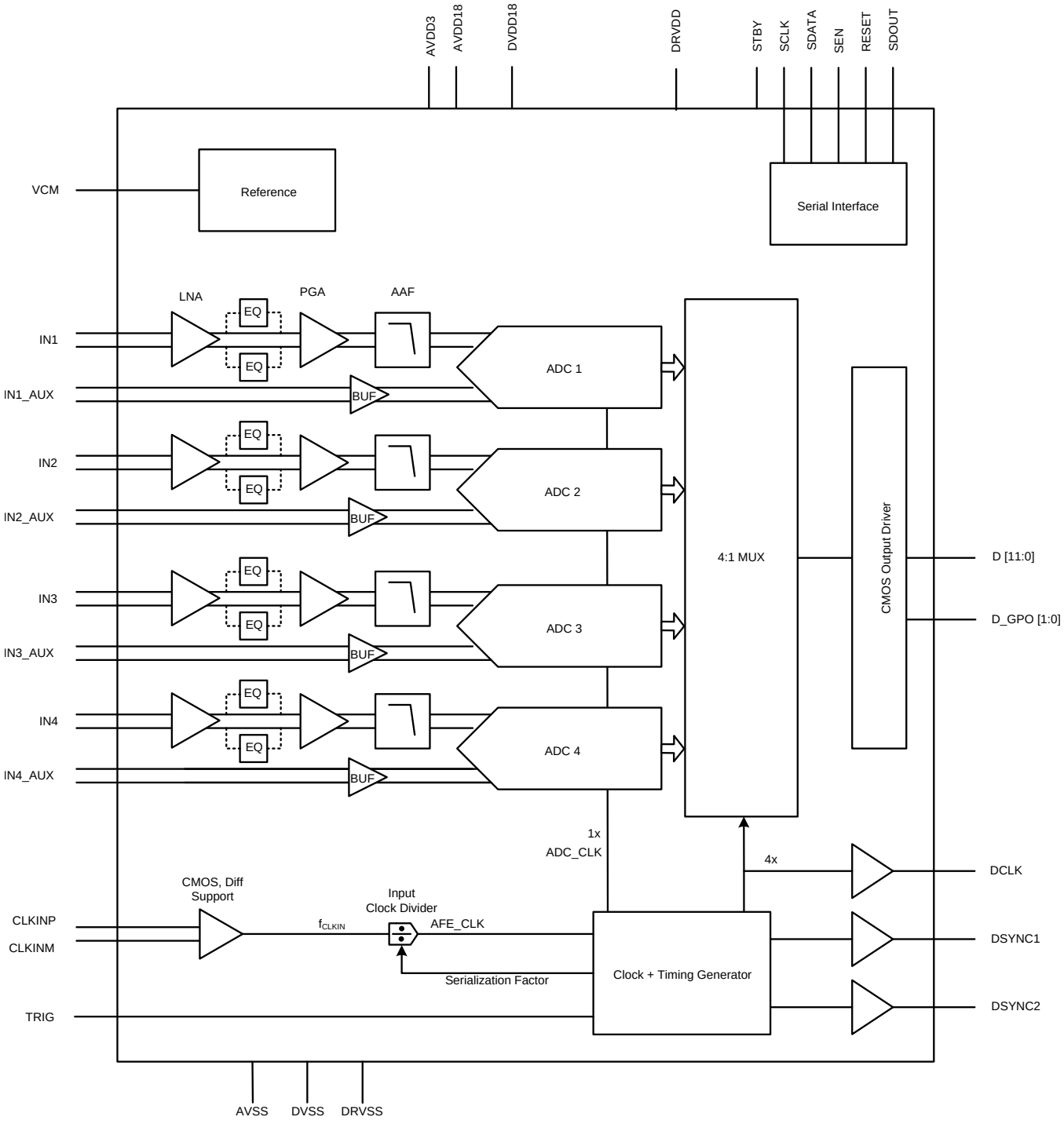
The AFE5401-Q1 is a very low-power, CMOS, monolithic, quad-channel, analog front-end (AFE). The signal path of each channel consists of a differential low-noise amplifier (LNA) followed by a differential programmable gain amplifier (PGA) in series with a differential antialias filter. The antialiasing filter output is sampled by a 12-bit, pipeline, analog-to-digital converter (ADC) based on a switched-capacitor architecture. Each ADC can also be differentially driven from IN_IP_AUX, IN_IM_AUX through an on-chip buffer (thus bypassing the LNA, PGA, and antialiasing filter).

Each block in the channel operates with a maximum 2-V_{PP} output swing. Each PGA has a programmable gain range from 0 dB to 30 dB, with a resolution of 3 dB.

After the input signals are captured by the sampling circuit, the samples are sequentially converted by a series of low-resolution stages inside the pipeline ADC at the clock rising edge. The outputs of these stages are combined in a digital logic block to form the final 12-bit word with a latency of 10.5 t_{AFE_CLK} clock cycles. The 12-bit words of all active channels are multiplexed and output as parallel CMOS levels. In addition to the data streams, a CMOS clock (DCLK) is also output. This clock must be used by the digital receiver [such as a digital signal processor (DSP)] to latch the AFE output parallel CMOS data.

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8.2 Functional Block Diagram



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8.3 Feature Description

8.3.1 Low-Noise Amplifier (LNA)

The analog input signal is buffered and amplified by an on-chip LNA. LNA gain is programmable with the LNA_GAIN register, as shown in Table 6.

Table 6. LNA_GAIN Register

LNA_GAIN	DESCRIPTION (dB)	LNA_GAIN_Linear
0	15	5.5
1	18	8
2	12	4
3	16.5	6.5

The LNA output is internally limited to 2 V_{PP}. Thus, the maximum-supported input peak-to-peak swing is set by 2 V / LNA_GAIN_Linear.

Input-referred noise in default mode is 2.9 nV/$\sqrt{Hz}$ at 30-dB PGA gain and 15-dB LNA gain. Input-referred noise can be further improved to 2.5 nV/$\sqrt{Hz}$ by enabling the HIGH_POW_LNA register bit. However, this noise reduction results in increased power dissipation.

8.3.2 Programmable Gain Amplifier (PGA)

The PGA amplifies the analog input signal by a programmable gain. Gain can be programmed using the PGA_GAIN register, common to all channels, in 3-dB steps with a gain range of 30 dB. In default mode, PGA gain ranges from 0 dB to 30 dB. In equalizer mode, PGA gain ranges from 15 dB to 45 dB. PGA_GAIN register settings are listed in Table 7. Figure 57 shows the typical SNR values across PGA gain.

Table 7. PGA_GAIN Register Settings

PGA_GAIN Settings	PGA GAIN IN DEFAULT MODE (dB)	PGA GAIN IN EQUALIZER MODE (dB)
0 (0 dB)	0.0	15.0
1 (3 dB)	2.9	17.9
2 (6 dB)	6.0	21.0
3 (9 dB)	8.8	23.8
4 (12 dB)	11.9	26.9
5 (15 dB)	14.8	29.8
6 (18 dB)	17.9	32.9
7 (21 dB)	20.8	35.8
8 (24 dB)	23.9	38.9
9 (27 dB)	26.8	41.8
10 (30 dB)	29.9	44.9

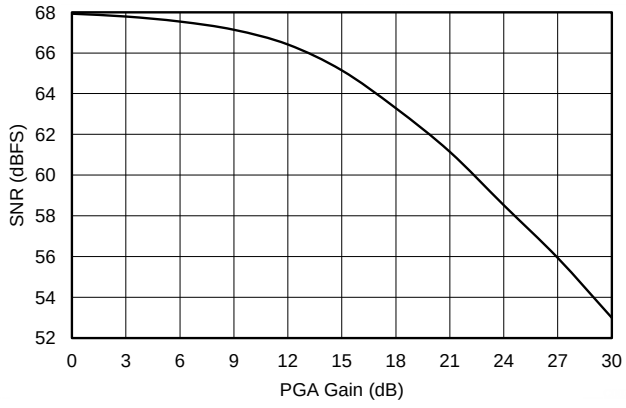


Figure 57. SNR Across PGA Gain

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8.3.3 Antialiasing Filter

The device introduces a third-order, elliptic, active, antialias, low-pass filter (LPF) in the analog signal path. The filter –3-dB corner frequency can be configured using the FILTER_BW register, as shown in Table 8. The corresponding frequency response plots are shown in Figure 58 and Figure 59.

Table 8. FILTER_BW Register

FILTER_BW	CORNER FREQUENCY (MHz)
0	8
1	7
2	10.5
3	12

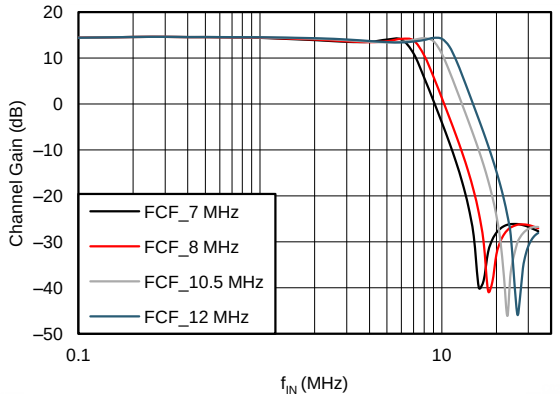


Figure 58. Filter Response Across Modes (PGA Gain = 0 dB)

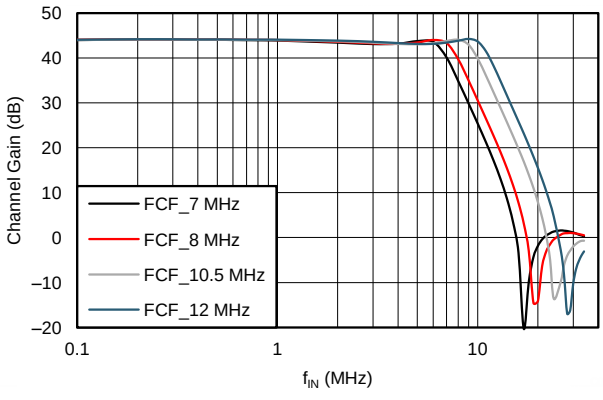


Figure 59. Filter Response Across Modes (PGA Gain = 30 dB)

8.3.4 Analog-to-Digital Converter (ADC)

The filtered analog input signal is sampled and converted into a digital equivalent code using a high-speed, low-power, 12-bit, pipeline ADC. The digital output of the device has a latency of 10.5 t_{AFE_CLK} cycles because of the pipeline nature of the ADC. The digitized output of the device is in binary twos complement (BTC) format. The output format can be changed to offset binary format with the OFF_BIN_DATA_FMT register bit.

8.3.5 Digital Gain

The ADC output can be incremented digitally using a digital gain block. Digital gain is common for all channels and can be configured by enabling MULT_EN and applying the desired DIG_GAIN. Channel gain is given by Equation 1:

$$\frac{V_{OUT}}{V_{IN}} = \frac{(DIG_GAIN + 32)}{32} \quad (1)$$

where:

- (DIG_GAIN + 32) is the mod 128 number.

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Figure 60 shows the typical digital gain curve for different DIG_GAIN values.

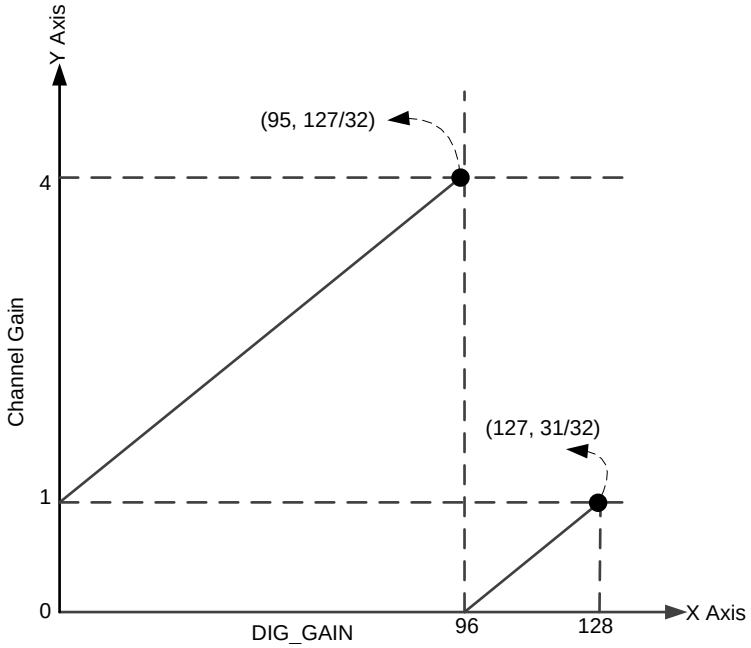


Figure 60. Digital Gain Graph

8.3.6 Input Clock Divider

The device clock input is passed through a clock divider block that can divide the input clock by a factor of 1, 2, 3, or 4. This divided clock (AFE_CLK) is used for simultaneously sampling the four ADC inputs. In default mode, a division factor of 1 is used where the AFE_CLK frequency is the same as the input clock frequency. The clock divider block can be enabled using the DIV_EN register bit and, when enabling this bit, the AFE_CLK frequency is automatically determined by the serialization factor set by the CH_OUT_DIS register bits (Table 12). The division factor can also be manually specified by enabling the DIV_FRC and DIV_REG register bits. Care must be taken to ensure that the input clock frequency is within the recommended operating range specified in the Recommended Operating Conditions.

After device reset, the divider is reset at the first pulse applied on the TRIG pin. This configuration is especially useful when using multiple devices in the system, where the sampling instants of all ADCs in the system must be synchronized. Figure 61 illustrates the TRIG timing diagram and the various divided-down AFE_CLK signals. Figure 62 provides the TRIG input setup and hold time with respect to the device clock input. Bit settings for the DIV_EN register, DIV_FRD register, and DIV_REG register are provided in Table 9, Table 10, and Table 11, respectively.

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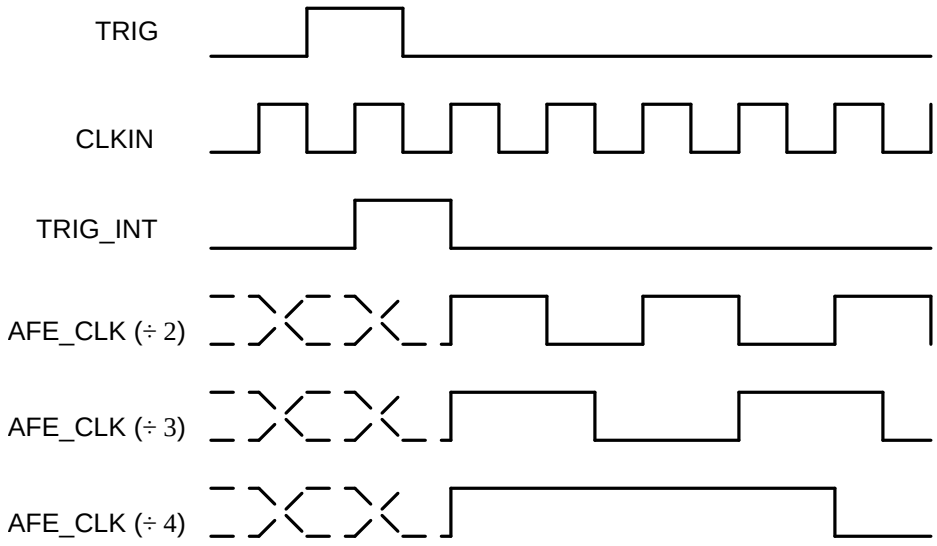


Figure 61. Input Clock Divider

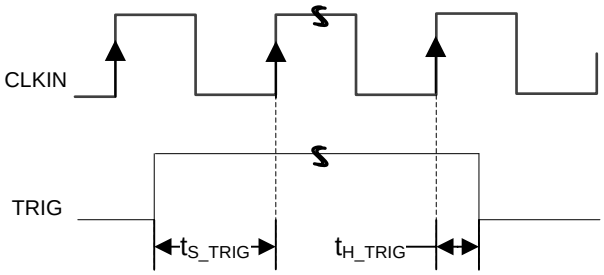


Figure 62. TRIG CLKIN Setup and Hold

Table 9. DIV_EN Register

DIV_EN	DESCRIPTION
0	Divider disabled and bypassed
1	Divider enabled

Table 10. DIV_FRC Register

DIV_FRC	DESCRIPTION
0	Input divider ratio = serialization factor(1) (automatically set)
1	Input divider ratio = DIV_REG (manually set)

(1) The divider ratio is automatically calculated to the serialization factor value based on the CH_OUT_DIS[1:4] register bits; see Table 12.

Table 11. DIV_REG Register

DIV_REG	DESCRIPTION
0	Divider disabled and bypassed
1	Divide-by-2
2	Divide-by-3
3	Divide-by-4

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8.3.7 Data Output Serialization

The input signals are digitized by the dedicated channel ADCs. Digitized signals are multiplexed and output on D[11:0] as parallel data.

The output data rate and the DCLK speed are automatically calculated based on the CH_OUT_DIS[1:4] bits. The number of zeroes in these four bits is equal to the serialization factor for the output data. When the register bit is set to 1, the output for the respective channel is disabled. The channels are arranged in ascending order, with the lowest active channel output first and the highest active channel output last. CH_OUT_DIS[1:4] controls only the output serialization and does not power-down individual channels. Table 12 lists the register values with the respective serialization factors and output sequence.

Table 12. CH_OUT_DIS Register

CH_OUT_DIS[1]	CH_OUT_DIS[2]	CH_OUT_DIS[3]	CH_OUT_DIS[4]	SERIALIZATION FACTOR	OUTPUT
0	0	0	0	4	CH1 → CH2 → CH3 → CH4
1	0	0	0	3	CH2 → CH3 → CH4
0	1	0	0	3	CH1 → CH3 → CH4
1	1	0	0	2	CH3 → CH4
0	0	1	0	3	CH1 → CH2 → CH4
1	0	1	0	2	CH2 → CH4
0	1	1	0	2	CH1 → CH4
1	1	1	0	1	CH4
0	0	0	1	3	CH1 → CH2 → CH3
1	0	0	1	2	CH2 → CH3
0	1	0	1	2	CH1 → CH3
1	1	0	1	1	CH3
0	0	1	1	2	CH1 → CH2
1	0	1	1	1	CH2
0	1	1	1	1	CH1
1	1	1	1	1	Not supported

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8.3.8 Setting the Input Common-Mode Voltage for the Analog Inputs

8.3.8.1 Main Channels

The device analog input consists of a differential LNA. The common-mode for the LNA inputs is internally set using two internal, programmable, single-ended resistors, as shown in Figure 63.

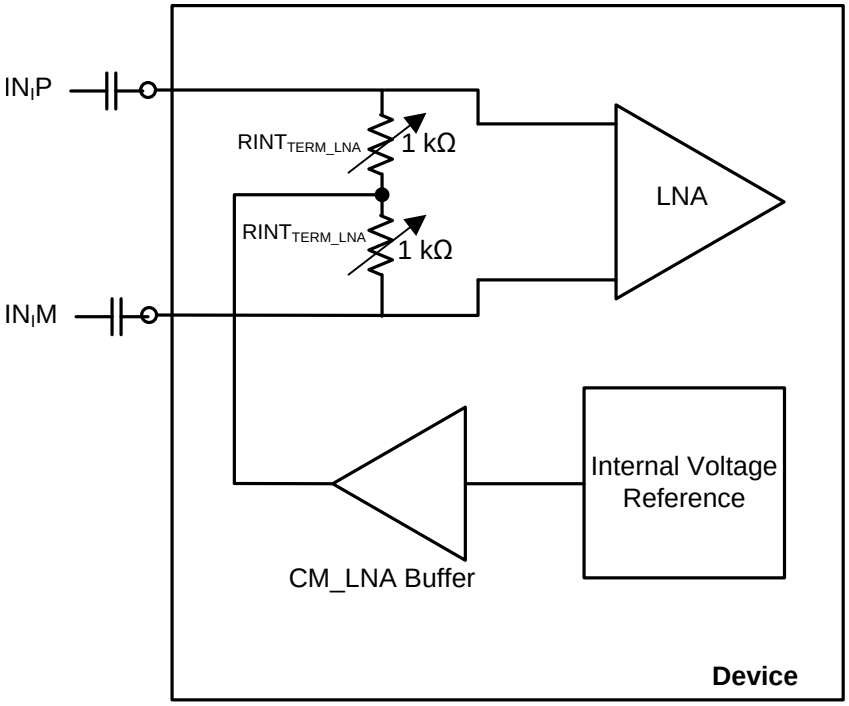


Figure 63. Common-Mode Biasing of LNA Input Pins

These resistors can be programmed to a higher value using the TERM_INT_20K_LNA register setting as described in Table 13.

Table 13. Internal Termination Register Setting (LNA)

TERM_INT_20K_LNA	DESCRIPTION
0	$RINT_{TERM_LNA}$ = 1 kΩ
1	$RINT_{TERM_LNA}$ = 10 kΩ

Hence, for proper operation, the input signal must be ac-coupled. Note that external input ac-coupling capacitors form a high-pass filter (HPF) with $RINT_{TERM_LNA}$. Therefore, the capacitor values should allow the lowest frequency of interest to pass with minimum attenuation. For typical frequencies greater than 1 MHz, a value of 50 nF or greater is recommended. The maximum input swing is limited by the LNA gain setting. LNA output swing is limited to 2 V_{PP} before the output becomes saturated or distorted.

Single ended mode of operation is also possible by connecting non-driven input pin to ground through a capacitor of 100 nF. However, this will result in reduced linearity.

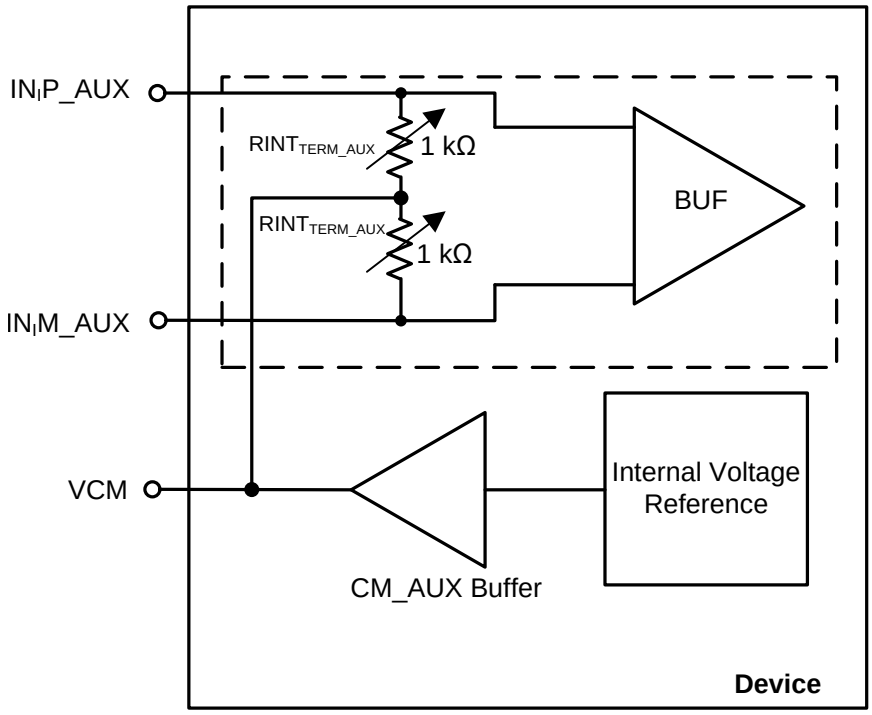
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8.3.8.2 Auxiliary Channel

The auxiliary analog inputs (IN_IP_AUX, IN_IM _AUX) can be enabled instead of the IN_IP, IN_IM inputs using the AUX_CH_I_EN bits (Table 14). The auxiliary analog input signal path consists of an input unity-gain buffer followed by an ADC. The LNA, PGA, equalizer, and antialiasing filter are bypassed and powered down in this mode. Figure 64 shows the internal block diagram for auxiliary channel mode. When this mode is enabled, the maximum input swing is limited to 2 V_{PP} before the input becomes saturated or distorted.

Table 14. AUX_CH_I_EN Register

AUX_CH_I_EN	DESCRIPTION
0	IN_IP, IN_IM active, analog
1	IN_IP _AUX, IN_IM_AUX



NOTE: Dashed area denotes one of four channels.

Figure 64. Common-Mode Biasing of Auxiliary Channel Input Pins

The dc common-mode on the IN_IP_AUX, IN_IM _AUX pins are internally biased to the optimum voltage (referred to as VCM).

The dc common-mode biasing is set with two internal, programmable, single-ended resistors ($RINT_{TERM_AUX}$). These resistors can be programmed to a higher value using the TERM_INT_20K_AUX register setting as described in Table 15.

Table 15. Internal Termination Register Setting (AUX)

TERM_INT_20K_AUX	DESCRIPTION
0	$RINT_{TERM_AUX}$ = 1 kΩ
1	$RINT_{TERM_AUX}$ = 10 kΩ

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The auxiliary inputs can also be ac-coupled as a result of the internal common-mode setting. The external input ac-coupling capacitors form a high-pass filter with $RINT_{TERM_AUX}$. Therefore, the capacitor values should allow the lowest frequency of interest to pass with minimum attenuation.

For typical frequencies greater than 1 MHz, a value of 50 nF or greater is recommended. For instances where the input signal cannot be ac-coupled because of system requirements, it is recommended to use the VCM output to set the dc common-mode of the input signal. The driving capability of VCM is limited. A 100-nF capacitor should be connected on each VCM input to AVSS.

8.4 Device Functional Modes

8.4.1 Equalizer Mode

In some applications, the input signal power linearly decreases with signal frequency. Such types of input spectrum can be equalized using a first-order signal equalizer. The device can be configured in two different equalizer modes: EQ_EN and EQ_EN_LOW_FC. Table 16 lists the register settings for these modes.

- EQ_EN mode: In this mode, a high-pass filter (HPF) is added to the analog signal path between the LNA output and PGA input.
- EQ_EN_LOW_FC mode: In this mode, attenuation from the HPF is limited to unity in the pass-band frequency range.

Table 16. EQ_EN and EQ_EN_LOW_FC Registers

EQ_EN	EQ_EN_LOW_FC	DESCRIPTION
0	0	Default mode
0	1	Default mode
1	0	Equalizer enabled
1	1	Equalizer with low-corner frequency enabled

The HPF and LPF cutoff frequencies (of the antialiasing filter) are the same as per the FILTER_BW setting. In this mode, overall channel gain increases by an additional fixed gain of 15 dB from the HPF block. Typical frequency response plots showing different equalizer modes along with the default mode are shown in Figure 65 and Figure 66.

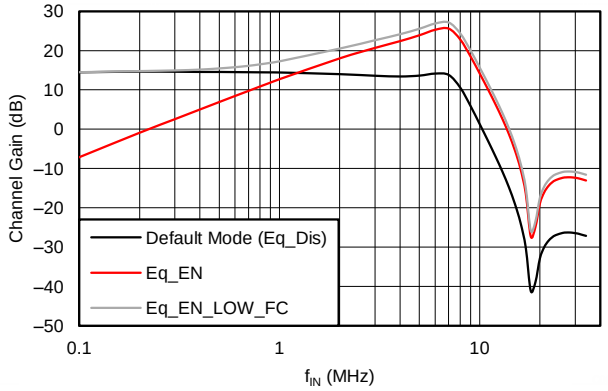


Figure 65. Filter Response (PGA Gain = 0 dB)

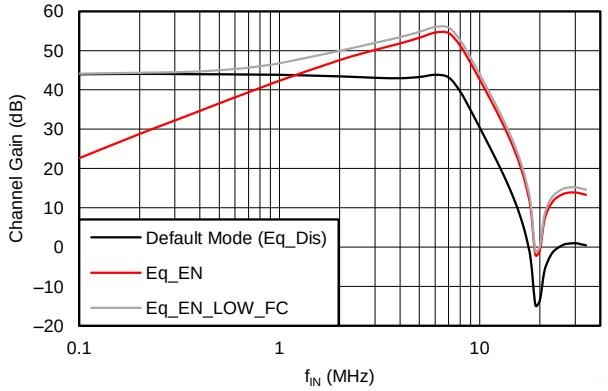


Figure 66. Filter Response (PGA Gain = 30 dB)

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8.4.2 Data Output Mode

The functionality of DSYNC1, DSYNC2, DCLK, and D[11:0] are controlled by selecting the data output mode. The functionality of the DSYNC1, DSYNC2, DCLK, and D[11:0] output pins for 4x serialization modes are shown in Figure 67 and Figure 68. Any event on the TRIG pin triggers the DSYNC1 and DSYNC2 signals. The DSYNC1 period is determined by the COMP_DSYNC1 register value and the DSYNC2 period is determined by the SAMPLE_COUNT register value. When OUT_MODE_EN = 0, data output is continuous. When OUT_MODE_EN = 1, data is active only during the sample phase. Output pins are configured using the registers described in Table 17 through Table 21.

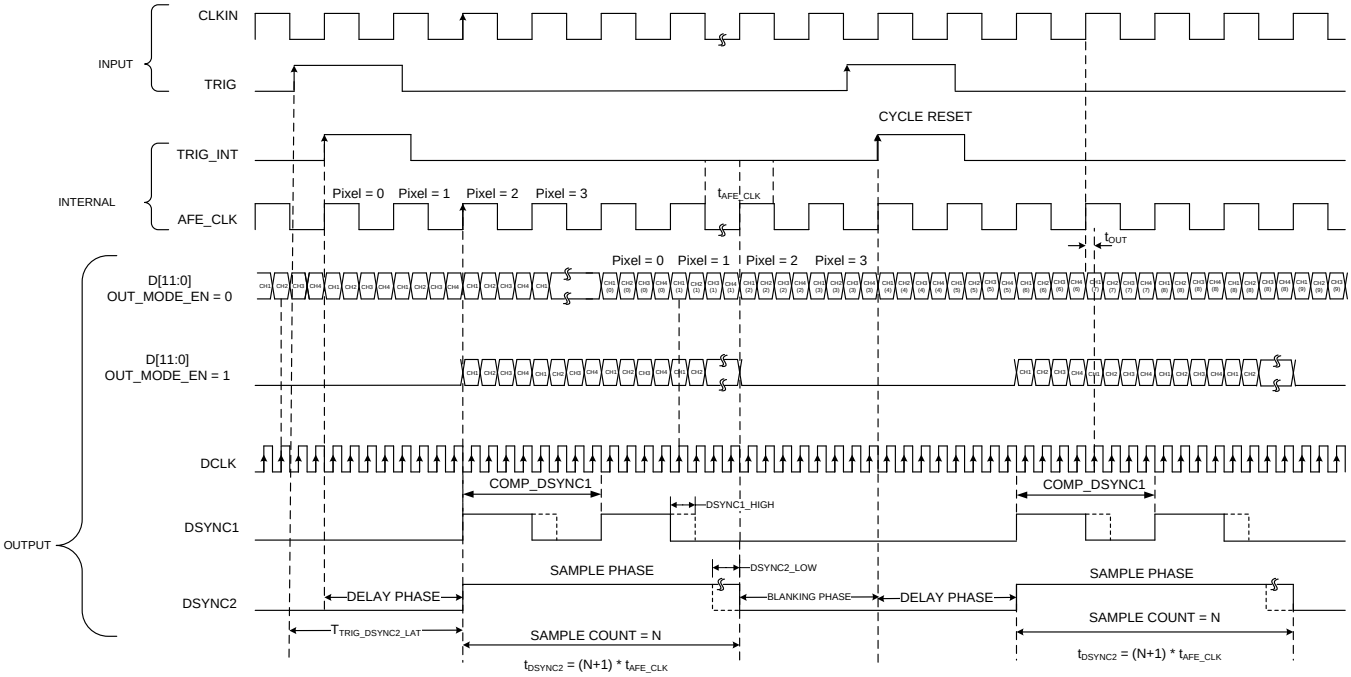


Figure 67. Data Output Timing Diagram (4x Serialization)

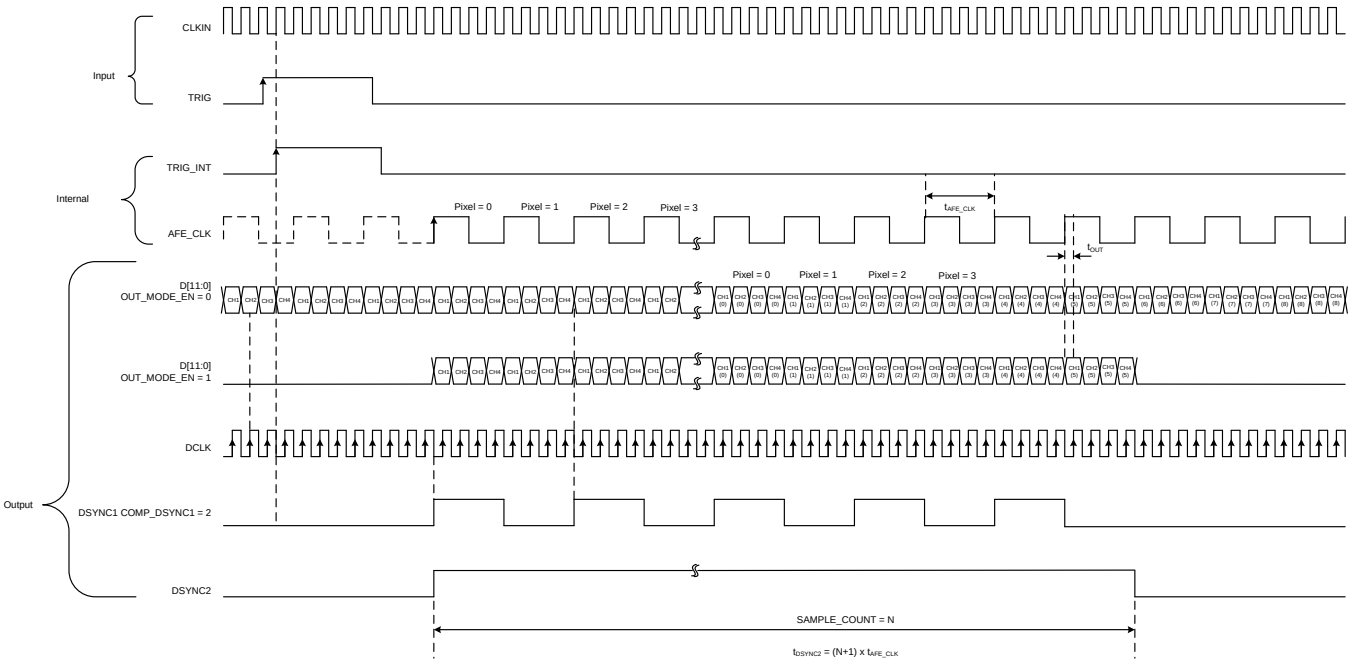


Figure 68. Data Output Timing Diagram (4x Serialization, Input Divider Enabled)

Table 17. Register Functions

REGISTER	FUNCTION
DELAY_COUNT[23:0]	From a TRIG event, the sample phase is delayed for a DELAY_COUNT number of t_{AFE_CLK} cycles
SAMPLE_COUNT[23:0]	From the end of DELAY_PHASE, the sample phase duration is the SAMPLE_COUNT number of t_{AFE_CLK} cycles
COMP_DSYNC1[15:0]	DSYNC1 period in number of t_{AFE_CLK}cycles

Table 18. DSYNC1_START_LOW Register

DSYNC1_START_LOW	DESCRIPTION
0	DSYNC1 is high at the sample phase start
1	DSYNC1 is low at the sample phase start

Table 19. OUT_MODE_EN Register

OUT_MODE_EN	DESCRIPTION
0	Data always active
1	Data active in sample phase

Table 20. DSYNC_EN Register

DSYNC_EN	DESCRIPTION
0	Disable DSYNC generation
1	Enable DSYNC generation

Table 21. OUT_BLANK_HIZ Register

OUT_BLANK_HIZ	DESCRIPTION
0	D[11:0] is low during inactive phase
1	D[11:0] is high impedance during inactive phase

NOTE

The signal processing blocks in the device are always active and are not controlled by output mode configuration settings.

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The functionality of the DSYNC1, DSYNC2, DCLK, and D[11:0] output pins with the input divider enabled for 3x serializations is shown in Figure 69.

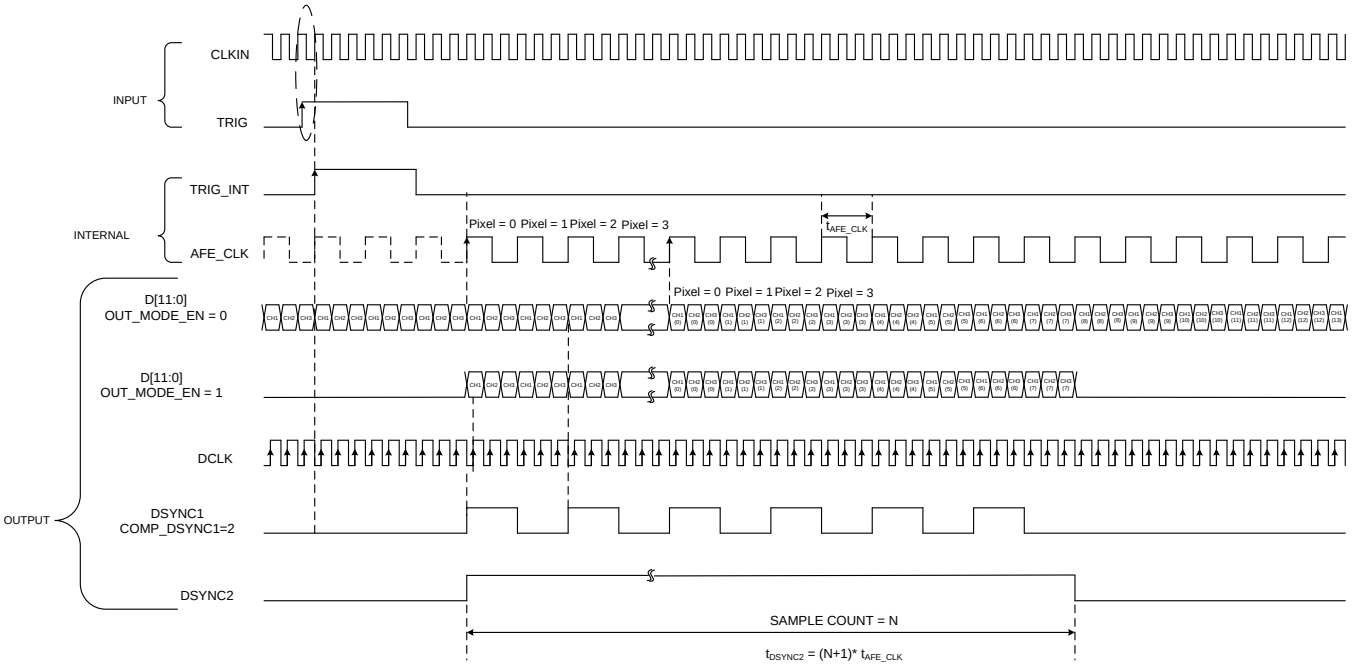


Figure 69. Data Output Timing (3x Serialization, Input Divider Enabled)

The TRIG to DSYNC2 latency is given by Table 22.

Table 22. TRIG to DSYNC2 Latency across Serialization Modes for AFE_CLK = 25 MHz

Serialization Modes	$T_{TRIG_DSYNC2_LAT}$ (1)	Units
4x	230	ns
3x	230	ns
2x	240	ns
1x	250	ns

(1) The TRIG_DSYNC2_LAT delay can vary by ± 8 ns.

8.4.2.1 Header

Each channel has an associated 12-bit header register. These registers can be written by an SPI write. The content of this register can be read out on the CMOS data output (D[11:0]) by configuring the HEADER_MODE register, as shown in Table 23.

Table 23. HEADER_MODE Register

HEADER_MODE	DESCRIPTION
0	ADC data at output
1	Header data at output
2	[Temperature data, diagnostic data, mean, noise, (-1), (-1), (-1), (-1)]. This data sequence is repeated.
3	Header data, temperature data, diagnostic data, mean, noise, ADC data

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In HEADER_MODE = 3, the header mode data output is shown in Figure 70.

In this mode, header data is transmitted with a latency with respect to the TRIG input. This latency is given by Equation 2:

TRIG to Header Latency ($T_{TRIG_HEADER_LAT}$) = t_{AFE_CLK} + $T_{TRIG_DSYNC2_LAT}$ (2)

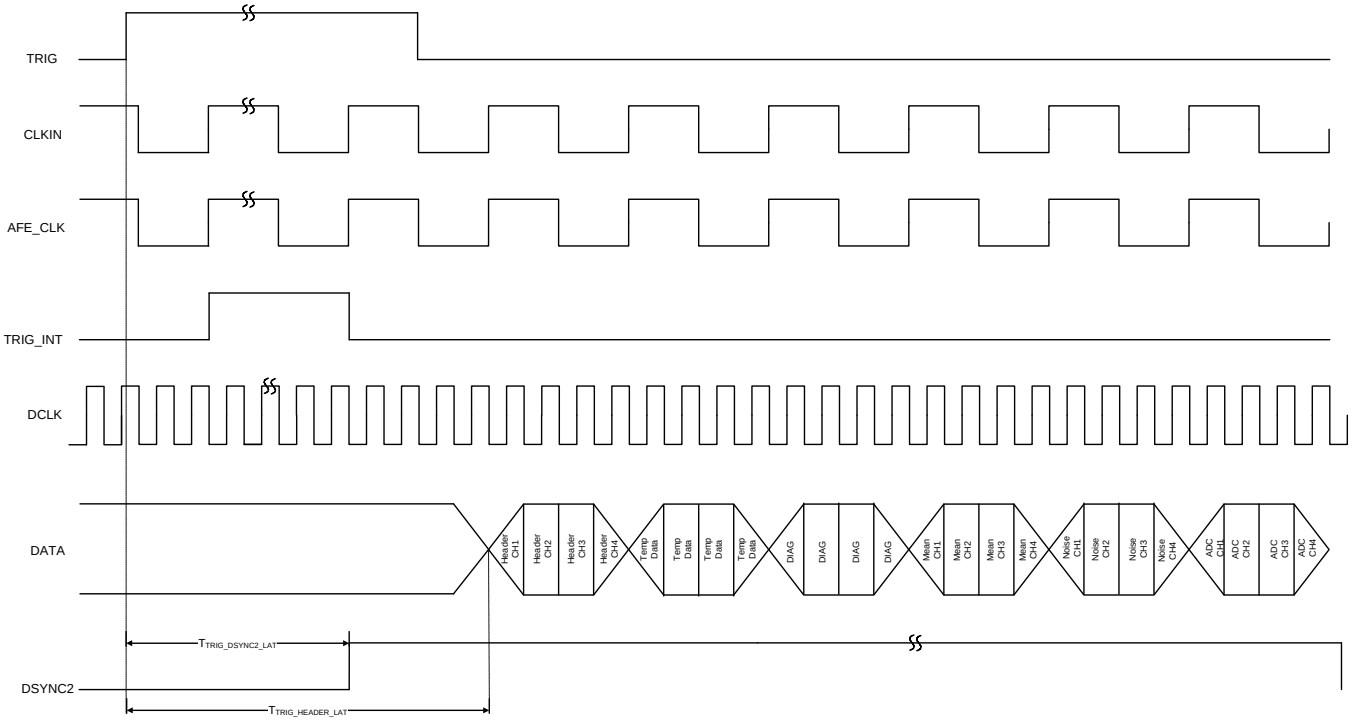


Figure 70. Header Mode Data Output (HEADER_MODE = 3)

8.4.2.2 Test Pattern Mode

In order to check the interface between the AFE and the receiver system, a test pattern can be directly programmed on the CMOS output. As shown in Table 24, different test patterns can be selected by setting the TST_PAT_MODE register.

Table 24. TST_PAT_MODE Register(1)

TST_PAT_MODE	DESCRIPTION
0	Normal ADC output data
1	SYNC pattern (D[11:0] = 111111000000)
2	Deskew pattern (D[11:0] = 010101010101)
3	Custom pattern as per CUSTOM_PATTERN[11:0] register bits
4	All 1s
5	Toggle data (output toggles between all 0s and all 1s)
6	All 0s
7	Full-scale ramp data

(1) In decimate-by-2 mode, alternate samples are dropped and thus output data D0 does not toggle for full-scale ramp data and output data D[11:0] does not toggle for toggle data.
Similarly, in decimate-by-4 mode, three samples are dropped and thus output data D0 and D1 do not toggle for full-scale ramp data and output data D[11:0] does not toggle for toggle data.

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8.4.3 Parity

Parity for each output sample of an active channel can be read on the D_GPO[1:0] pins by configuring these pins with the DGPO1_MODE, DGPO0_MODE register, as shown in Table 25. Parity generation can be enabled using the D_GPO_EN bit, as shown in Table 26. The type of parity generation can be configured to odd or even based on the PARITY_ODD bit, as shown in Table 27.

Table 25. DGPO0_MODE, DGPO1_MODE Register

DGPO0_MODE, DGPO1_MODE	DESCRIPTION
0	Low
1	Parity
2	Overload
3	D[11]

Table 26. D_GPO_EN Register

D_GPO_EN	DESCRIPTION
0	D_GPO[x] pins are disabled
1	D_GPO[x] pins are enabled

Table 27. PARITY_ODD Register

PARITY_ODD	DESCRIPTION
0	Even
1	Odd

8.4.4 Standby, Power-Down Mode

The device can be put into standby mode with the STDBY register bit. In this mode, all blocks except the ADC reference blocks are powered down. In GLOBAL_PDN mode, all blocks including the ADC reference blocks are powered down. However, in both modes, the serial interface is active.

8.4.5 Digital Filtering to Improve Stop-Band Attenuation

The device introduces a standard 11-tap, symmetric finite impulse response (FIR) digital filter for additional stop-band attenuation in decimate-by-2 and decimate-by-4 modes. In both modes, the FIR digital filter coefficients (C1 to C6) must be configured to obtain the desired filter characteristics. However, set 1 coefficients are loaded by default at device reset.

In this mode, device power consumption increases and the DSYNC period scales according to the decimation mode (the DSYNC period increases by 2x in decimate-by-2 mode and 4x in decimate-by-4 mode when compared to normal mode). Maximum AFE_CLK frequency supported in the decimation modes is 50 MHz.

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8.4.5.1 Decimate-by-2 Mode

In this mode, the DECIMATE_2_EN and FILT_EN register bits must be set, and the filter coefficients should be configured. Figure 71 shows typical filter response in decimate-by-2 mode for the filter coefficient of set 1 (default). Note that the output data rate is reduced by a factor of 2 as compared to default mode for the given clock input frequency.

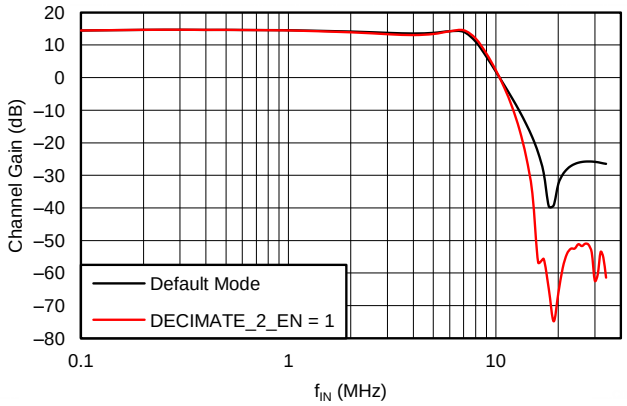
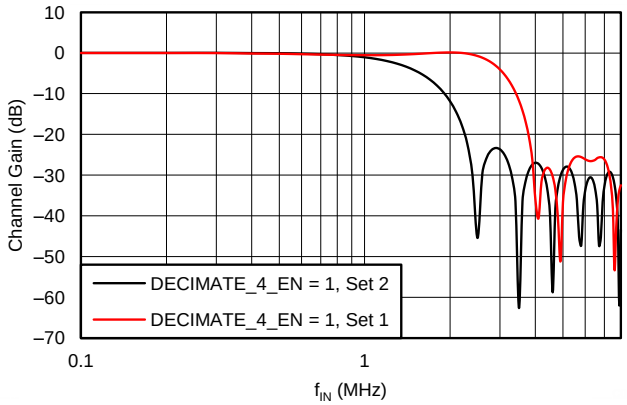


Figure 71. Decimate-by-2 Filter Response (f_S = 50 MHz)

8.4.5.2 Decimate-by-4 Mode

In this mode, the DECIMATE_2_EN, DECIMATE_4_EN, and FILT_EN register bits must be set, and the filter coefficients should be configured. Figure 72 shows a typical filter response in decimate-by-4 mode for the filter coefficient of set 1 (default) and set 2. Note that the output data rate is reduced by a factor of 4 as compared to default mode for the given clock input frequency.



(1) Set 1: C1 = 5, C2 = 2, C3 = –13, C4 = –2, C5 = 38, and C6 = 66. Set 2: C1 = –5, C2 = –2, C3 = 7, C4 = 19, C5 = 30, and C6 = 34.

Figure 72. Decimate-by-4 Filter Response (f_S = 12.5 MHz)

8.4.6 Diagnostic Mode

The device offers various diagnostic modes to check proper device operation at a system level. These modes can be enabled using the SPI and the outputs of these modes are stored in diagnostic read-only registers.

1. Internal reference status check: In this mode, the on-chip band-gap voltage, ADC reference, and clock generation are verified for functionality. Reading a 0 on these bits indicates that these blocks are functioning properly. The DIAG_MODE_EN register bit must be set to 1. The DIG_REG register bits for this mode are:
   – DIG_REG[0] for ADC references,
   – DIG_REG[1] for band gap, and
   – DIG_REG[2] for clock generation.

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2. DC input force: In this mode, a dc voltage can be internally forced at the LNA input to test the entire signal chain. During this test, the device analog inputs should be left floating. This mode can be asserted by setting the DC_INP_EN bit to 1 and programming the DC_INP_PROG[0:2] bits. In this mode, the equalizer is disabled internally.
3. Variance (noise) and mean measurement: Variance and mean of the ADC output can be analyzed using the on-chip STAT module. The STAT_EN, STAT_CALC_CYCLE, and STAT_CH_SEL, STAT_CH_AUTO_SEL options should be set to compute the variance and mean. These values can be monitored using channel-specific, read-only registers. Alternatively, these values can also be read using HEADER_MODE. Output variance and mean calculation is determined by Equation 3.

$$VARIANCE = \sum_{k=0}^{k=2^{(STAT_CALC_CYCLE+1)}} \frac{|x(k) - MEAN|}{2^{(STAT_CALC_CYCLE+1)}}$$

$$MEAN = \sum_{k=0}^{k=2^{(STAT_CALC_CYCLE+1)}} \frac{|x(k)|}{2^{(STAT_CALC_CYCLE+1)}} \quad (3)$$

STAT_CALC_CYCLE must be set to a large value to obtain better accuracy. Mean provides the average dc value of the ADC output (mid code). The STAT module integration time is defined by: $t_{AFE_CLK} \times 2^{(STAT_CALC_CYCLE+1)}$ when the STAT_CH_SEL option is selected. When STAT_CH_AUTO_SEL is enabled, the STAT module integration time is defined by: $4 \times t_{AFE_CLK} \times 2^{(STAT_CALC_CYCLE+1)}$.

4. Temperature sensor: The device junction temperature measurement can be enabled and monitored using TEMP_SENS_EN and TEMP_CONV_EN. The temperature output is saved in a diagnostic read-only register, TEMP_DATA. Alternatively, this data can also be read using HEADER_MODE. The TEMP_DATA value is a 9-bit, twos complement data in degrees Celsius. The temperature data is internally updated as per Equation 4:

$$\text{Temperature Data Update Cycle} = 1024 \times T_{AFE_CLK} \times 16 \quad (4)$$

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8.4.7 Signal Chain Probe

To enhance system-level debug capabilities, the device offers a mode where the output of each block in the signal chain can be connected to the ADC input. With this mode, internal signals can be easily monitored to ensure that each block output is not saturated. Figure 73 shows the device signal chain block diagram. Figure 74 and Figure 75 show typical frequency response plots at the output of each stage.

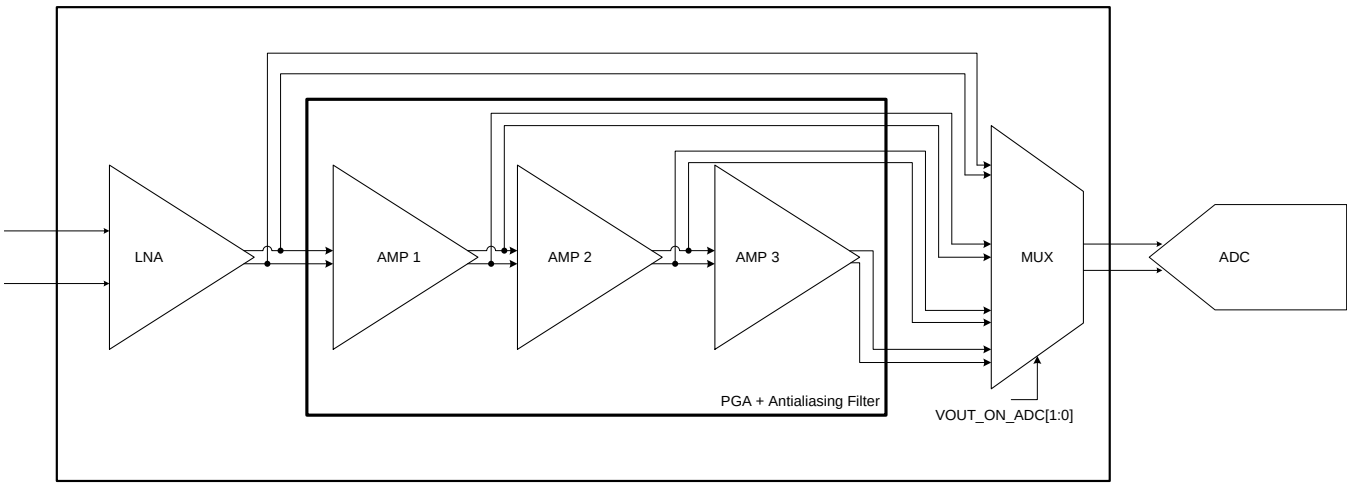


Figure 73. Signal Chain Block Diagram

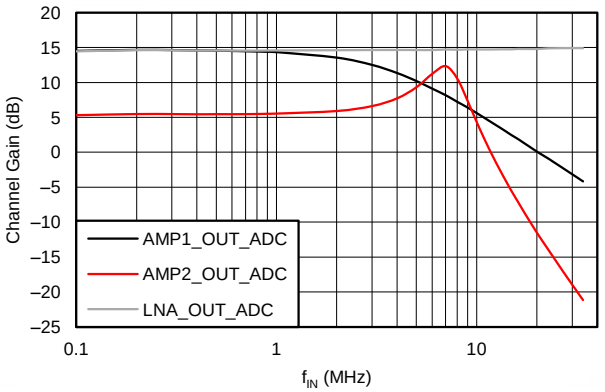


Figure 74. Frequency Response for VOUT_ON_ADC Settings (PGA Gain = 0 dB)

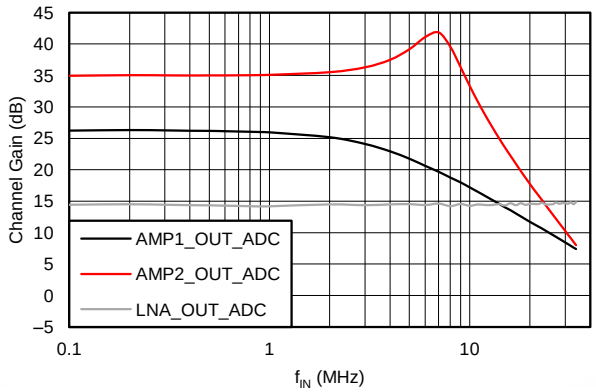


Figure 75. Frequency Response for VOUT_ON_ADC Settings (PGA Gain = 30 dB)

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8.5 Programming

8.5.1 Serial Interface

Different modes can be programmed through the serial interface formed by the SEN (serial interface enable), SCLK (serial interface clock), SDATA (serial interface data) and RESET pins. SCLK and SDATA have a 150-kΩ pull-down resistor to ground and SEN has a 150-kΩ pull-up resistor to DVDD18. Serially shifting bits into the device is enabled when SEN is low. SDATA serial data bits are latched at every SCLK rising edge when SEN is active (low). Serial data bits are loaded into the register at every 24th SCLK rising edge when SEN is low. If the word length exceeds a multiple of 24 bits, the excess bits are ignored. Data bits can be loaded in multiples of 24-bit words within a single active SEN pulse (an internal counter counts groups of 24 clocks after the SEN falling edge). The interface can function with SCLK frequencies from 20 MHz down to very low speeds and even with a non-50% duty-cycle SCLK. Data bits are divided into two main portions: a register address (8 bits, A[7:0]) and data (16 bits, D[15:0]).

8.5.2 Register Initialization

After power up, the internal registers must be initialized to the default value (0). Initialization can be accomplished in one of two ways:

- Either through a hardware reset, by applying a positive pulse to the RESET pin, or
- Through a software reset with the serial interface, by setting the SW_RST bit high. Setting this bit initializes the internal registers to the respective default values (all 0s) and then self-resets the SW_RST bit low. In this case, the RESET pin can stay low (inactive).

NOTE

- No damage occurs to the part by applying voltage to the RESET pin while device power is off.
- For correct device operation, a positive pulse must be applied to the RESET pin. This pulse sets the internal control registers to 0. However, no power-supply sequencing is required.
- Reset only affects the digital registers and places the device in a default state. Reset does not function as a power-down and, therefore, all internal blocks are functional.

During a register write through the SPI, the effects on data propagate through the pipe while the internal registers change values. At the same time, some glitches may be present on the output because of the transition of register values (for instance, if any output-controlling modes change). The signal on the RESET pin must be low in order to write to the internal registers because reset is level-sensitive and asynchronous with the input clock. Although only 40 ns are required after the RESET rising edge to change the registers, the output data may take up to 20 clock cycles (worst-case) to be considered stable. For more information on RESET, see the Timing Requirements: RESET.

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Programming (continued)

8.5.2.1 Register Write Mode

In register write mode, the REG_READ_EN bit must be set to 0. In this mode, the SDOUT signal outputs 0. Figure 76 shows this process.

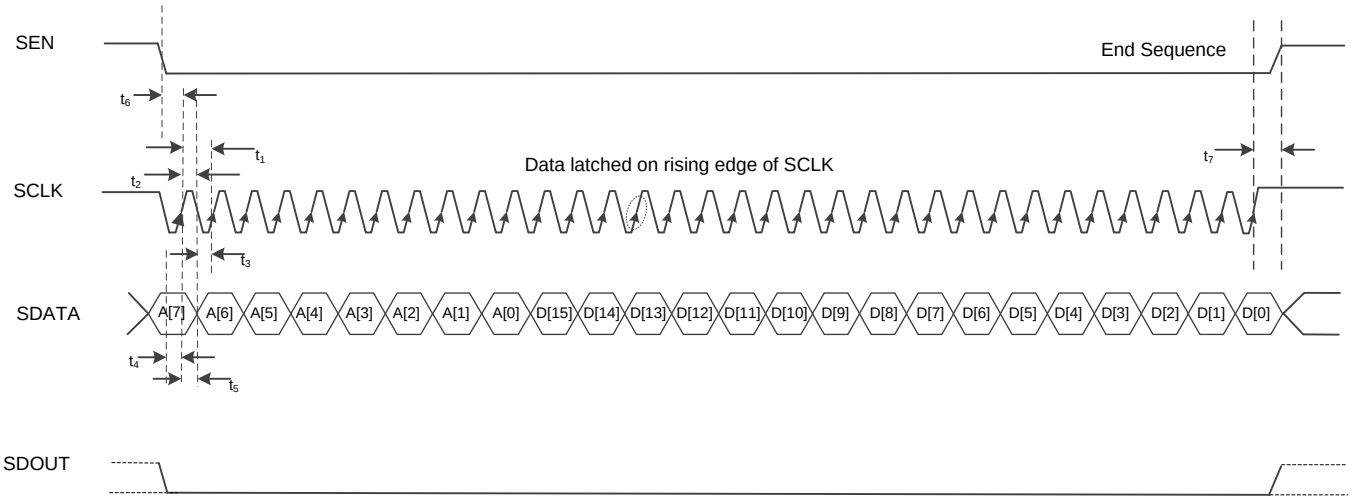


Figure 76. Serial Interface Register Write

8.5.2.2 Register Read Mode

In register readout mode, the REG_READ_EN bit must be set to 1. Then, a serial interface cycle should be initiated, specifying the address of the register (A[7:0]) whose content must be read out of the device. The data bits are *don't care*. The device outputs the contents (D[15:0]) of the selected register on the SDOUT pin. The external controller latches the data on SDOUT at the SCLK rising edge. Figure 77 shows this process.

The timing specifications for the serial interface operation is listed in the Timing Requirements: Serial Interface Operation.

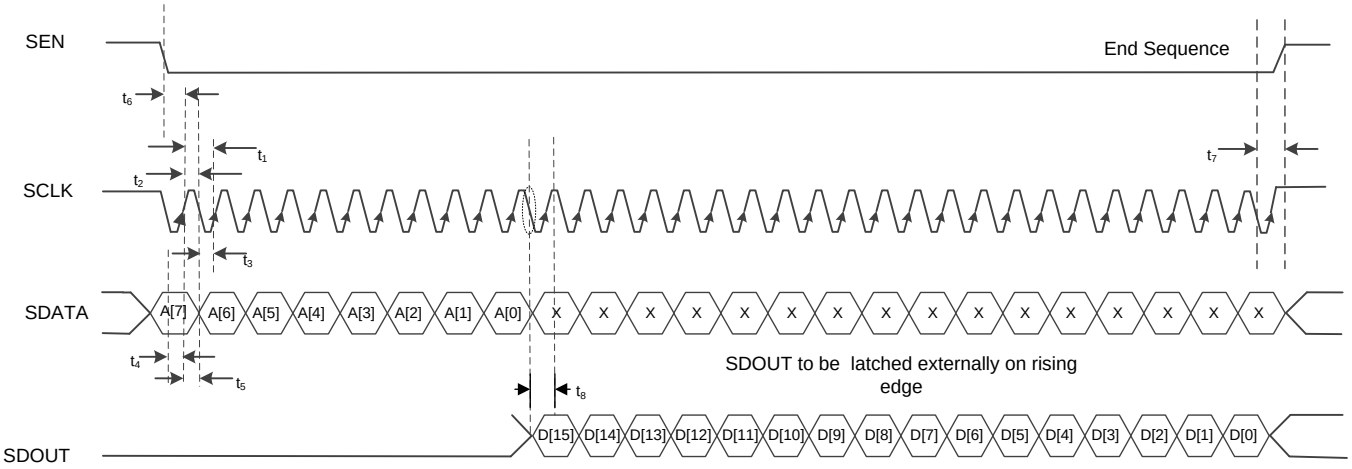


Figure 77. Serial Interface Register Readout Enable

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Programming (continued)

8.5.3 CMOS Output Interface

The digital data from the four channels are multiplexed and output over a 12-bit parallel CMOS bus to reduce the device pin count. In addition to the data, a CMOS clock (DCLK) is also output, which can be used by the digital receiver to latch the AFE output data. The output data and clock buffers can typically drive a 5-pF load capacitance in default mode. To drive larger loads (10 pF to 15 pF), the strength of the CMOS output buffers can be increased using the STR_CTRL_CLK and STR_CTRL_DATA register bits. Note that the setup and hold time of the output data (with respect to DCLK) degrade with higher load capacitances. See Table 1, which provides timings for 5-pF and 15-pF load capacitances.

8.5.3.1 Synchronization and Triggering

While the digital data from the four channels is multiplexed on the output bus, some mechanism is required to identify the data from the individual channels. Other than the output data and DCLK, the device also outputs DSYNCx signals that can be used for channel identification.

The DSYNCx output signals function with the TRIG input signal. Every time that a trigger pulse is received on the TRIG pin, the device outputs the DSYNC1 and DSYNC2 signals. The DSYNCx signals can be configured in the following ways:

- The delay between the arrival of the TRIG signal and the DSYNCx signal becoming active is programmable in a number of AFE_CLK cycles (using the DELAY_COUNT register bit).
- The period of the DSYNC1 signal is programmable in terms of AFE_CLK clock cycles by using the COMP_DSYNC1 register bits.
- The active time of the DSYNC2 signal is programmable using the SAMPLE_COUNT register bits.

The rising edge of the DSYNC1 signal coincides with the channel 1 data, as shown in Figure 78. This occurrence can be used by the receiving device to identify individual channels.

The sample phase period corresponds to the period when valid data is available from the device when OUT_MODE_EN = 1.

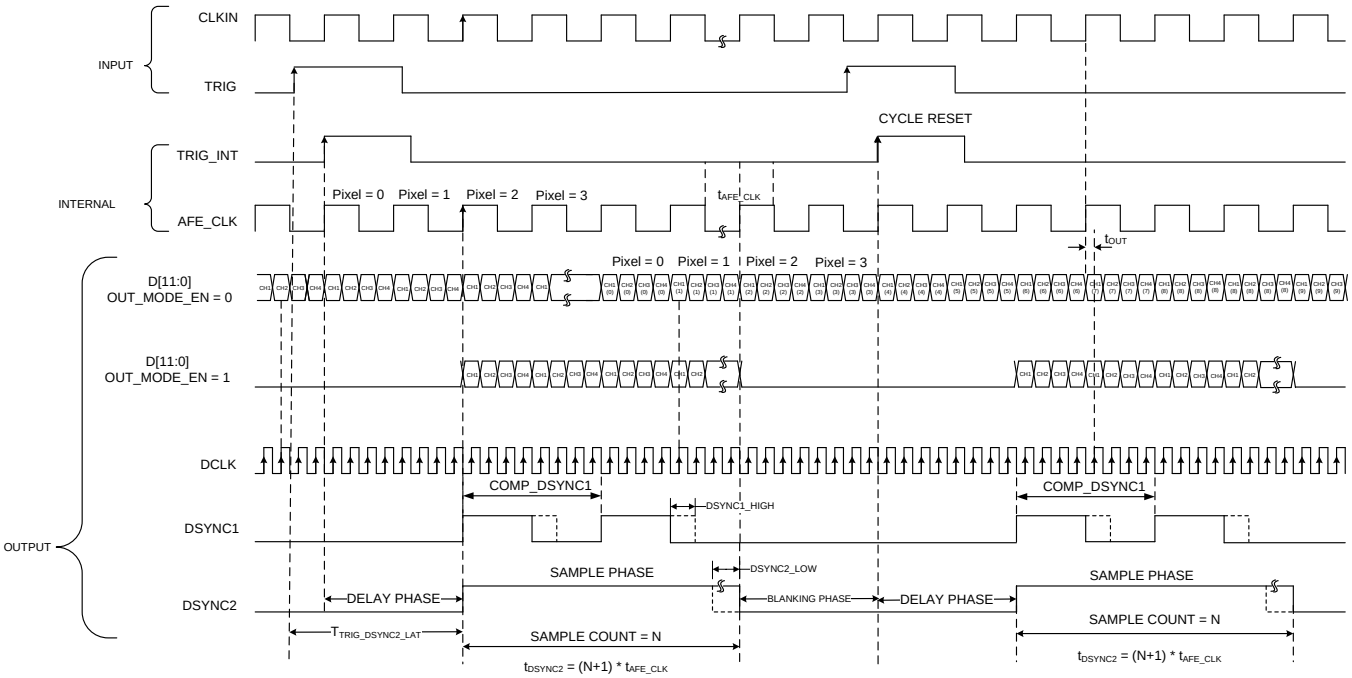


Figure 78. DSYNCx Timing Diagram

8.6 Register Maps

8.6.1 Functional Register Map

Table 28 shows the register map for the AFE5401 registers.

Table 28. Register Map

REGISTER	BIT 15	BIT 14	BIT 13	BIT 12	BIT 11	BIT 10	BIT 9	BIT 8	BIT 7	BIT 6	BIT 5	BIT 4	BIT 3	BIT 2	BIT 1	BIT 0
0 (00h)	0	0	0	0	0	0	0	0	0	0	0	0	0	0	REG_ READ_EN	SW_RST
1 (01h)	0	0	0	0	0	STDBY	0	0	DECIMATE _4_EN	DIV_REG		DIV_FRC	DECIMATE _2_EN	DIV_EN	SE_CLK_ MODE	GLOBAL_ PDN
2 (02h)	TST_PAT_MODE			0	0	0	0	0	0	DGPO0_MODE		DGPO1_MODE		0	0	0
3 (03h)	0	0	0	0	0	0	TEMP_DATA									
4 (04h)	OUT_ BLANK_HIZ	OUT_ MODE_EN	DCLK_ INVERT	TEMP_ CONV_EN	TEMP_ SENS_EN	0	0	0	0	0	0	0	OFF_BIN_ DATA_FMT	0	0	0
5 (05h)	CUSTOM_PAT															
6 (06h)	0	0	0	0	0	0	0	0	0	0	0	0	0	DIAG_REG		
7 (07h)	D_GPO_EN	PARITY_ ODD	STAT_ EN	DCP_INP_ EN	DCP_INP_PROG			DIAG_ MODE_EN	0	0	0	0	FILTER_BW		HEADER_MODE	
8 (08h)	C2_FIR								DIG_GAIN_C1_FIR							
9 (09h)	C4_FIR								C3_FIR							
10 (0Ah)	C6_FIR								C5_FIR							
15 (0Fh)	0	0	0	0	0	FAST_ DGPO	0	0	0	0	0	0	0	0	0	0
19 (13h)	0	OB_ DISABLE	STR_CTRL_CLK				STR_CTRL_DATA				0	0	0	0	0	0
21 (15h)	DELAY_COUNT[23:16]								SAMPLE_COUNT[23:16]							
22 (16h)	DELAY_COUNT[15:0]															
23 (17h)	SAMPLE_COUNT[15:0]															
24 (18h)	TRIG_FALL	DSYNC1_ START_ LOW	0	DSYNC_EN	0	COMP_DSYNC1[15:6]										0
25 (19h)	COMP_DSYNC1[5:0]						0	0	DSYNC2_LOW[23:16]							
26 (1Ah)	DSYNC2_LOW[15:0]															
27 (1Bh)	DSYNC1_HIGH															
29 (1Dh)	OFFSET_ DIS	0	STAT_CH_SEL		0	0	STAT_CALC_CYCLE					0	0	0	0	STAT_CH_ AUTO_SEL
30 (1Eh)	0	0	0	0	0	0	0	MULT_EN	FILT_EN	0	0	0	0	0	0	0
32 (20h)	0	0	0	0	HEADER_CH1											
33 (21h)	CH_OUT_ DIS1	AUX_CH1_ EN	PDN_CH1	INVERT_ CH1	0	0	OFFSET_CH1									
34 (22h)	0	0	MEAN_CH1													
35 (23h)	0	0	NOISE_CH1													
36 (24h)	0	0	0	0	HEADER_CH2											

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Register Maps (continued)

Table 28. Register Map (continued)

REGISTER	BIT 15	BIT 14	BIT 13	BIT 12	BIT 11	BIT 10	BIT 9	BIT 8	BIT 7	BIT 6	BIT 5	BIT 4	BIT 3	BIT 2	BIT 1	BIT 0
37 (25h)	CH_OUT_DIS2	AUX_CH2_EN	PDN_CH2	INVERT_CH2	0	0	OFFSET_CH2									
38 (26h)	0	0	MEAN_CH2													
39 (27h)	0	0	NOISE_CH2													
40 (28h)	0	0	0	0	HEADER_CH3											
41 (29h)	CH_OUT_DIS3	AUX_CH3_EN	PDN_CH3	INVERT_CH3	0	0	OFFSET_CH3									
42 (2A)	0	0	MEAN_CH3													
43(2B)	0	0	NOISE_CH3													
44 (2Ch)	0	0	0	0	HEADER_CH4											
45 (2Dh)	CH_OUT_DIS4	AUX_CH4_EN	PDN_CH4	INVERT_CH4	0	0	OFFSET_CH4									
46(2Eh)	0	0	MEAN_CH4													
47(2Fh)	0	0	NOISE_CH4													
65 (41h)	0	0	0	0	0	TERM_INT_20K_AUX	0	0	0	0	0	0	0	0	0	0
69 (45h)	TERM_INT_20K_LNA	LNA_GAIN		PGA_GAIN						EQ_EN	0	0	0	0	0	0
70 (46h)	0	HPL_EN	0	0	0	0	0	0	0	0	0	0	0	0	VOUT_ON_ADC	
71(47h)	0	0	0	0	0	0	0	0	0	0	0	0	HIGH_POW_LNA	EQ_EN_LOW_FC	0	0
100(64h)	0	HF_AFE_CLK_EN		0	0	0	0	0	0	0	0	0	0	0	0	0

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8.6.2 Register Descriptions

Figure 79. Register 0 (00h)

15	14	13	12	11	10	9	8
0	0	0	0	0	0	0	0
7	6	5	4	3	2	1	0
0	0	0	0	0	0	REG_READ_EN	SW_RST

Bits 15:2 **Must write 0**

Bit 1 **REG_READ_EN: Register read mode**

0 = Write (default)
1 = Enable register read

Bit 0 **SW_RST: Software reset**

This bit is the software reset for the entire device. This bit is self-clearing.

Figure 80. Register 1 (01h)

15	14	13	12	11	10	9	8
0	0	0	0	0	STDBY	0	0
7	6	5	4	3	2	1	0
DECIMATE_4_EN	DIV_REG		DIV_FRC	DECIMATE_2_EN	DIV_EN	SE_CLK_MODE	GLOBAL_PDN

Bits 15:11 **Must write 0**

Bit 10 **STDBY: Full device standby**

0 = Normal (default)
1 = Standby

Bits 9:8 **Must write 0**

Bit 7 **DECIMATE_4_EN**

0 = Decimate-by-4 mode not enabled
1 = Decimate-by-4 mode enabled

The DECIMATE_2_EN and FILT_EN bits must be set.
FIR filter coefficients (C1 to C6) must be written for proper operation.
If the AFE_CLK frequency > 25 MHz, then HF_AFE_CLK_EN must be set.

Bits 6:5 **DIV_REG: Input clock divider ratio in DIV_FRC mode**

DIV_REG	f_{AFE_CLK}	
0	CLKIN ÷ 1	Input divider disabled and bypassed
1	CLKIN ÷ 2	
2	CLKIN ÷ 3	
3	CLKIN ÷ 4	

Bit 4 **DIV_FRC: Force input divider ratio**

0 = Auto computed based on CH_OUT_DISx (default). For more details, refer to Table 12.
1 = AFE clock frequency is based on DIV_REG settings

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Bit 3 **DECIMATE_2_EN**

0 = Normal mode
1 = Decimate-by-2 mode enabled

The FILT_EN bit must be set for proper operation.
FIR filter coefficients (C1 to C6) must be written for proper operation.
If the AFE_CLK frequency > 25 MHz, then HF_AFE_CLK_EN must also be set.

Bit 2 **DIV_EN: Enable CLKIN divider**

0 = Disabled and bypassed (default)
1 = Enabled

Bit 1 **SE_CLK_MODE: Single-ended input clock configuration**

0 = Differential (default)
1 = Single-ended

Bit 0 **GLOBAL_PDN: Full device power-down**

0 = Normal (default)
1 = Global PDN

Figure 81. Register 2 (02h)

15	14	13	12	11	10	9	8
TST_PAT_MODE			0	0	0	0	0
7	6	5	4	3	2	1	0
0	DGPO0_MODE		DGPO1_MODE		0	0	0

Bits 15:13 **TST_PAT_MODE: Test pattern for CMOS output**

0 = Normal (default)
1 = SYNC
2 = Deskew
3 = Custom register 5[15:0]
4 = All 1s
5 = Toggle
6 = All 0s
7 = Ramp

Bits 12:7 **Must write 0**

Bits 6:5 **DGPO0_MODE: DGPO0 mode configuration**

0 = Low (default)
1 = Parity
2 = Overload
3 = D[11]

Bits 4:3 **DGPO1_MODE: DGPO1 mode configuration**

0 = Low (default)
1 = Parity
2 = Overload
3 = D[11]

Bits 2:0 **Must write 0**

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Figure 82. Register 3 (03h)

15	14	13	12	11	10	9	8
0	0	0	0	0	0	TEMP_DATA	
7	6	5	4	3	2	1	0
TEMP_DATA							

Bits 15:10 **Ignore bits**

Bits 9:0 **TEMP_DATA: Read-only temperature readout register**

Data is 9-bit, twos complement format in degrees Celsius.

Figure 83. Register 4 (04h)

15	14	13	12	11	10	9	8
OUT_BLANK_HIZ	OUT_MODE_EN	DCLK_INVERT	TEMP_CONV_EN	TEMP_SENS_EN	0	0	0
7	6	5	4	3	2	1	0
0	0	0	0	OFF_BIN_DATA_FMT	0	0	0

Bit 15 **OUT_BLANK_HIZ: Output status during blanking phase**

0 = D[11:0] and D_GPO[1:0] are low (default) if EN_OUT_MODE = 1
1 = D[11:0] and D_GPO[1:0] are Hi-Z if EN_OUT_MODE = 1

For more details, refer to Figure 67.

Bit 14 **OUT_MODE_EN: Enables output mode gating with DSYNC2**

0 = CMOS data is always active (default)
1 = Output mode enabled. Data is transmitted only during sample phase.

Bit 13 **DCLK_INVERT: Invert DCLK**

0 = DCLK rising edge at the center of data (default)
1 = DCLK falling edge at the center of data

Bit 12 **TEMP_CONV_EN: Enable Temperature Sensor output to digital conversion**

0 = Hold conversion
1 = Convert

Bit 11 **TEMP_SENS_EN: Enable temperature sensor block**

0 = Disable temperature sensor
1 = Enable temperature sensor

Bits 10:4 **Must write 0**

Bit 3 **OFF_BIN_DATA_FMT: Output data format**

0 = Twos complement (default)
1 = Offset binary

Bits 2:0 **Must write 0**

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Figure 84. Register 5 (05h)

15	14	13	12	11	10	9	8
CUSTOM_PAT							
7	6	5	4	3	2	1	0
CUSTOM_PAT							

Bits 15:0 **CUSTOM_PAT: Custom pattern data**

These bits set the custom data pattern.

Figure 85. Register 6 (06h)

15	14	13	12	11	10	9	8
0	0	0	0	0	0	0	0
7	6	5	4	3	2	1	0
0	0	0	0	0	DIAG_REG[2:0]		

Bits 15:3 **Ignore bits**

Bits 2:0 **DIAG_REG: Read only diagnostic readout register**

DIAG_REG[0] = 0: ADC references are correct
DIAG_REG[1] = 0: Indicates band gap is correct
DIAG_REG[2] = 0: Indicates clock generation is correct

Figure 86. Register 7 (07h)

15	14	13	12	11	10	9	8
D_GPO_EN	PARITY_ODD	STAT_EN	DC_INP_EN	DC_INP_PROG			DIAG_MODE_EN
7	6	5	4	3	2	1	0
0	0	0	0	FILTER_BW		HEADER_MODE	

Bit 15 **D_GPO_EN: Enable D_GPO functionality**

0 = D_GPO[x] pins are disabled (default)
1 = D_GPO[x] pins are enabled

Bit 14 **PARITY_ODD: Parity type**

0 = Even (default)
1 = Odd

Bit 13 **STAT_EN: Enable noise and mean calculation of ADC output**

0 = Default
1 = Enables noise and mean computation if STAT_CALC_CYCLE is set.

Bit 12 **DC_INP_EN: Enable dc analog voltage at LNA input. In this mode, equalizer is disabled automatically.**

0 = Normal
1 = DC input force is controlled by DC_INP_PROG.

Bits 11:9 **DC_INP_PROG: DC Input programmability**

0 = 0 mV
1 = 0 mV
2 = 50 mV
3 = –50 mV
4 = 100 mV
5 = –100 mV
6 = 100 mV
7 = –100 mV

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Bit 8 **DIAG_MODE_EN: Enable diagnostic mode**

0 = Disable diagnostic circuit
1 = Enable diagnostic circuit

Bits 7:4 **Must write 0**

Bits 3:2 **FILTER_BW: Filter corner frequency**

0 = 8 MHz (default)
1 = 7 MHz
2 = 10.5 MHz
3 = 12 MHz

Bits 1:0 **HEADER_MODE: Header output mode**

0 = ADC data at output (default)
1 = Header data at output
2 = [Temperature data, diagnostic data, mean, noise, (-1), (-1), (-1), (-1)]. This data sequence is repeated.
3 = Header data, temperature data, diagnostic data, mean, noise, ADC data.
Refer to Figure 70 for more information.

Figure 87. Register 8 (08h)

15	14	13	12	11	10	9	8
C2_FIR							
7	6	5	4	3	2	1	0
DIG_GAIN_C1_FIR							

Bits 15:8 **C2_FIR: Coefficient C2 for FIR digital filter** (1)

2 = Default value

Bit 7:0 **DIG_GAIN_C1_FIR: Digital Gain common for all channels, coefficient C1 for decimation filter**

$$\text{Digital Filter Gain} = \frac{(DIG_GAIN + 32)}{32} \quad (5)$$

where:

- (DIG_GAIN + 32) is Mod(2) 128.

Refer to Figure 60 for more information.

Mode	C1 Functionality
With MULT_EN	DIG_GAIN
With DECIMATE_X _EN	Coefficient C1 for FIR digital filter

5 = Default value

(1) C1 to C6 FIR filter coefficients are in twos complement form.
(2) Mod = Remainder of the division.

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Figure 88. Register 9 (09h)

15	14	13	12	11	10	9	8
C4_FIR							
7	6	5	4	3	2	1	0
C3_FIR							

Bits 15:8 **C4_FIR: Coefficient C4 for FIR digital filter(1)**

–2 = Default value

Bit 7:0 **C3_FIR: Coefficient C3 for FIR digital filter(1)**

–13 = Default value

(1) C1 to C6 FIR filter coefficients are in twos complement form.

Figure 89. Register 10 (0Ah)

15	14	13	12	11	10	9	8
C6_FIR							
7	6	5	4	3	2	1	0
C5_FIR							

Bits 15:8 **C6_FIR: Coefficient C6 for FIR digital filter(1)**

66 = Default value

Bit 7:0 **C5_FIR: Coefficient C5 for FIR digital filter(1)**

38 = Default value

(1) C1 to C6 FIR filter coefficients are in twos complement form.

Figure 90. Register 15 (0Fh)

15	14	13	12	11	10	9	8
0	0	0	0	0	FAST_DGPO	0	0
7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	0

Bits 15:11, and Bits 9:0 **Must write 0**

Bit 10 **FAST_DGPO: Fast DGPO output buffer**

0 = Default strength (default)
1 = Higher drive strength on D_GPO[x] pins.

Must write 0

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Figure 91. Register 19 (13h)

15	14	13	12	11	10	9	8
0	OB_DISABLE	STR_CTRL_CLK				STR_CTRL_DATA	
7	6	5	4	3	2	1	0
STR_CTRL_DATA		0	0	0	0	0	0

Bits 15, Bits 5:0 **Must write 0**

Bit 14 **OB_DISABLE: CMOS output buffers D[11:0], DCLK disabled**

0 = Active CMOS output buffers
1 = Hi-Z CMOS output Buffers

Bits 13:10 **STR_CTRL_CLK: Controls strength of CMOS output DCLK buffer**

STR_CTRL_CLK	Drive Strength	DRVDD (V)
0	Default strength (C_{LOAD} = 5 pF)	3.3
6	Maximum strength (C_{LOAD} = 15 pF)	3.3
5	Default strength (C_{LOAD} = 5 pF)	1.8
14	Maximum strength (C_{LOAD} = 15 pF)	1.8

All other options are reserved.

Bit 9:6 **STR_CTRL_DATA: Controls strength of CMOS output DATA buffers**

STR_CTRL_DATA	Drive Strength	DRVDD (V)
0	Default strength (C_{LOAD} = 5 pF)	3.3
6	Maximum strength (C_{LOAD} = 15 pF)	3.3
5	Default strength (C_{LOAD} = 5 pF)	1.8
14	Maximum strength (C_{LOAD} = 15 pF)	1.8

All other options are reserved.

Figure 92. Register 21 (15h)

15	14	13	12	11	10	9	8
DELAY_COUNT[23:16]							
7	6	5	4	3	2	1	0
SAMPLE_COUNT[23:16]							

Bits 15:8 **DELAY_COUNT[23:16]: Delay counter, upper bits**

These bits determine the delay phase in terms of t_{AFE_CLK}.

DELAY_PHASE = (DELAY_COUNT + 1) × t_{AFE_CLK}.
The valid range for DELAY_COUNT is from 0 to (2^{24} – 2).
The maximum supported values of DELAY_COUNT + SAMPLE_COUNT is (2^{24} – 2).

Bits 7:0 **SAMPLE_COUNT[23:16]: Sample counter, upper bits**

These bits determine the sample phase in terms of t_{AFE_CLK}.

Sample phase = (SAMPLE_COUNT + 1) × t_{AFE_CLK}.
The valid range for SAMPLE_COUNT is from 0 to (2^{24} – 2).
The maximum supported values of DELAY_COUNT + SAMPLE_COUNT is (2^{24} – 2).

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Figure 93. Register 22 (16h)

15	14	13	12	11	10	9	8
DELAY_COUNT[15:0]							
7	6	5	4	3	2	1	0
DELAY_COUNT[15:0]							

Bits 15:0 **DELAY_COUNT[15:0]: Delay counter, lower bits**

These bits determine the delay phase in terms of t_{AFE_CLK}.

DELAY_PHASE = (DELAY_COUNT + 1) × t_{AFE_CLK}.
The valid range for DELAY_COUNT is from 0 to (2^{24} – 2).
The maximum supported values of DELAY_COUNT + SAMPLE_COUNT is (2^{24} – 2).

Figure 94. Register 23 (17h)

15	14	13	12	11	10	9	8
SAMPLE_COUNT[15:0]							
7	6	5	4	3	2	1	0
SAMPLE_COUNT[15:0]							

Bits 15:0 **SAMPLE_COUNT[15:0]: Sample counter, lower bits**

These bits determine the sample phase in terms of t_{AFE_CLK}.

Sample phase = (SAMPLE_COUNT + 1) × t_{AFE_CLK}.
The valid range for SAMPLE_COUNT is from 0 to (2^{24} – 2).
The maximum supported values of DELAY_COUNT + SAMPLE_COUNT is (2^{24} – 2).

Figure 95. Register 24 (18h)

15	14	13	12	11	10	9	8
TRIG_FALL	DSYNC1_START_LOW	0	DSYNC_EN	0	COMP_DSYNC1[15:6]		
7	6	5	4	3	2	1	0
COMP_DSYNC1[15:6]							0

Bit 15 **TRIG_FALL**

0 = TRIG event on the TRIG rising edge
1 = TRIG event on the TRIG falling edge

Bit 14 **DSYNC1_START_LOW: Selects DSYNC1 start level**

0 = DSYNC1 starts with logic high (default)
1 = DSYNC1 starts with logic low

Bit 13 **Must write 0**

Bit 12 **DSYNC_EN: Enable DSYNC1/2 generation**

0 = Disable DSYNC1/2 signals (default - logic low)
1 = Enable DSYNC1/2 signals

Bit 11 **Must write 0**

Bits 10:1 **COMP_DSYNC1[15:6]: DSYNC1, upper bits**

These bits determine the DSYNC1 period in the number of t_{AFE_CLK} cycles. For COMP_DSYNC1 = 0 or 1, DSYNC1 is static.

Bit 0 **Must write 0**

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Figure 96. Register 25 (19h)

15	14	13	12	11	10	9	8
COMP_DSYNC1[5:0]						0	0
7	6	5	4	3	2	1	0
DSYNC2_LOW[23:16]							

Bits 15:10 **COMP_DSYNC1[5:0]: DSYNC1, lower bits**

These bits determine the DSYNC1 period in the number of t_{AFE_CLK} cycles. For COMP_DSYNC1 = 0 or 1, DSYNC1 is static.

Bits 9:8 **Must write 0**

Bits 7:0 **DSYNC2_LOW[23:16]: DSYNC2, upper bits**

Low pulse duration of DSYNC2 in number of t_{AFE_CLK} clocks.

Figure 97. Register 26 (1Ah)

15	14	13	12	11	10	9	8
DSYNC2_LOW[15:0]							
7	6	5	4	3	2	1	0
DSYNC2_LOW[15:0]							

Bits 15:0 **DSYNC2_LOW[15:0]: DSYNC2, lower bits**

Low pulse duration of DSYNC2 in number of t_{AFE_CLK} clocks.

Figure 98. Register 27 (1Bh)

15	14	13	12	11	10	9	8
DSYNC1_HIGH							
7	6	5	4	3	2	1	0
DSYNC1_HIGH							

Bits 15:0 **DSYNC1_HIGH: DSYNC1**

High pulse duration of DSYNC1, in number of t_{AFE_CLK} clocks.

DSYNC1 high = high for [(DSYNC1_HI + COMP_DSYNC1 ÷ 2) Mod (1) COMP_DSYNC1]

(1) Mod = Remainder of the division

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Figure 99. Register 29 (1Dh)

15	14	13	12	11	10	9	8
OFFSET_DIS	0	STAT_CH_SEL		0	0	STAT_CALC_CYCLE	
7	6	5	4	3	2	1	0
STAT_CALC_CYCLE			0	0	0	0	STAT_CH_AUTO_SEL

Bit 15 **OFFSET_DIS: Bypass OFFSET addition at channel output**

0 = Default. The OFFSET_CHx register value is added to the channel output.
1 = Disable OFFSET. The OFFSET_CHx register value is not added to the channel output.

Bit 14 **Always write 0**

Bits 13:12 **STAT_CH_SEL: Manual channel selection for computation by STAT module**

0 = Channel 1
1 = Channel 2
2 = Channel 3
3 = Channel 4

Bits 11:10 **Always write 0**

Bits 9:5 **STAT_CALC_CYCLE**

Number of ADC samples used for STAT computation = $2^{STAT_CALC_CYCLE+1}$,
STAT_CALC_CYCLE range = 0 to 30

and Bits 4:1 **Always write 0**

Bit 0 **STAT_CH_AUTO_SEL: Automatic channel selection for SNR Computation**

0 = Static, computation is done based on the STAT_CH_SEL selection
1 = Auto, computation is sequentially done for all four channels

Figure 100. Register 30 (1Eh)

15	14	13	12	11	10	9	8
0	0	0	0	0	0	0	MULT_EN
7	6	5	4	3	2	1	0
FILT_EN	0	0	0	0	0	0	0

Bits 15:9 **Must write 0**

Bit 8 **MULT_EN: Channel multiplier enable**

0 = Disable multiplier
1 = Enable multiplier. For digital gain, DIG_GAIN_C1_FIR must be written.

Bit 7 **FILT_EN: Digital decimation filter enable**

0 = Disable filter
1 = Enable standard 11-tap, symmetric FIR digital filter.

Bits 6:0 **Must write 0**

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Figure 101. Register 32 (20h)

15	14	13	12	11	10	9	8
0	0	0	0	HEADER_CH1			
7	6	5	4	3	2	1	0
HEADER_CH1							

Bits 15:12 **Must write 0**

Bits 11:0 **HEADER_CH1: Header information for channel 1**

These bits provide the header information for channel 1.

Figure 102. Register 33 (21h)

15	14	13	12	11	10	9	8
CH_OUT_DIS1	AUX_CH1_EN	PDN_CH1	INVERT_ CH1	0	0	OFFSET_CH1	
7	6	5	4	3	2	1	0
OFFSET_CH1							

Bit 15 **CH_OUT_DIS1: Channel 1 disable**

Channel 1 is not muxed out.

0 = Channel 1 is output (default)
1 = Channel 1 is not output

Bit 14 **AUX_CH1_EN: Enable auxiliary channel for channel 1**

0 = Filter (default)
1 = Auxiliary

Bit 13 **PDN_CH1: Power-down channel 1**

0 = Active (default)
1 = Power-down

Bit 12 **INVERT_CH1: Invert channel 1 output**

0 = Normal ouput (default)
1 = Inverted output

Bits 11:10 **Must write 0**

Bits 9:0 **OFFSET_CH1: Output offset of channel 1 range**

Output offset value = OFFSET_CH1 ÷ 4, output offset value is added to channel output.

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Figure 103. Register 34 (22h)

15	14	13	12	11	10	9	8
0	0	MEAN_CH1					
7	6	5	4	3	2	1	0
MEAN_CH1							

Bits 15:14 **Must write 0**

Bits 13:0 **MEAN_CH1: Mean for channel 1 (read-only register)**

These bits provide the mean information computed by STAT module for channel 1.

Figure 104. Register 35 (23h)

15	14	13	12	11	10	9	8
0	0	NOISE_CH1					
7	6	5	4	3	2	1	0
NOISE_CH1							

Bits 15:14 **Must write 0**

Bits 13:0 **NOISE_CH1: Noise for channel 1 (read-only register)**

These bits provide the noise information computed by STAT module for channel 1.

Figure 105. Register 36 (24h)

15	14	13	12	11	10	9	8
0	0	0	0	HEADER_CH2			
7	6	5	4	3	2	1	0
HEADER_CH2							

Bits 15:12 **Must write 0**

Bits 11:0 **HEADER_CH2: Header information for channel 2**

These bits provide the header information for channel 2.

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Figure 106. Register 37 (25h)

15	14	13	12	11	10	9	8
CH_OUT_DIS2	AUX_CH2_EN	PDN_CH2	INVERT_CH2	0	0	OFFSET_CH2	
7	6	5	4	3	2	1	0
OFFSET_CH2							

Bit 15 **CH_OUT_DIS2: Channel 2 disable**

Channel 2 is not muxed out.

0 = Channel 2 is output (default)
1 = Channel 2 is not output

Bit 14 **AUX_CH2_EN: Enable auxiliary channel for channel 2**

0 = Filter (default)
1 = Auxiliary

Bit 13 **PDN_CH2: Power-down channel 2**

0 = Active (default)
1 = Power-down

Bit 12 **INVERT_CH2: Invert channel 2 output**

0 = Normal (default)
1 = Inverted output

Bits 11:10 **Must write 0**

Bits 9:0 **OFFSET_CH2: Output offset of Channel 2**

Output offset value = OFFSET_CH2 ÷ 4, output offset value is added to the channel output

Figure 107. Register 38 (26h)

15	14	13	12	11	10	9	8
0	0	MEAN_CH2					
7	6	5	4	3	2	1	0
MEAN_CH2							

Bits 15:14 **Must write 0**

Bits 13:0 **MEAN_CH2: Mean for channel 2 (read-only register)**

These bits provide the mean information computed by the STAT module for channel 2.

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Figure 108. Register 39 (27h)

15	14	13	12	11	10	9	8
0	0	NOISE_CH2					
7	6	5	4	3	2	1	0
NOISE_CH2							

Bits 15:14 **Must write 0**

Bits 13:0 **NOISE_CH2: Noise for channel 2 (read-only register)**

These bits provide the noise information computed by the STAT module for channel 2.

Figure 109. Register 40 (28h)

15	14	13	12	11	10	9	8
0	0	0	0	HEADER_CH3			
7	6	5	4	3	2	1	0
HEADER_CH3							

Bits 15:12 **Must write 0**

Bits 11:0 **HEADER_CH3: Header information for channel 3**

These bits provide the header information for channel 3.

Figure 110. Register 41 (29h)

15	14	13	12	11	10	9	8
CH_OUT_DIS3	AUX_CH3_EN	PDN_CH3	INVERT_CH3	0	0	OFFSET_CH3	
7	6	5	4	3	2	1	0
OFFSET_CH3							

Bit 15 **CH_OUT_DIS3: Channel 3 disable**

Channel 3 is not muxed out.

0 = Channel 3 is output (default)
1 = Channel 3 is not output

Bit 14 **AUX_CH3_EN: Enable auxiliary channel for channel 3**

0 = Filter (default)
1 = Auxiliary

Bit 13 **PDN_CH3: Power-down channel 3**

0 = Active (default)
1 = Power-down

Bit 12 **INVERT_CH3: Invert channel 3 output**

0 = Normal (default)
1 = Inverted output

Bits 11:10 **Must write 0**

Bits 9:0 **OFFSET_CH3: Output offset of Channel 3**

Output offset value = OFFSET_CH3 ÷ 4, output offset value is added to the channel output

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Figure 111. Register 42 (2Ah)

15	14	13	12	11	10	9	8
0	0	MEAN_CH3					
7	6	5	4	3	2	1	0
MEAN_CH3							

Bits 15:14 **Must write 0**

Bits 13:0 **MEAN_CH3: Mean for channel 3 (read-only register)**

These bits provide the mean information computed by the STAT module for channel 3.

Figure 112. Register 43 (2Bh)

15	14	13	12	11	10	9	8
0	0	NOISE_CH3					
7	6	5	4	3	2	1	0
NOISE_CH3							

Bits 15:14 **Must write 0**

Bits 13:0 **NOISE_CH3: Noise for channel 3 (read-only register)**

These bits provide the noise information computed by the STAT module for channel 3.

Figure 113. Register 44 (2Ch)

15	14	13	12	11	10	9	8
0	0	0	0	HEADER_CH4			
7	6	5	4	3	2	1	0
HEADER_CH4							

Bits 15:12 **Must write 0**

Bits 11:0 **HEADER_CH4: Header information for channel 4**

These bits provide the header information for channel 4.

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Figure 114. Register 45 (2Dh)

15	14	13	12	11	10	9	8
CH_OUT_DIS4	AUX_CH4_EN	PDN_CH4	INVERT_CH4	0	0	OFFSET_CH4	
7	6	5	4	3	2	1	0
OFFSET_CH4							

Bit 15 **CH_OUT_DIS1: Channel 4 disable**

Channel 4 is not muxed out.

0 = Channel 4 is output (default)
1 = Channel 4 is not output

Bit 14 **AUX_CH4_EN: Enable auxiliary channel for channel 4**

0 = Filter (default)
1 = Auxiliary

Bit 13 **PDN_CH4: Power-down channel 4**

0 = Active (default)
1 = Power-down

Bit 12 **INVERT_CH4: Invert channel 4 output**

0 = Normal (default)
1 = Inverted output

Bits 11:10 **Must write 0**

Bits 9:0 **OFFSET_CH4: Output offset of channel 4**

Output offset value = OFFSET_CH4 ÷ 4, output offset value is added to the channel output

Figure 115. Register 46 (2Eh)

15	14	13	12	11	10	9	8
0	0	MEAN_CH4					
7	6	5	4	3	2	1	0
MEAN_CH4							

Bits 15:14 **Must write 0**

Bits 13:0 **MEAN_CH4: Mean for channel 4 (read-only register)**

These bits provide the mean information computed by the STAT module for channel 4.

Figure 116. Register 47 (2Fh)

15	14	13	12	11	10	9	8
0	0	NOISE_CH4					
7	6	5	4	3	2	1	0
NOISE_CH4							

Bits 15:14 **Must write 0**

Bits 13:0 **NOISE_CH4: Noise for channel 4 (read-only register)**

These bits provide the noise information computed by the STAT module for channel 4.

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Figure 117. Register 65 (41h)

15	14	13	12	11	10	9	8
0	0	0	0	0	TERM_INT_20K_AUX	0	0
7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	0

Bits 15:11 **Must write 0**

Bit 10 **TERM_INT_20K_AUX: Auxiliary input termination**

This bit is common for all channels. This bit provides an auxiliary input internal differential termination of 20 kΩ.

0 = 2-kΩ differential resistance (default)
1 = 20-kΩ differential resistance

Bits 9:0 **Must write 0**

Figure 118. Register 69 (45h)

15	14	13	12	11	10	9	8
TERM_INT_20K_LNA	LNA_GAIN		PGA_GAIN				
7	6	5	4	3	2	1	0
PGA_GAIN	EQ_EN	0	0	0	0	0	0

Bit 15 **TERM_INT_20K_LNA: LNA input termination**

This bit is common for all channels. This bit provides LNA input internal differential termination of 20 kΩ.

0 = 2-kΩ differential resistance (default)
1 = 20-kΩ differential resistance

Bits 14:13 **LNA_GAIN: LNA gain**

These bits are common for all channels.

0 = 15 dB (default)
1 = 18 dB
2 = 12 dB
3 = 16.5 dB

Bits 12:7 **PGA_GAIN: PGA gain**

These bits are common for all channels. PGA gain = 0 dB, 3 dB, 6 dB, 9 dB, 12 dB, 15 dB, 18 dB, 21 dB, 24 dB, 27 dB, and 30 dB.

0 = 0 dB
1 = 3 dB
2 = 6 dB
3 = 9 dB
4 = 12 dB
5 = 15 dB
6 = 18 dB
7 = 21 dB
8 = 24 dB
9 = 27 dB
10 = 30 dB

Bit 6 **EQ_EN: Equalizer enable**

These bits are common for all channels.

0 = Disabled (default)
1 = Enabled

Bits 5:0 **Must write 0**

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Figure 119. Register 70 (46h)

15	14	13	12	11	10	9	8
0	HPL_EN	0	0	0	0	0	0
7	6	5	4	3	2	1	0
0	0	0	0	0	0	VOUT_ON_ADC	

Bit 15 **Must write 0**

Bit 14 **HPL_EN: High-performance linearity mode**

0 = Default
1 = Improves linearity (HD3) with increased power dissipation

Bits 13:2 **Must write 0**

Bits 1:0 **VOUT_ON_ADC: Check analog block output on ADC input**

0 = LNA + antialiasing filter + ADC (default)
1 = LNA + ADC
2 = AMP1 + ADC
3 = AMP2 + ADC

Figure 120. Register 71 (47h)

15	14	13	12	11	10	9	8
0	0	0	0	0	0	0	0
7	6	5	4	3	2	1	0
0	0	0	0	HIGH_POW_LNA	EQ_EN_LOW_FC	0	0

Bits 15:4 **Must write 0**

Bit 3 **HIGH_POW_LNA**

0 = Default mode
1 = High-power LNA improves channel input-referred noise at high LNA and PGA gains compared to default mode. This mode increases power dissipation.

Bit 2 **EQ_EN_LOW_FC: Enable Equalizer Low Frequency Corner Frequency**

0 = Disable
1 = Enable; EQ_EN must also be enabled for this mode

Bits 1:0 **Must write 0**

Figure 121. Register 100 (64h)

15	14	13	12	11	10	9	8
0	HF_AFE_CLK_EN		0	0	0	0	0
7	6	5	4	3	2	1	0
0	0	0	0	0	0	0	0

Bits 15 **Must write 0**

Bits 14:13 **HF_AFE_CLK_EN**

0 = Default
3 = For f_{AFE_CLK} > 25 MHz (in decimation modes)

Bits 12:0 **Must write 0**

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9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The AFE5401-Q1 is a quad-channel, analog front-end (AFE), targeting applications where the level of integration is critical. Each channel comprises a complete base-band signal chain with:

- A low-noise amplifier (LNA),
- A programmable equalizer (EQ),
- A programmable gain amplifier (PGA), and
- An antialias filter (AAF)
- A high-speed, 12-bit, analog-to-digital converter (ADC) that samples at 25 MSPS per channel.

Having four integrated signal chain channels enables the device to be used in different end-use systems such as:

- Automotive radar (where a down-converted base-band signal from an RF front-end can be applied to the inputs of the AFE)
- Applications where up to 12-MHz voltage signal is available from a transducer

9.2 Typical Application

As Figure 122 illustrates, the device also consists of four auxiliary channels, where the analog signal chain (LNA, PGA) is bypassed and the analog inputs can be directly digitized. This configuration is very useful in the system to digitize monitoring signals (such as battery voltages and temperature sensor outputs).

As the *Design Requirements* section describes, the device can accept a variety of input clock signals (such as differential sine-wave, LVPECL, or LVDS). The can also functions seamlessly with a single-ended LVCMOS (1.8 V) clock input.

The device is designed to have a simple CMOS output data interface. Used with the TRIG and DSYNCx signals, the device can be interfaced to standard video ports of DSPs and other field-programmable gate array (FPGA) and micro-controller based receivers.

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Typical Application (continued)

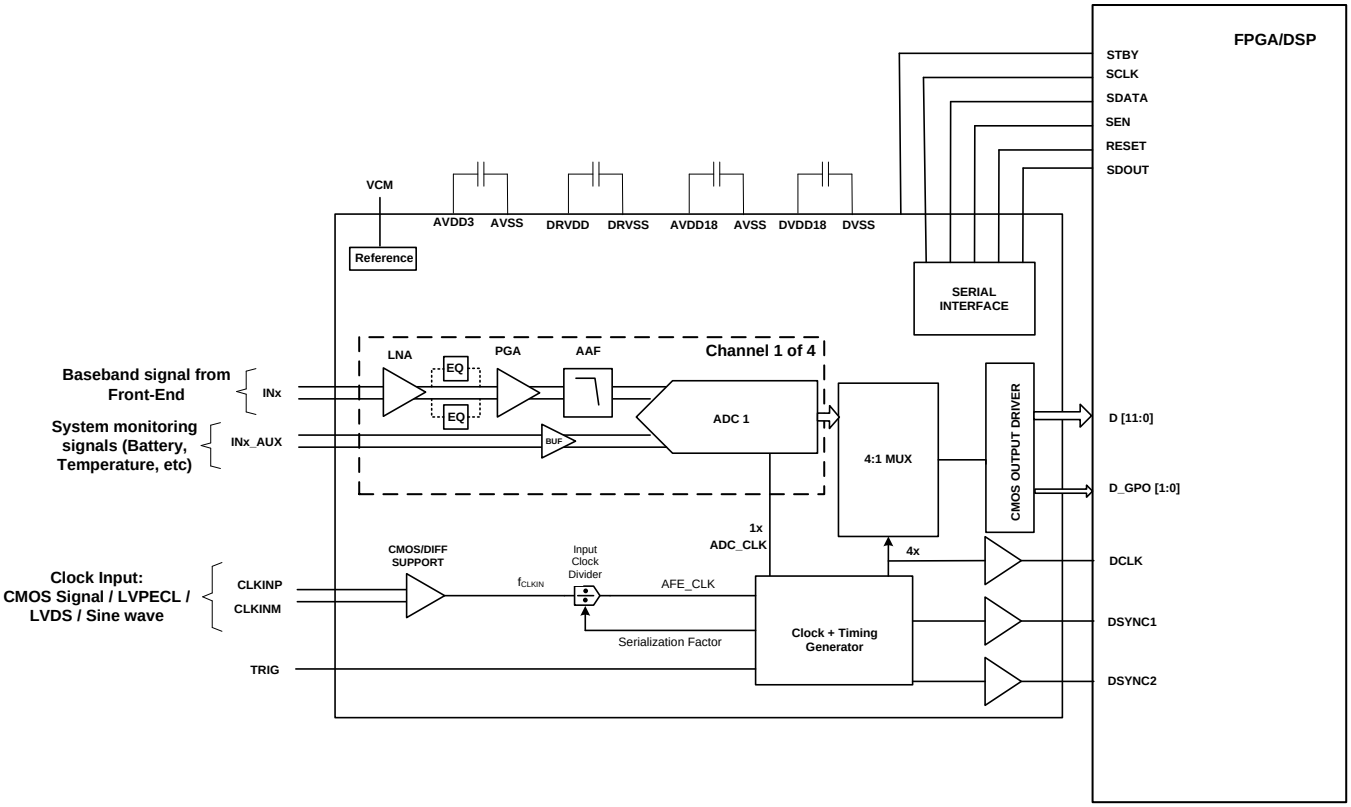


Figure 122. Typical Application Diagram

9.2.1 Design Requirements

The device can operate with either single-ended (CMOS) or differential input clocks (such as sine wave, LVPECL, and LVDS). Operating with a low-jitter differential clock is recommended for good SNR performance. In differential mode, the clock inputs are internally biased to the optimum common-mode voltage (approximately 0.95 V). While driving with an external LVPECL or LVDS driver, TI recommends ac-coupling the clock signals because the clock pins are internally biased to the common-mode voltage.

9.2.2 Detailed Design Procedure

For the LVDS input clock, R_{TERM} = 100 Ω is recommended. For the LVPECL clock input, R_{TERM} must be determined based on the LVPECL driver recommendations. To operate using a single-ended clock, connect a CMOS clock source to CLKINP and tie CLKINM to GND. The device automatically detects the presence of a single-ended clock without requiring any configuration and disables internal biasing. Typical clock termination schemes are illustrated in Figure 125, Figure 126, Figure 127, and Figure 128. Typical characteristic plots across input clock amplitude and duty cycle are shown in Application Curves.

Figure 123 and Figure 124 illustrate the equivalent circuits of the clock input pins for Differential and Single-Ended input clock respectively.

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Typical Application (continued)

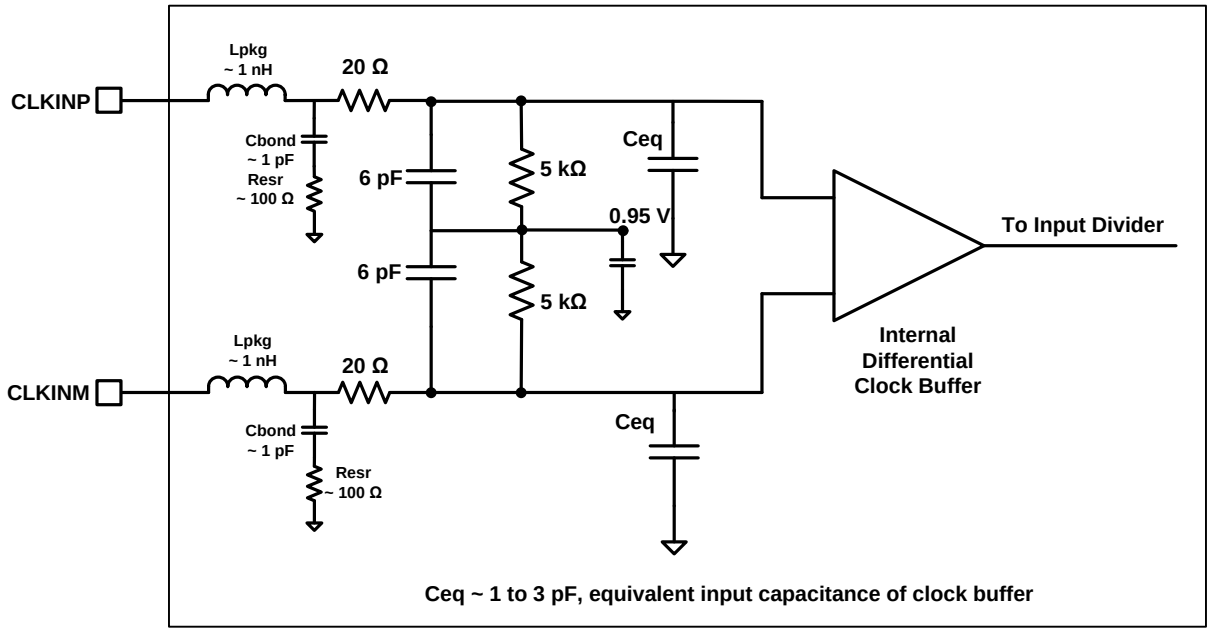


Figure 123. Clock Input Equivalent Circuit (Differential Mode)

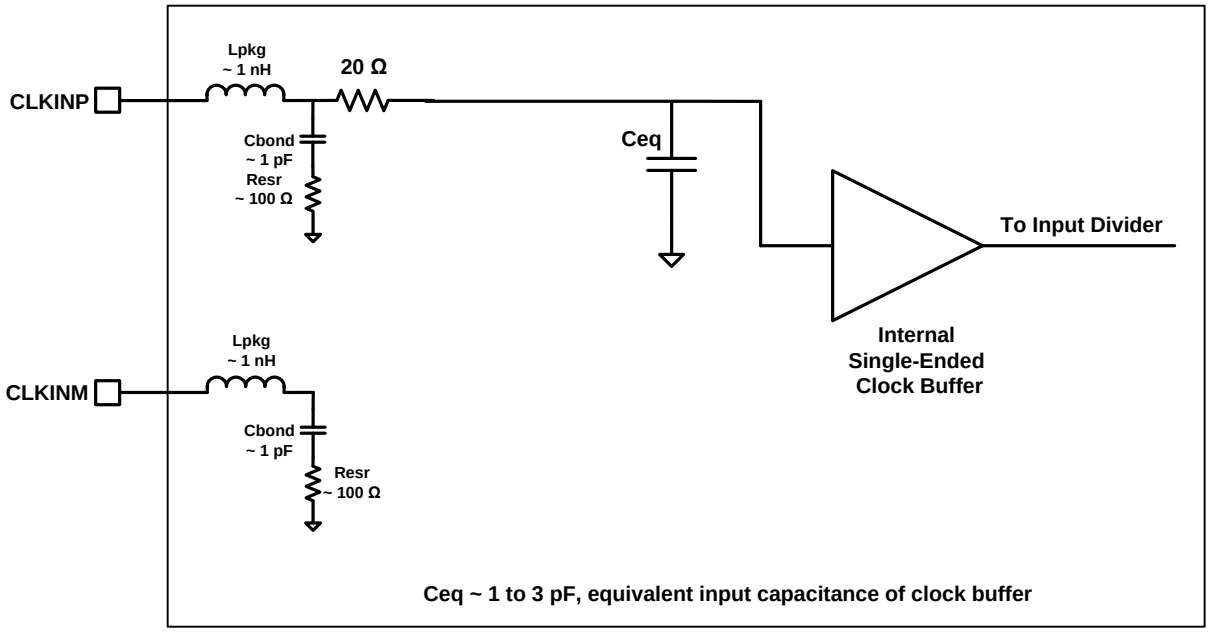


Figure 124. Clock Input Equivalent Circuit (Single-Ended Mode)

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Typical Application (continued)

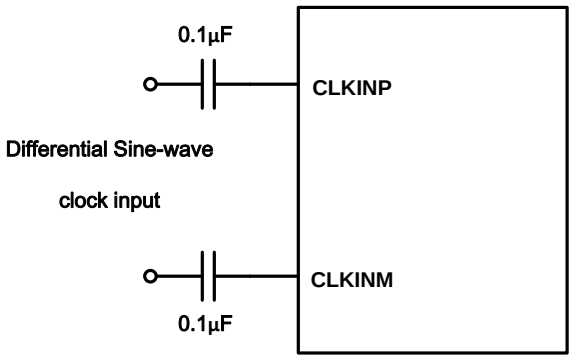


Figure 125. Differential Sine-Wave Clock Driving Circuit

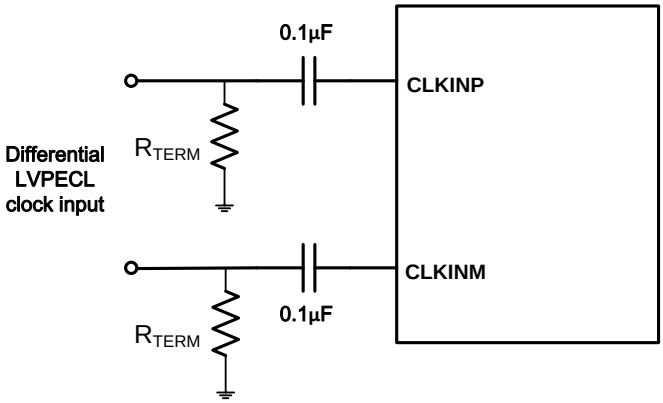


Figure 126. Differential LVPECL Clock Driving Circuit

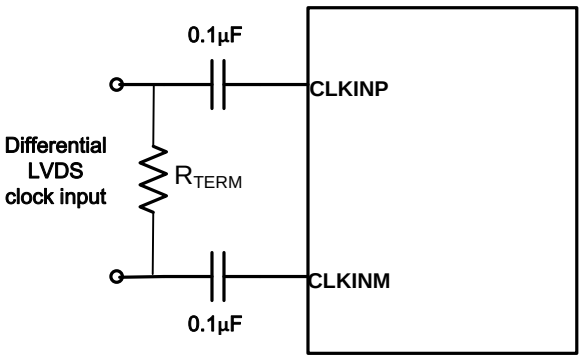


Figure 127. Differential LVDS Clock Driving Circuit

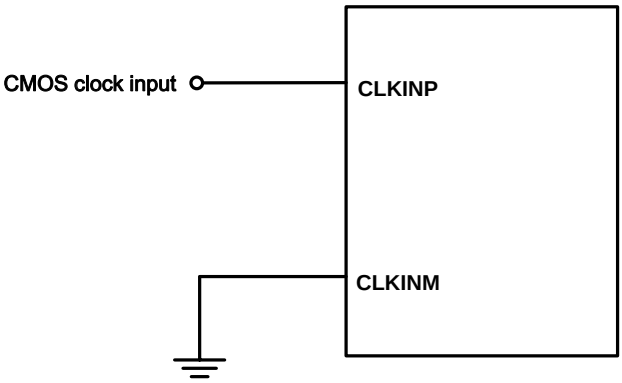


Figure 128. Single-Ended Clock Driving Circuit

9.2.3 Application Curves

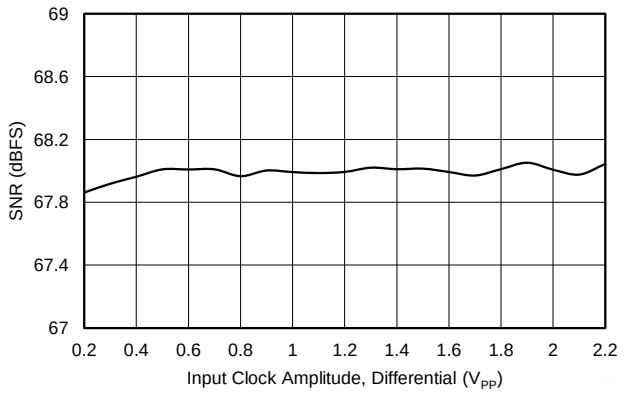


Figure 129. Signal-to-Noise Ratio vs Input Clock Amplitude (PGA Gain = 0 dB)

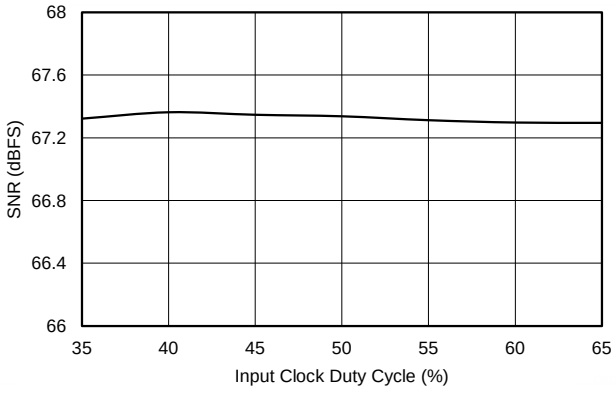


Figure 130. Signal-to-Noise Ratio vs Input Clock Duty Cycle (PGA Gain = 0 dB)

10 Power Supply Recommendations

10.1 Power Supply Sequencing

During power-up, the AVDD18, DVDD18, and DRVDD supplies can appear in any sequence. All supplies are separated in the device. Externally, they can be driven from separate supplies with suitable filtering. No power supply sequencing is required.

10.2 Power Supply Decoupling

Minimal external decoupling can be used without loss in performance because the device already includes internal decoupling. Note that decoupling capacitors can help filter external power-supply noise, so the optimum number of capacitors depends on the actual application. The decoupling capacitors should be placed as close as possible to the device supply pins.

11 Layout

11.1 Layout Guidelines

All analog inputs must be differentially and symmetrically routed to the differential input pins of the device for best performance. CMOS outputs traces should be kept as short as possible to reduce the trace capacitance that loads the CMOS output buffers. Multiple ground vias can be added around the CMOS output data traces, especially when the traces are routed on more than one layer. TI recommends matching the lengths of the output data traces (D[11:0]) to reduce the skew across data bits.

Switching noise (caused by CMOS output data transitions) can couple into the analog inputs and degrade SNR. This condition is particularly of concern because of the high gain present in the analog input channel. Digital outputs coupling back to analog inputs can be minimized by proper separation of analog and digital areas in the board layout. Figure 131 illustrates an example layout where the analog and digital portions are routed separately. This example also uses splits in the ground plane to minimize digital currents from looping into analog areas. At the same time, note that the analog and digital grounds are shorted below the device. A single ground plane is sufficient to give good performance, provided the analog, digital, and clock sections of the board are cleanly partitioned.

The device package consists of an exposed pad. In addition to providing a path for heat dissipation, the pad is also internally connected to the analog ground. Therefore, the exposed pad must be soldered to the ground plane for best thermal and electrical performance. For detailed information, see application notes *QFN Layout Guidelines* and *QFN/SON PCB Attachment*. Figure 131 and Figure 132 illustrate the layout diagrams taken from the *AFE5401-Q1 EVM User's Guide*.

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11.2 Layout Example

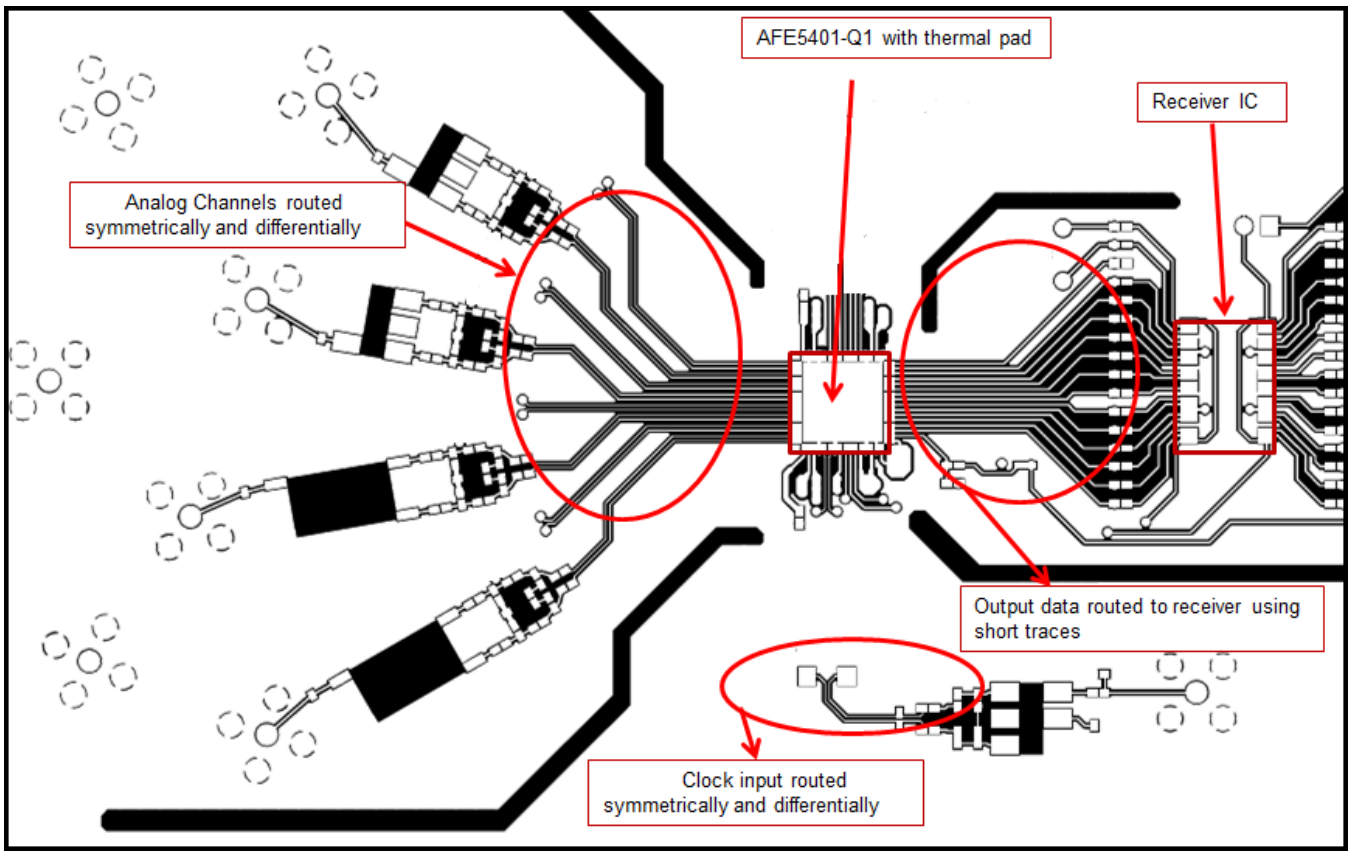


Figure 131. Layout Diagram: Signal Routing

Layout Example (continued)

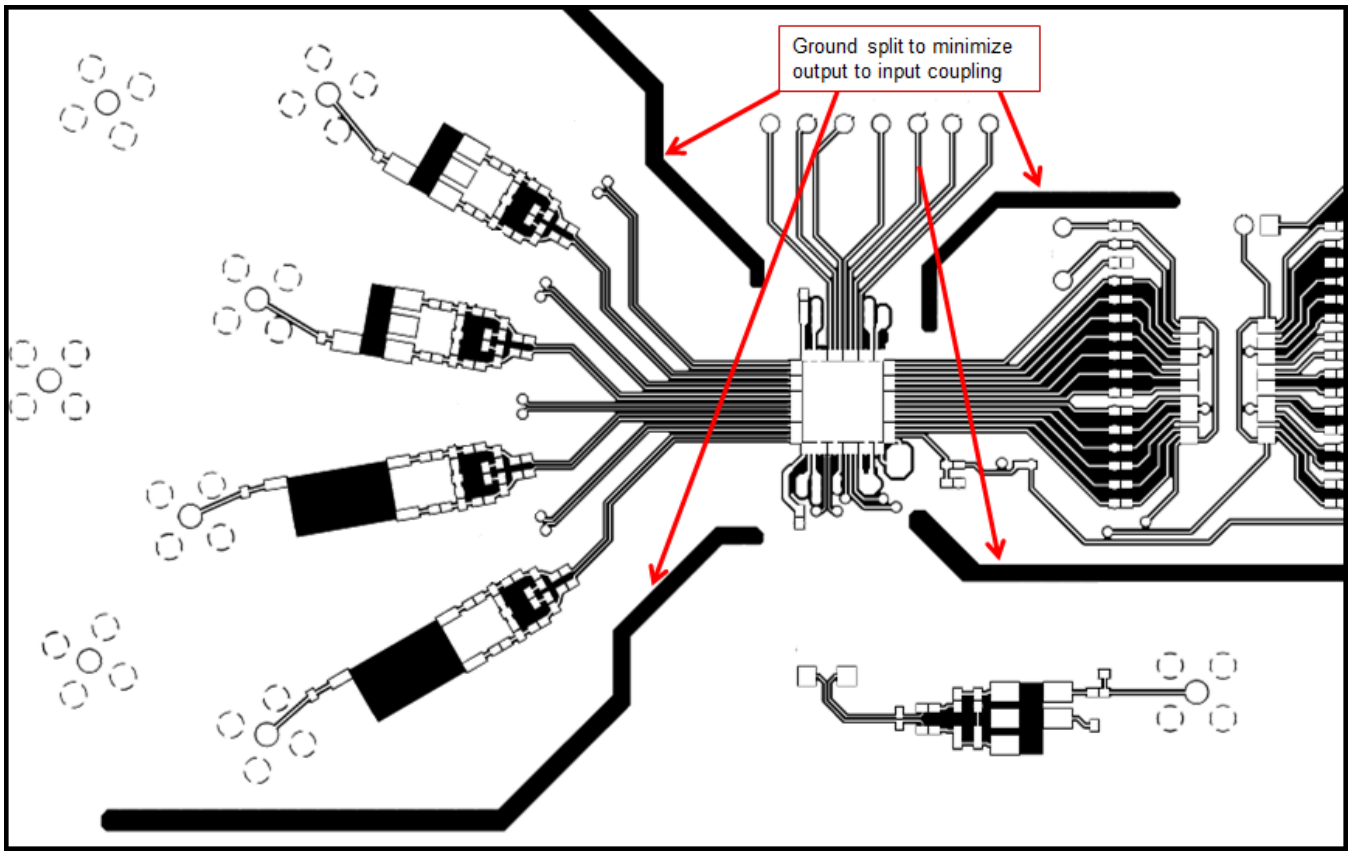


Figure 132. Layout Diagram: Ground Split

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12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- *QFN Layout Guidelines*
- *QFN/SON PCB Attachment*
- *AFE5401-Q1 EVM User's Guide*

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community ***TI's Engineer-to-Engineer (E2E) Community.*** Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support ***TI's Design Support*** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

E2E is a trademark of Texas Instruments.
SONAR is a trademark of Cakewalk, Inc.
All other trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
AFE5401TRGCRQ1	ACTIVE	VQFN	RGC	64	2000	Green (RoHS & no Sb/Br)	NIPDAU	Level-3-260C-168 HR	-40 to 105	AFE5401	Samples
AFE5401TRGCTQ1	ACTIVE	VQFN	RGC	64	250	Green (RoHS & no Sb/Br)	NIPDAU	Level-3-260C-168 HR	-40 to 105	AFE5401	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

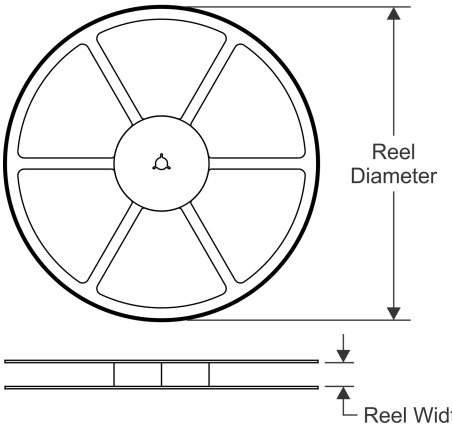
(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

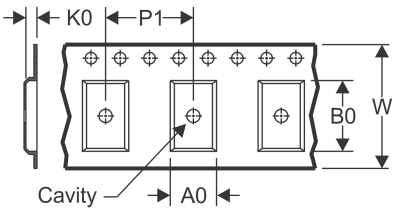
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

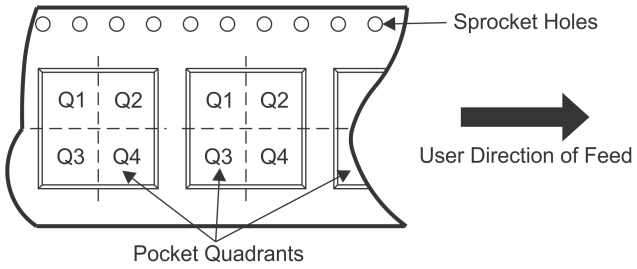


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

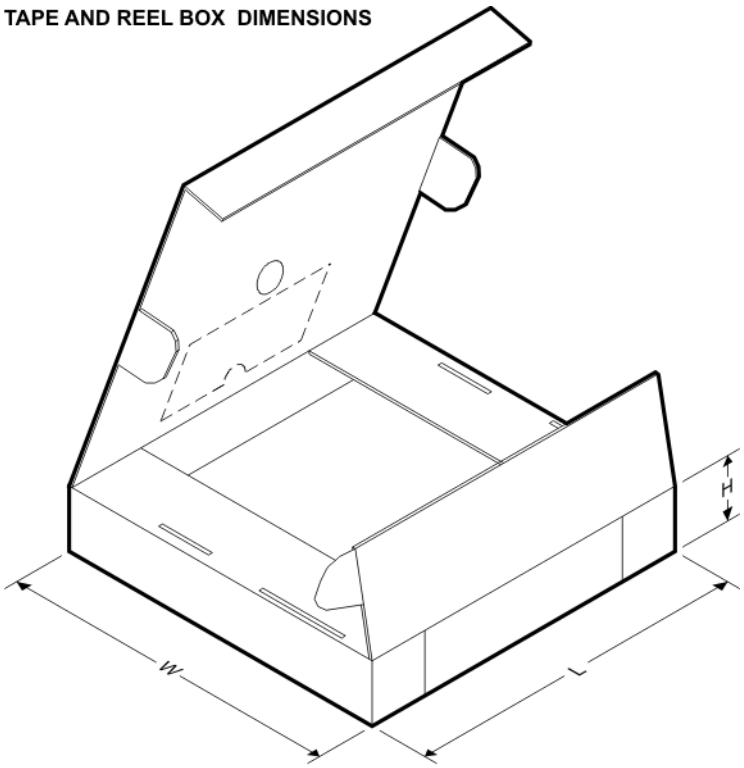
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
AFE5401TRGCRQ1	VQFN	RGC	64	2000	330.0	16.4	9.3	9.3	1.5	12.0	16.0	Q2
AFE5401TRGCTQ1	VQFN	RGC	64	250	180.0	16.4	9.3	9.3	1.5	12.0	16.0	Q2

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
AFE5401TRGCRQ1	VQFN	RGC	64	2000	350.0	350.0	43.0
AFE5401TRGCTQ1	VQFN	RGC	64	250	213.0	191.0	55.0

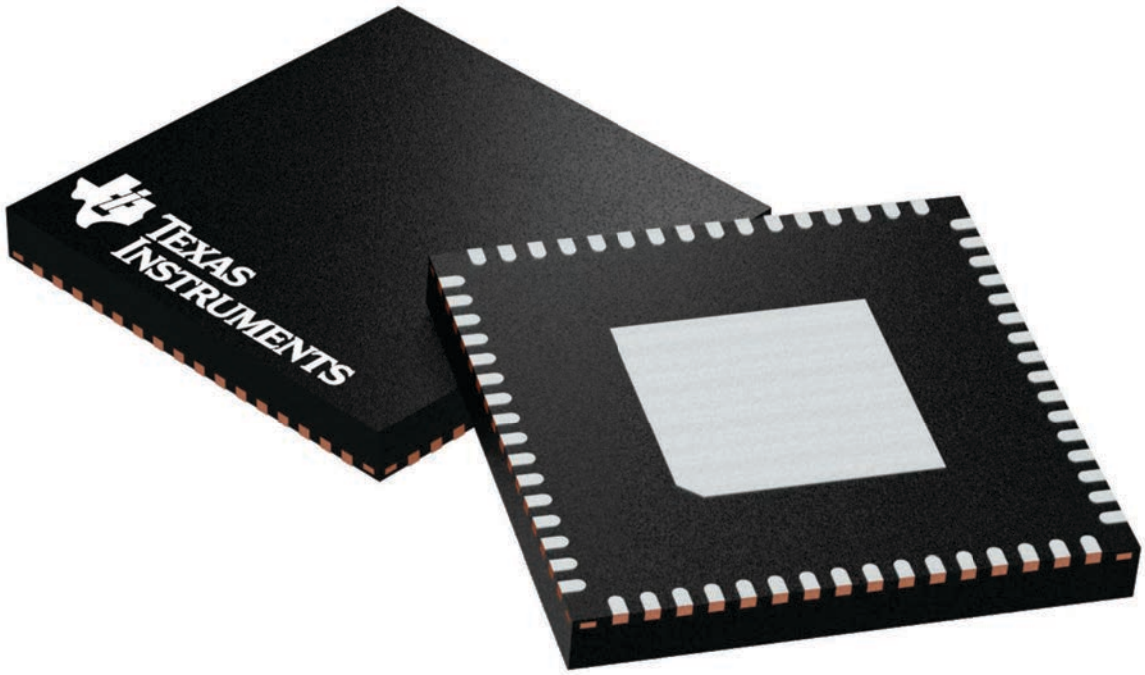
GENERIC PACKAGE VIEW

RGC 64

VQFN - 1 mm max height

9 x 9, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD



Images above are just a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.

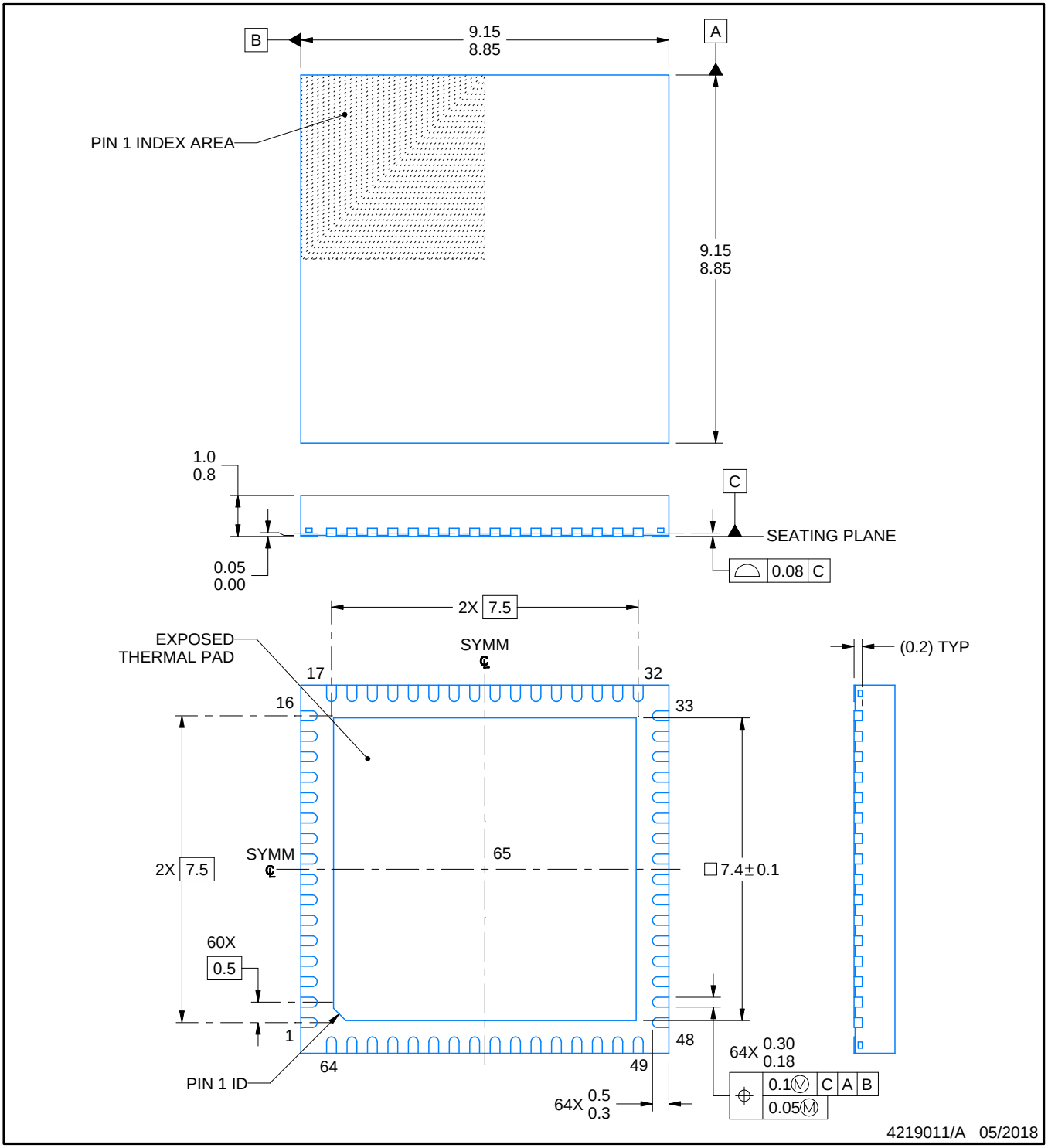
4224597/A

RGC0064H

PACKAGE OUTLINE

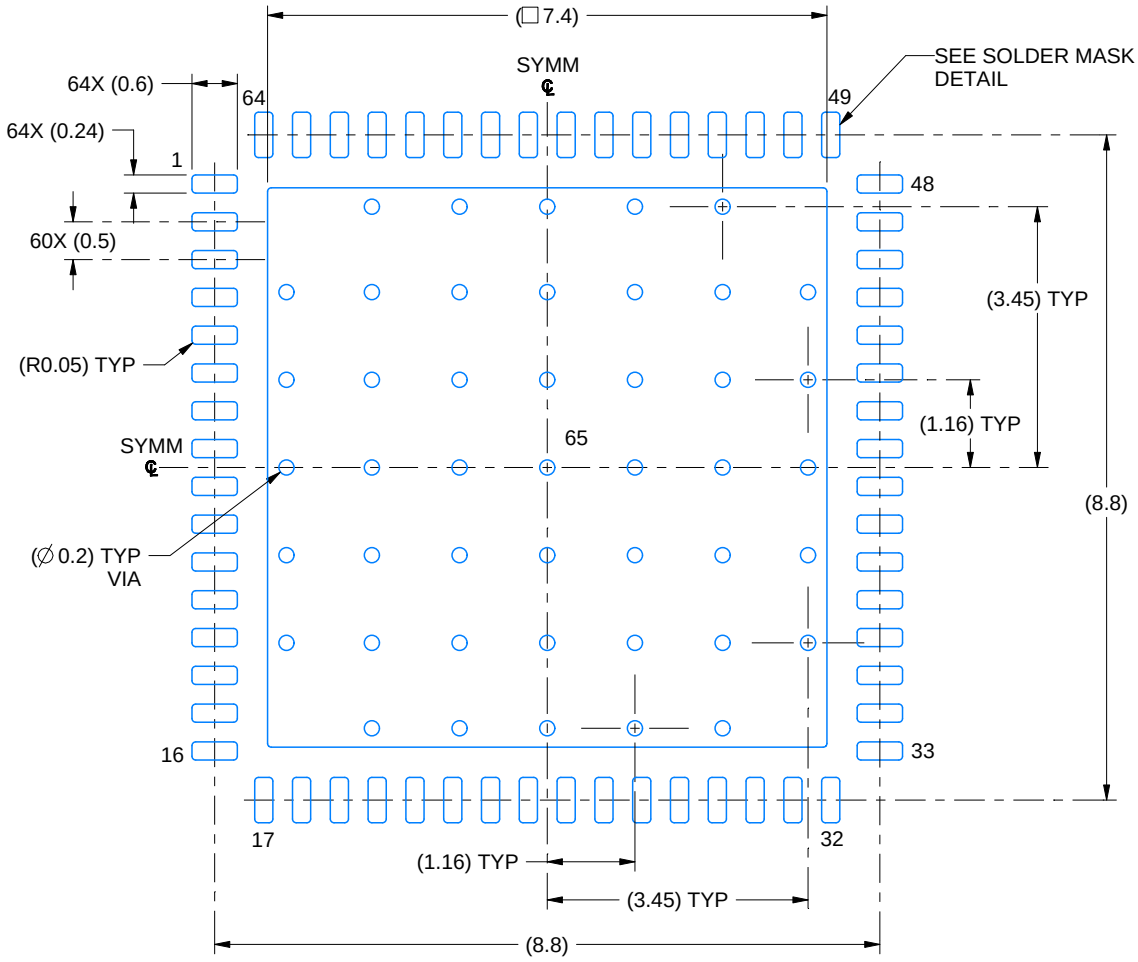
VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

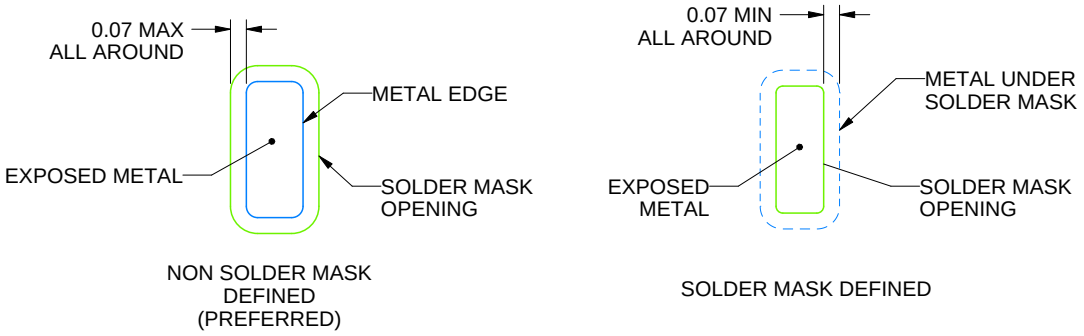


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X

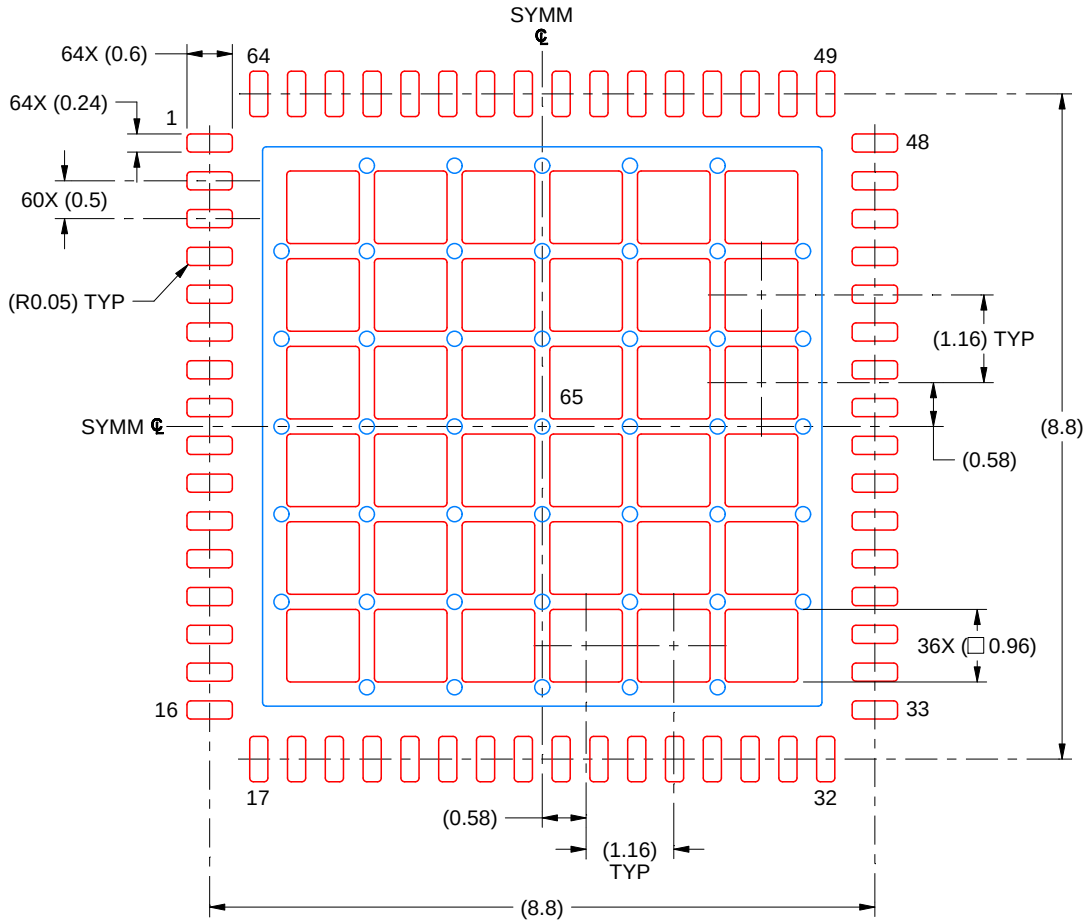


SOLDER MASK DETAILS

4219011/A 05/2018

NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



SOLDER PASTE EXAMPLE
BASED ON 0.125 MM THICK STENCIL
SCALE: 10X

EXPOSED PAD 65
61% PRINTED SOLDER COVERAGE BY AREA UNDER PACKAGE

4219011/A 05/2018

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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